



ABSTRACT

This report covers the radiation characterization results of the TPS73801-SEP low-dropout regulator. The study was done to determine total ionizing dose (TID) effects under low dose rate (LDR) up to 50 krad(Si) as a one time characterization. The results show that all samples passed within the specified limits up to 50 krad(Si) and radiation lot acceptance testing (RLAT) will be performed using 22 units at 20 krad(Si) for future wafer lots. Furthermore, the TPS73801-SEP is packaged in a space enhanced plastic for low outgassing characteristics and is single event latch-up (SEL) immune up to 43 MeV-cm²/mg making the device suitable for low Earth orbit space applications. The device is ideal for clean analog supply conditions. Examples include low noise linear regulator power supply for RF, VCOs, receivers, and amplifiers.

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1 Device Information

The TPS73801-SEP is a 1-A LDO regulator optimized for fast transient response. The device is capable of supplying 1 A at a dropout voltage of 300 mV. The low operating quiescent current (1 mA) drops to less than 1 μ A in shutdown. In addition to the low quiescent current, the TPS73801-SEP regulator incorporates several protection features which make it ideal for use in battery-powered systems.

1.1 Device Details

Table 1-1 lists the device information used in the initial TID characterization and qualification for LDR.

Table 1-1. Device and Exposure Details

TID LDR Details	
TI Device Number	TPS73801-SEP
Package	6-pin DCQ (SOT-223)
Technology	J11
Die Lot Number	0025369
A/T Lot Number / Date Code	0646206/06Z736H
Quantity Tested	67 irradiated devices + 3 control
Lot Accept/Reject	Devices passed 3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si), 50 krad(Si)
LDR Radiation Facility	Cobham RAD Solutions, Colorado Springs, CO
LDR Dose Level	3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si), 50 krad(Si)
LDR Dose Rate	0.01 rad(Si)/s
LDR Radiation Source	Gammacell JLSA 81-22 Co-60
Irradiation Temperature	Ambient, room temperature

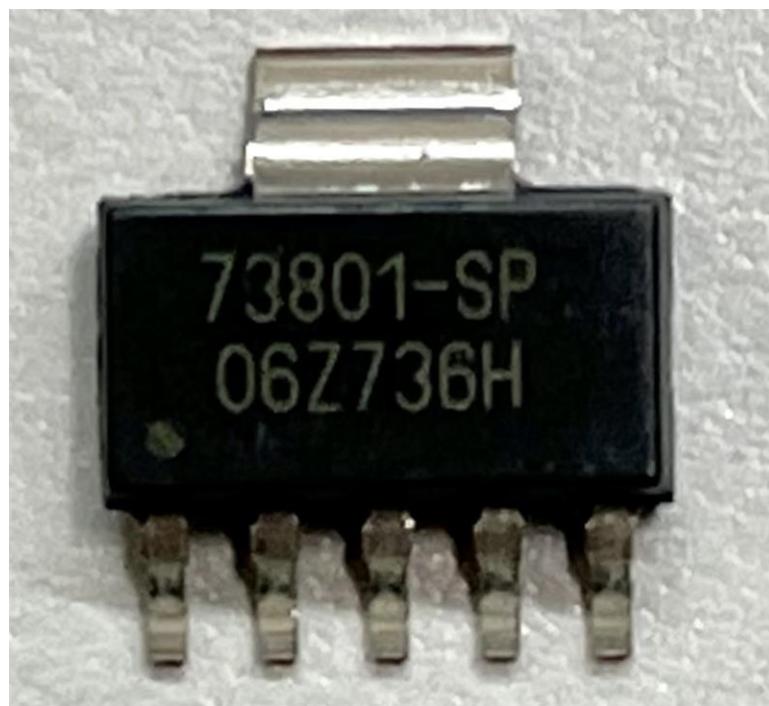


Figure 1-1. TPS73801-SEP Device Photo

2 Total Dose Test Setup

2.1 Test Overview

The TPS73801-SEP was irradiated at a low dose rate of less than 10 mrad(Si)/s. The product was irradiated up to 50 krad(Si) and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device was functional and passed all electrical parametric tests with readings within data sheet electrical specification limits.

2.2 Test Description and Facilities

The TPS73801-SEP LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10-mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/s to a maximum of approximately 65 rad(Si)/s, determined by the distance from the source. The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE test limits are set per data sheet electrical limits based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

The devices were tested in both biased and unbiased conditions as described below:

2.3.1 Unbiased

For the unbiased conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the bias conditions for each pin during irradiation.

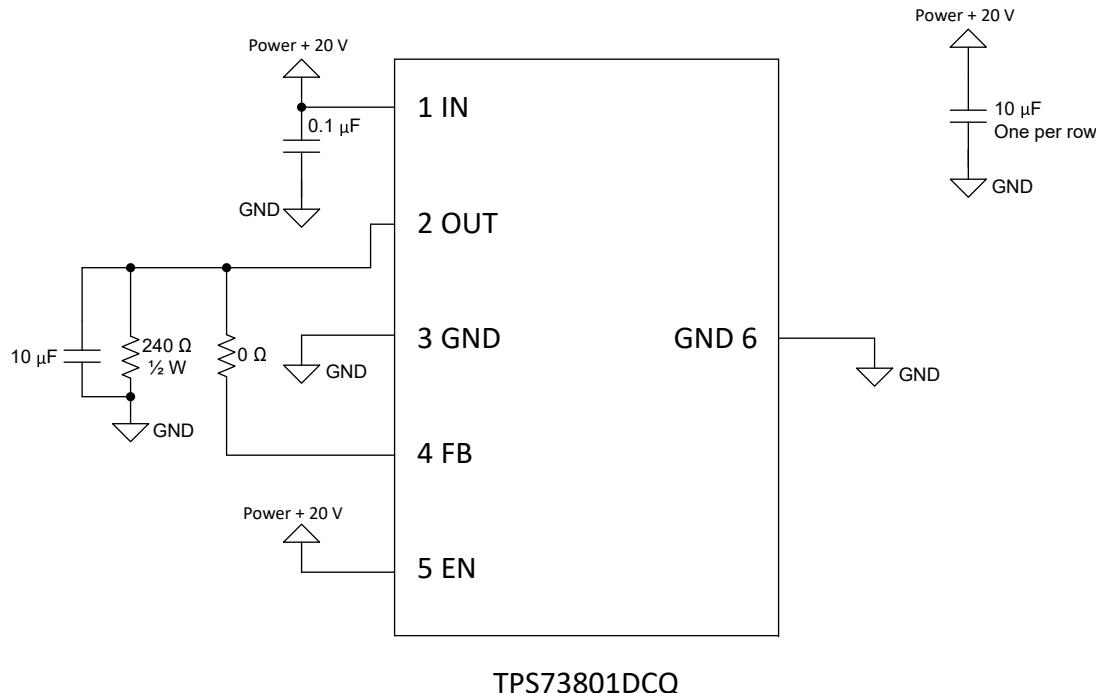


Figure 2-1. TPS73801-SEP Biased Diagram

2.4 Test Configuration and Condition

A step-stress (3k, 10k, 20k, 30k, and 50k) test method was used to determine the TID hardness level. That is, after a predetermined TID level was reached, an electrical test was performed on a given sample of parts to verify that the units are within specified data sheet electrical test limits. From initial feasibility studies the difference between pre- and post-irradiation was greater for samples that were biased, hence for RLAT 22 units were used at the 20-krad(Si) dose level with biased setup conditions and this will be repeated for each wafer lot.

Table 2-1 list the serialized samples that was used during the radiation hardness-assured (RHA) characterization.

Table 2-1. LDR 3-krad(Si) to 50-krad(Si) Biased and Unbiased Device Information

LDR = 10 mrad(Si)/s				
Total Samples: 67				
Exposure Levels				
3 krad(Si)	10 krad(Si)	20 krad(Si)	30 krad(Si)	50 krad(Si)
Biased 1, 2, 3, 4, 5	Biased 11, 12, 13, 14, 15	Biased 41, 42, 43, 44, 45, 46, 47, 48, 49, 50, 51, 52, 53, 54, 55, 56, 57, 58, 59, 60, 61, 62	Biased 21, 22, 23, 24, 25	Biased 31, 32, 33, 34, 35
Unbiased 6, 7, 8, 9, 10	Unbiased 16, 17, 18, 19, 20	Unbiased 63, 64, 65, 66, 67	Unbiased 26, 27, 28, 29, 30	Unbiased 36, 37, 38, 39, 40

3 Tested Parameters

Table 3-1 links the test numbers for each test condition with the data sheet parameters.

Table 3-1. TPS73801-SEP Data Sheet Parameters With Test Numbers

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT	Test# or Name
V _{FB} FB pin voltage	T _j = 25°C, V _{IN} = 2.21 V, I _{LOAD} = 1 mA	1.192	1.21	1.228	V	60.1__VOUT_1MA_VINMIN
	T _j = 25°C, V _{IN} = 20 V, I _{LOAD} = 1 mA	1.174	1.21	1.246	V	60.2__VOUT_1MA_VINMAX
	T _j = 25°C, V _{IN} = 2.5 V, I _{LOAD} = 1 mA	1.174	1.21	1.246	V	60.3__VOUT_1mA_VINNOM
	T _j = 25°C, V _{IN} = 2.5 V, I _{LOAD} = 1 A	1.174	1.21	1.246	V	60.4__VOUT_1A_VINNOM
Line regulation	T _j = 25°C, ΔV _{IN} = 2.21 V to 20 V, I _{LOAD} = 1 mA		1.5	5	mV	60.5__LINE REG
Load regulation	T _j = 25°C, V _{IN} = 2.5 V, ΔI _{LOAD} = 1 mA to 1 A		2	8	mV	60.6__LOAD REG
V _{D0} Dropout voltage V _{IN} = V _{OUT(NOMINAL)}	T _j = 25°C, I _{LOAD} = 1 mA		0.02	0.06	V	50.1__DROPOUT_1MA
	T _j = 25°C, I _{LOAD} = 100 mA		0.1	0.17	V	50.2__DROPOUT_100MA
	T _j = 25°C, I _{LOAD} = 500 mA		0.19	0.27	V	50.3__DROPOUT_500MA
	T _j = 25°C, I _{LOAD} = 1 A		0.24	0.3	V	50.4__DROPOUT_1000MA
I _{GND} GND pin current V _{IN} = V _{OUT(NOMINAL)} + 1	T _j = 25°C, I _{LOAD} = 0 mA		1	1.5	mA	55.1__GND_CURRENT_0mA
	T _j = 25°C, I _{LOAD} = 1 mA		1.1	1.6	mA	55.2__GND_CURRENT_1mA
	T _j = 25°C, I _{LOAD} = 100 mA		3.8	5.5	mA	55.3__GND_CURRENT_100mA
	T _j = 25°C, I _{LOAD} = 500 mA		15	25	mA	55.4__GND_CURRENT_500mA
	T _j = 25°C, I _{LOAD} = 1 A		35	80	mA	55.5__GND_CURRENT_1000m
I _{FB} FB pin bias current	T _j = 25°C		3	10	μA	15.5__I_FB_pin
I _{EN} EN pin current	T _j = 25°C, V _{EN} = 0 V		0.01	1	μA	15.1__I_EN_0V
	T _j = 25°C, V _{EN} = 20 V		3	30	μA	15.2__I_EN_20V
Quiescent current in shutdown	T _j = 25°C, V _{IN} = 6 V, V _{EN} = 0 V		0.01	1	μA	30.1__IQ_SHUTDOWN_VIN_6V
I _{REV} Input reverse leakage current	T _j = 25°C, V _{IN} = -20 V, V _{OUT} = 0 V			1	mA	5.1__IIL_VIN_-20V
I _{RO} Reverse output current	T _j = 25°C, V _{OUT} = 1.21 V, V _{IN} < 1.21 V	300	600	μA	4.1__IRO_VOUT_1.21_VIN_1.21V	
					4.2__IRO_VOUT_1.21_VIN_0V	

4 Total Ionizing Dose RHA Characterization Test Results

4.1 Total Ionizing Dose RHA Characterization Summary Results

The parametric data for the TPS73801-SEP is within data sheet limits up to 50 krad(Si) for both biased and unbiased setup conditions.

Overall, the TPS73801-SEP showed a strong degree of hardness to LDR irradiation up to 50 krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the data sheet electrical specification.

Measurements taken post-irradiation showed that the drift for samples that were biased was greater compared to the unbiased samples.

5 Applicable and Reference Documents

5.1 Applicable Documents

- [TPS73801-SEP 1-A Low-Noise Fast-Transient-Response Low-Dropout Regulator in Space Enhanced Plastic data sheet](#)
- [TPS73801-SEP Single-Event Effects \(SEE\) Test Report](#)

5.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MILSTD- 883 TM 1019. The document can be found at the DLA website.

A Specifications Requiring Clarification

Specifications Requiring Clarification

Table A-1. Specifications Requiring Clarification - Set #1

Data sheet specifications and input condition for which there is no parametric data and, therefore, not in the TID report. Functionality is assured by ATE testing.

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
V _{IN} Input voltage	T _j = 25°C	2.2	1.9	20	V
V _{EN} Shutdown threshold	V _{OUT} = OFF to ON		0.9	2	V
	V _{OUT} = ON to OFF	0.15	0.75		V

Table A-2. Specifications Requiring Clarification - Set #2

Data sheet specifications for which no data is available in TID report as specification was verified through bench testing. TID testing is by ATE.

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
V _N Output voltage noise	T _j = 25°C, C _{OUT} = 10 μF, I _{LOAD} = 1 A, BW = 10 Hz to 100 kHz		45		μV _{RMS}
PSRR Ripple rejection	T _j = 25°C, V _{IN} – V _{OUT} = 1.5 V (avg), V _{RIPPLE} = 0.5 V _{P-P} , f _{RIPPLE} = 120 Hz, I _{LOAD} = 0.75 A	55	63		dB
I _{CL} Current limit	T _j = 25°C, V _{IN} = 7 V, V _{OUT} = 0 V		2		A
	T _A = –55°C to 125°C, V _{IN} = V _{OUT(NOMINAL)} + 1	1.6			A

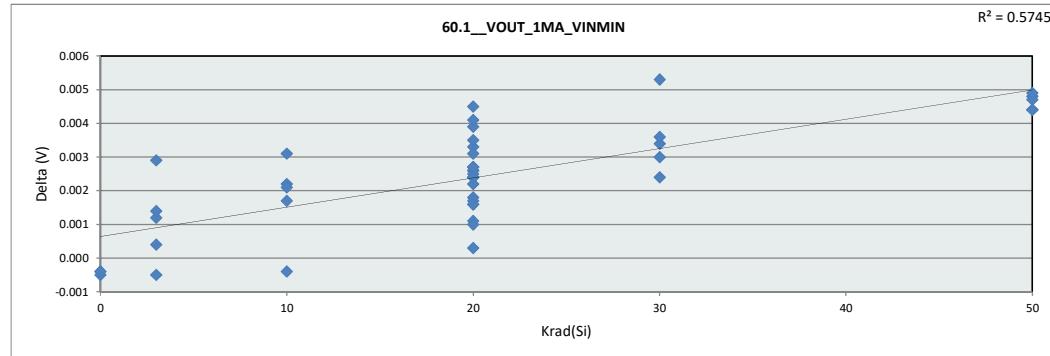
B Total Ionizing Dose LDR Data Report

This appendix provides the TPS73801-SEP TID LDR data report. The report shows the variation for each parameter up to 50 krad(Si).

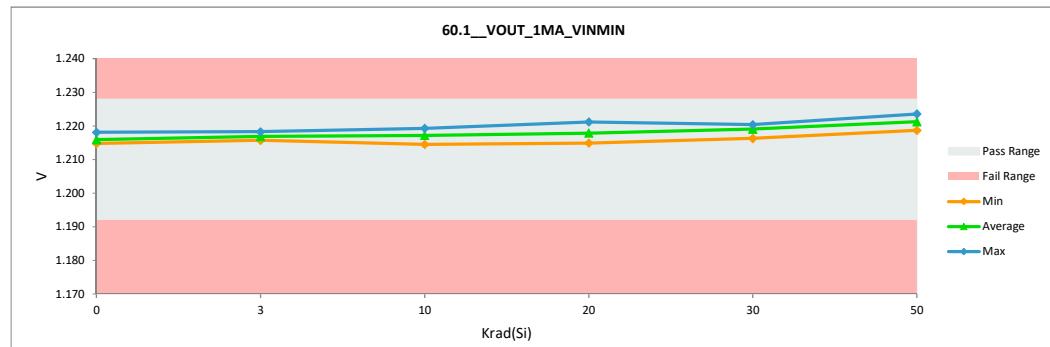
**TID LDR Data - BIASED
TPS73801-SEP**

TID LDR Data (Biased)
TPS73801-SEP

60.1_VOUT_1MA_VINMIN				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.228	1.228		
Min Limit	1.192	1.192		
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.215	1.215	0.000
0	69	1.219	1.218	0.000
0	70	1.215	1.215	0.000
3	1	1.215	1.218	0.003
3	2	1.214	1.216	0.001
3	3	1.216	1.216	-0.001
3	4	1.217	1.217	0.000
3	5	1.216	1.217	0.001
10	11	1.215	1.219	0.003
10	12	1.217	1.217	0.000
10	13	1.217	1.219	0.002
10	14	1.213	1.214	0.002
10	15	1.215	1.217	0.002
20	41	1.213	1.217	0.004
20	42	1.215	1.219	0.004
20	43	1.217	1.218	0.001
20	44	1.214	1.216	0.003
20	45	1.218	1.221	0.003
20	46	1.217	1.220	0.003
20	47	1.220	1.221	0.001
20	48	1.215	1.218	0.002
20	49	1.213	1.216	0.003
20	50	1.214	1.216	0.002
20	51	1.215	1.218	0.002
20	52	1.216	1.217	0.002
20	53	1.215	1.217	0.002
20	54	1.217	1.220	0.003
20	55	1.215	1.217	0.002
20	56	1.217	1.220	0.002
20	57	1.215	1.215	0.000
20	58	1.213	1.215	0.002
20	59	1.219	1.221	0.003
20	60	1.215	1.219	0.005
20	61	1.214	1.216	0.002
20	62	1.214	1.218	0.003
30	21	1.214	1.216	0.002
30	22	1.216	1.220	0.003
30	23	1.217	1.220	0.003
30	24	1.216	1.219	0.004
30	25	1.215	1.220	0.005
50	31	1.216	1.221	0.005
50	32	1.216	1.221	0.005
50	33	1.219	1.224	0.004
50	34	1.214	1.219	0.005
50	35	1.217	1.222	0.004
Max		1.220	1.224	0.005
Average		1.216	1.218	0.002
Min		1.213	1.214	-0.001
Std Dev		0.002	0.002	0.002

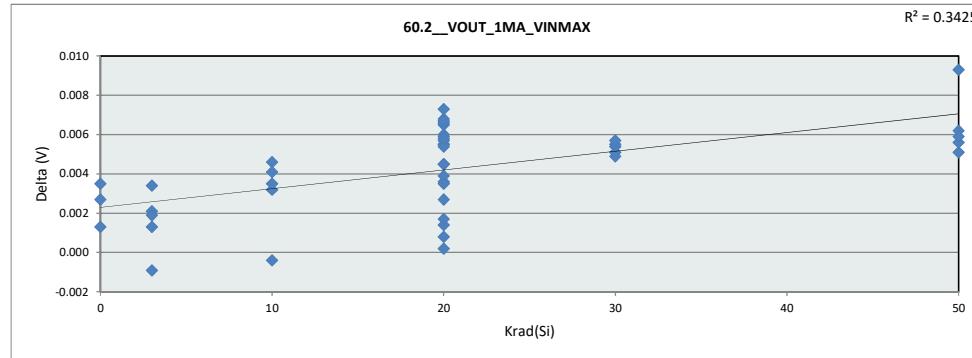


60.1_VOUT_1MA_VINMIN						
Test Site						
Tester						
Test Number						
Max Limit	1.228	V				
Min Limit	1.192	V				
Krad(Si)	0	3	10	20	30	50
LL	1.192	1.192	1.192	1.192	1.192	1.192
Min	1.215	1.216	1.215	1.216	1.216	1.219
Average	1.216	1.217	1.217	1.218	1.219	1.221
Max	1.218	1.218	1.219	1.221	1.220	1.224
UL	1.228	1.228	1.228	1.228	1.228	1.228

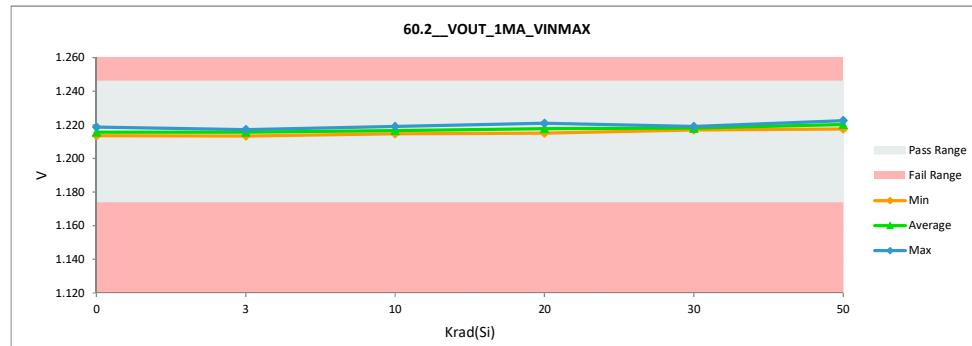


TID LDR Data (Biased)
TPS73801-SEP

60.2_VOUT_1MA_VINMAX				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.246	1.246		
Min Limit	1.174	1.174		
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.212	1.214	0.001
0	69	1.216	1.219	0.003
0	70	1.211	1.215	0.003
3	1	1.214	1.217	0.003
3	2	1.211	1.213	0.002
3	3	1.217	1.216	-0.001
3	4	1.214	1.216	0.002
3	5	1.215	1.217	0.001
10	11	1.211	1.216	0.005
10	12	1.215	1.218	0.003
10	13	1.216	1.219	0.003
10	14	1.211	1.215	0.004
10	15	1.216	1.215	0.000
20	41	1.210	1.217	0.007
20	42	1.213	1.217	0.004
20	43	1.213	1.217	0.005
20	44	1.211	1.217	0.007
20	45	1.214	1.219	0.005
20	46	1.214	1.221	0.007
20	47	1.215	1.221	0.006
20	48	1.216	1.217	0.001
20	49	1.211	1.215	0.004
20	50	1.211	1.217	0.006
20	51	1.213	1.219	0.006
20	52	1.216	1.217	0.001
20	53	1.211	1.217	0.006
20	54	1.215	1.218	0.003
20	55	1.211	1.217	0.007
20	56	1.215	1.220	0.005
20	57	1.215	1.217	0.002
20	58	1.210	1.216	0.006
20	59	1.218	1.220	0.003
20	60	1.212	1.220	0.007
20	61	1.215	1.215	0.000
20	62	1.211	1.216	0.004
30	21	1.212	1.217	0.005
30	22	1.213	1.218	0.005
30	23	1.214	1.219	0.005
30	24	1.211	1.217	0.006
30	25	1.214	1.219	0.005
50	31	1.213	1.219	0.006
50	32	1.215	1.220	0.005
50	33	1.216	1.221	0.006
50	34	1.212	1.217	0.006
50	35	1.213	1.223	0.009
Max		1.218	1.223	0.009
Average		1.213	1.218	0.004
Min		1.210	1.213	-0.001
Std Dev		0.002	0.002	0.002

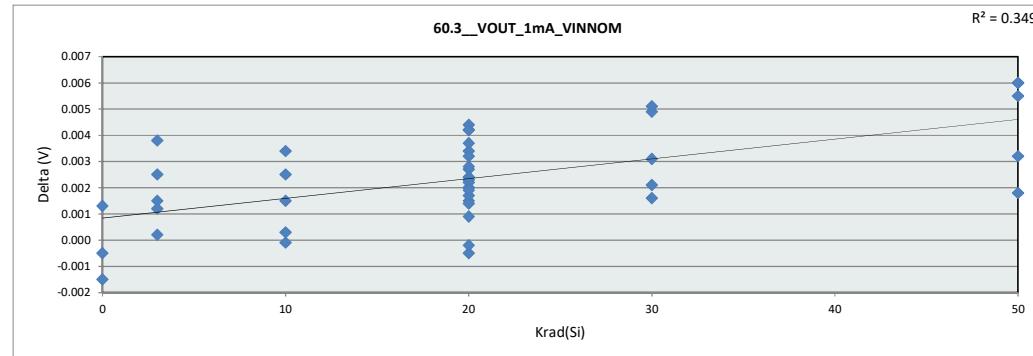


60.2_VOUT_1MA_VINMAX						
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.214	1.213	1.215	1.217	1.218	1.218
Average	1.216	1.216	1.217	1.218	1.218	1.220
Max	1.219	1.217	1.219	1.221	1.219	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246

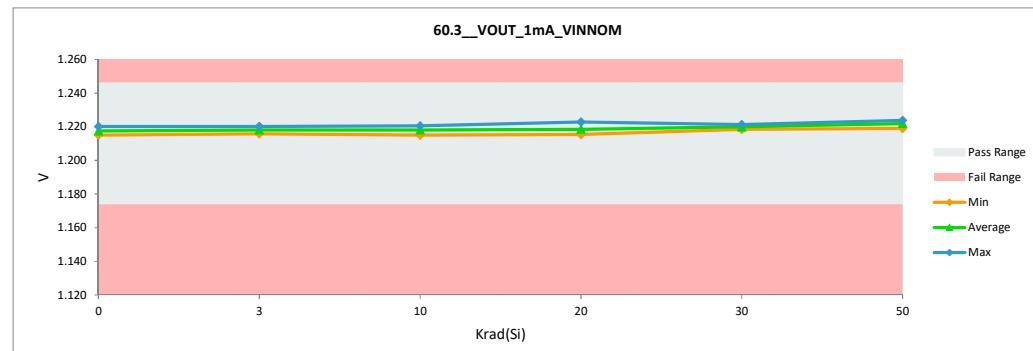


TID LDR Data (Biased)
TPS73801-SEP

60.3_VOUT_1mA_VINNOM				
Test Site	Tester	Test Number	Unit	
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.217	1.215	-0.001
0	69	1.219	1.220	0.001
0	70	1.218	1.217	0.000
3	1	1.215	1.219	0.004
3	2	1.214	1.216	0.002
3	3	1.217	1.218	0.001
3	4	1.217	1.218	0.000
3	5	1.218	1.220	0.002
10	11	1.217	1.219	0.001
10	12	1.218	1.218	0.000
10	13	1.217	1.220	0.003
10	14	1.215	1.215	0.000
10	15	1.215	1.218	0.002
20	41	1.214	1.217	0.002
20	42	1.216	1.218	0.002
20	43	1.218	1.219	0.002
20	44	1.214	1.216	0.002
20	45	1.218	1.221	0.003
20	46	1.219	1.221	0.002
20	47	1.221	1.223	0.002
20	48	1.214	1.217	0.003
20	49	1.213	1.217	0.004
20	50	1.216	1.215	-0.001
20	51	1.216	1.219	0.003
20	52	1.215	1.219	0.004
20	53	1.218	1.217	0.000
20	54	1.217	1.220	0.004
20	55	1.215	1.217	0.002
20	56	1.218	1.220	0.002
20	57	1.215	1.217	0.001
20	58	1.215	1.217	0.002
20	59	1.219	1.222	0.003
20	60	1.217	1.221	0.004
20	61	1.214	1.216	0.002
20	62	1.216	1.217	0.001
30	21	1.216	1.218	0.002
30	22	1.216	1.221	0.005
30	23	1.217	1.219	0.002
30	24	1.216	1.221	0.005
30	25	1.217	1.220	0.003
50	31	1.216	1.222	0.006
50	32	1.216	1.222	0.006
50	33	1.220	1.222	0.002
50	34	1.216	1.219	0.003
50	35	1.218	1.224	0.005
Max		1.221	1.224	0.006
Average		1.217	1.219	0.002
Min		1.213	1.215	-0.001
Std Dev		0.002	0.002	0.002

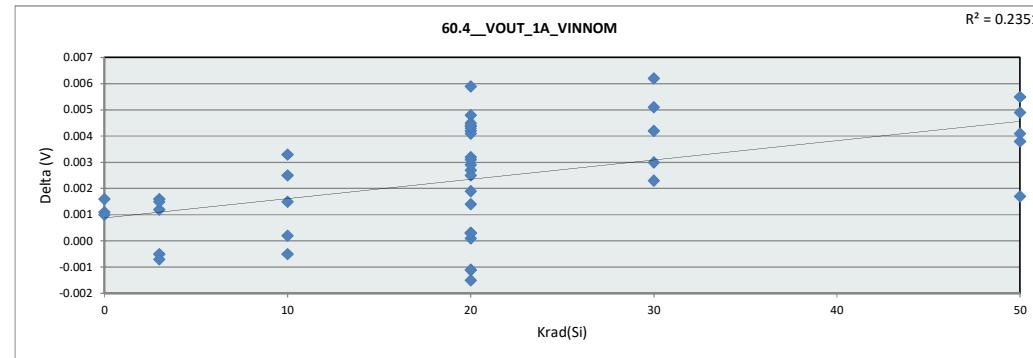


60.3_VOUT_1mA_VINNOM						
Test Site	Tester	Test Number	Max Limit	V	Min Limit	V
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.216	1.215	1.218	1.219	1.219
Average	1.218	1.218	1.218	1.218	1.220	1.222
Max	1.220	1.220	1.221	1.223	1.221	1.224
UL	1.246	1.246	1.246	1.246	1.246	1.246

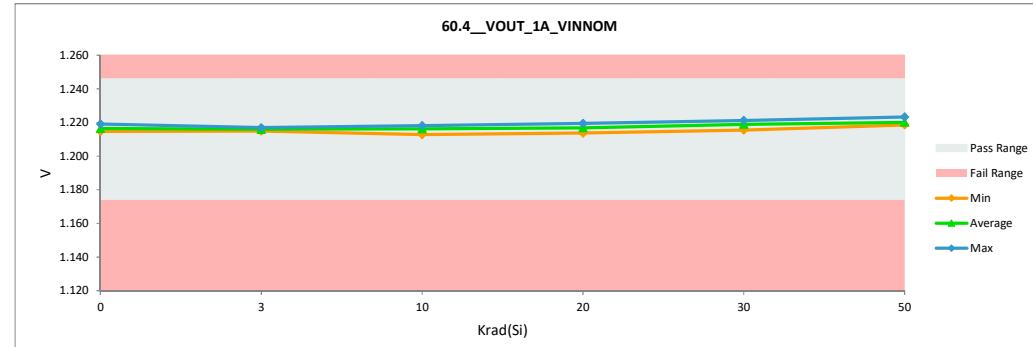


TID LDR Data (Biased)
TPS73801-SEP

60.4_VOUT_1A_VINNOM				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.246	1.246		
Min Limit	1.174	1.174		
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.214	1.215	0.002
0	69	1.218	1.219	0.001
0	70	1.214	1.215	0.001
3	1	1.215	1.216	0.002
3	2	1.214	1.215	0.001
3	3	1.215	1.217	0.002
3	4	1.216	1.216	0.000
3	5	1.217	1.216	-0.001
10	11	1.215	1.218	0.002
10	12	1.216	1.216	0.000
10	13	1.217	1.218	0.002
10	14	1.213	1.213	0.000
10	15	1.214	1.217	0.003
20	41	1.212	1.217	0.005
20	42	1.214	1.218	0.005
20	43	1.214	1.217	0.003
20	44	1.211	1.217	0.006
20	45	1.214	1.219	0.004
20	46	1.215	1.219	0.004
20	47	1.219	1.219	0.000
20	48	1.216	1.216	0.000
20	49	1.214	1.217	0.003
20	50	1.215	1.215	0.000
20	51	1.217	1.217	0.000
20	52	1.216	1.217	0.001
20	53	1.213	1.217	0.004
20	54	1.218	1.217	-0.001
20	55	1.212	1.217	0.004
20	56	1.215	1.218	0.003
20	57	1.213	1.215	0.002
20	58	1.215	1.214	-0.001
20	59	1.216	1.218	0.002
20	60	1.213	1.217	0.004
20	61	1.211	1.214	0.003
20	62	1.215	1.214	-0.001
30	21	1.213	1.215	0.002
30	22	1.215	1.219	0.004
30	23	1.216	1.221	0.005
30	24	1.216	1.219	0.003
30	25	1.215	1.221	0.006
50	31	1.215	1.219	0.004
50	32	1.217	1.219	0.002
50	33	1.218	1.223	0.005
50	34	1.215	1.220	0.004
50	35	1.216	1.220	0.005
Max		1.219	1.223	0.006
Average		1.215	1.217	0.002
Min		1.211	1.213	-0.001
Std Dev		0.002	0.002	0.002



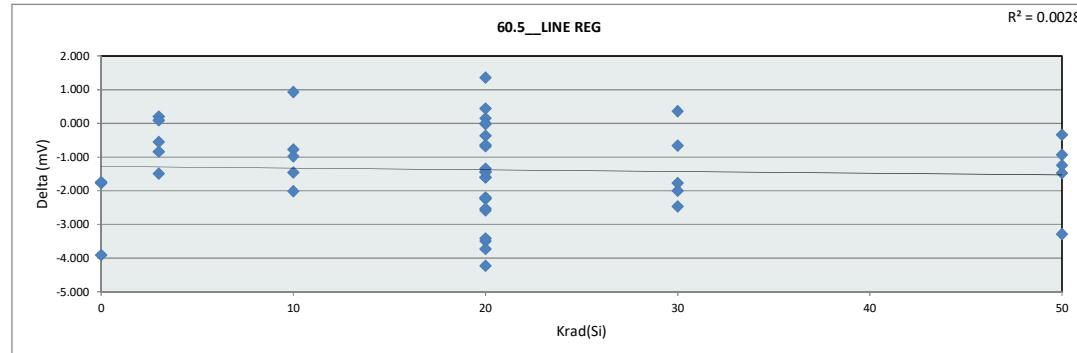
60.4_VOUT_1A_VINNOM						
Test Site						
Tester						
Test Number						
Max Limit	1.246	V				
Min Limit	1.174	V				
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.215	1.213	1.214	1.216	1.219
Average	1.216	1.216	1.216	1.217	1.219	1.220
Max	1.219	1.217	1.218	1.219	1.221	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246



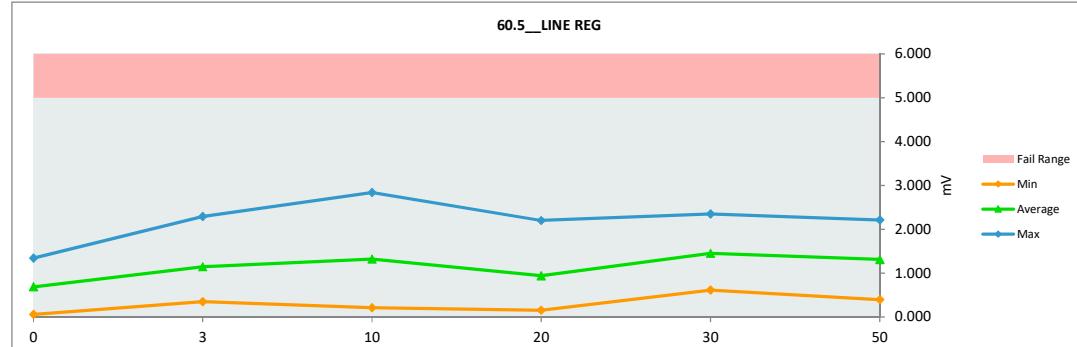
TID LDR Data (Biased)

TPS73801-SEP

60.5 LINE REG					
Test Site					
Tester					
Test Number					
Unit	mV	mV			
Max Limit	5	5			
Min Limit					
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	3.112	1.342	-1.771	
0	69	2.410	0.666	-1.744	
0	70	3.971	0.060	-3.912	
3	1	1.480	0.928	-0.552	
3	2	3.136	2.293	-0.843	
3	3	0.151	0.349	0.198	
3	4	2.809	1.314	-1.495	
3	5	0.758	0.842	0.084	
10	11	4.301	2.840	-1.461	
10	12	2.370	1.597	-0.773	
10	13	1.196	0.213	-0.982	
10	14	2.256	0.239	-2.017	
10	15	0.776	1.707	0.931	
20	41	2.776	0.191	-2.586	
20	42	1.535	1.973	0.439	
20	43	4.156	0.655	-3.501	
20	44	2.761	1.160	-1.601	
20	45	3.692	1.450	-2.242	
20	46	3.381	0.843	-2.538	
20	47	4.384	0.157	-4.227	
20	48	0.563	0.541	-0.022	
20	49	1.333	0.961	-0.373	
20	50	3.278	1.057	-2.221	
20	51	2.367	0.912	-1.455	
20	52	0.474	0.621	0.147	
20	53	4.301	0.885	-3.416	
20	54	2.247	1.564	-0.682	
20	55	4.088	0.356	-3.732	
20	56	2.339	0.734	-1.605	
20	57	0.846	2.202	1.355	
20	58	2.779	1.337	-1.442	
20	59	0.719	0.713	-0.006	
20	60	2.504	0.304	-2.200	
20	61	1.007	0.366	-0.641	
20	62	3.051	1.708	-1.343	
30	21	1.888	1.224	-0.663	
30	22	3.347	1.573	-1.774	
30	23	3.084	0.614	-2.470	
30	24	4.348	2.348	-2.000	
30	25	1.132	1.494	0.362	
50	31	3.422	1.944	-1.478	
50	32	0.739	0.395	-0.344	
50	33	3.458	2.213	-1.245	
50	34	2.168	1.232	-0.936	
50	35	4.054	0.765	-3.288	
Max		4.384	2.840	1.355	
Average		2.466	1.086	-1.379	
Min		0.151	0.060	-4.227	
Std Dev		1.247	0.687	1.306	

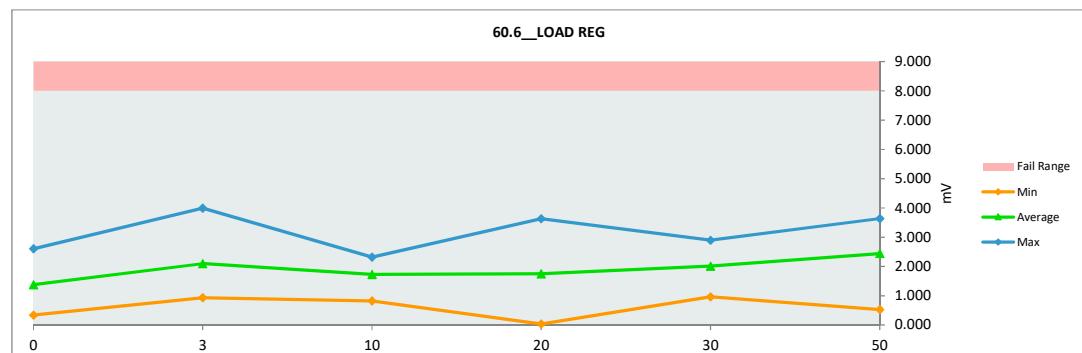
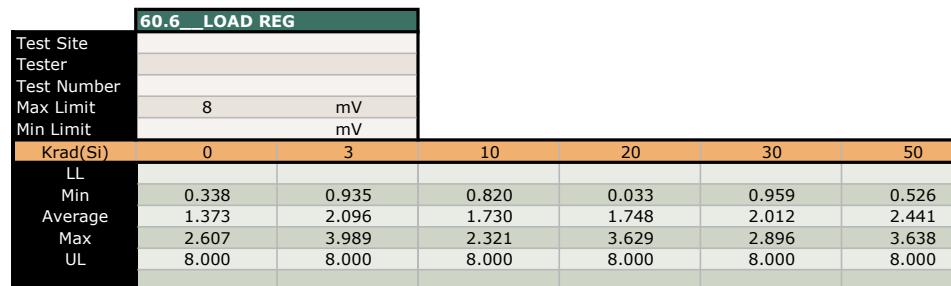
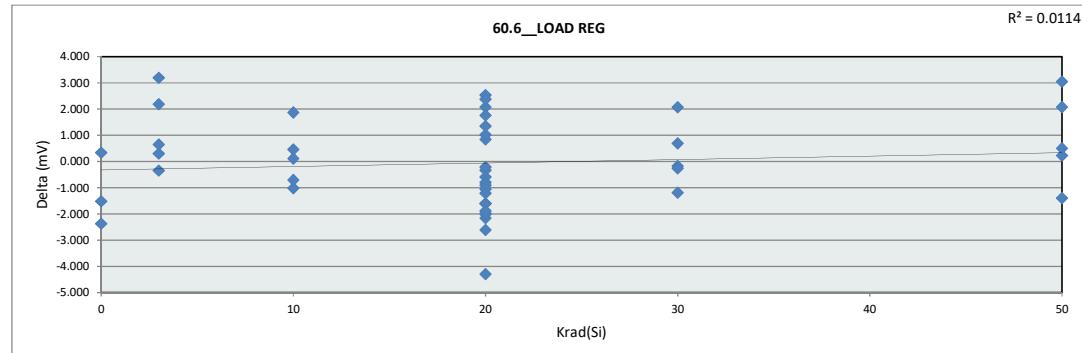


60.5 LINE REG						
Test Site						
Tester						
Test Number						
Max Limit	5	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.060	0.349	0.213	0.157	0.614	0.395
Average	0.689	1.145	1.319	0.940	1.451	1.310
Max	1.342	2.293	2.840	2.202	2.348	2.213
UL	5.000	5.000	5.000	5.000	5.000	5.000



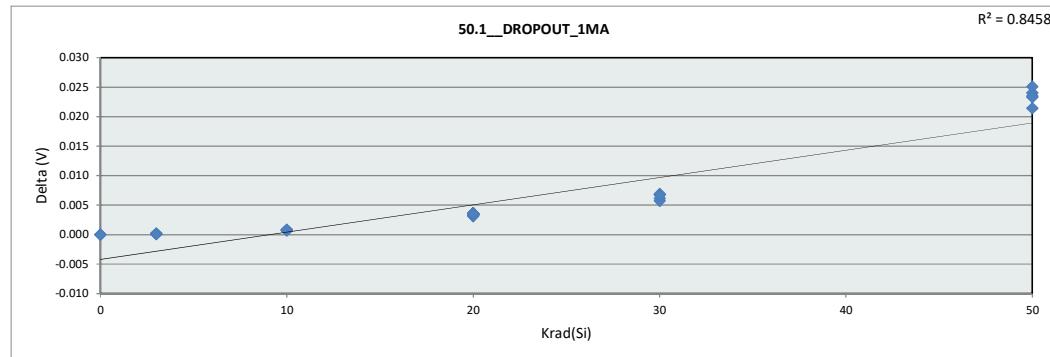
TID LDR Data (Biased)
TPS73801-SEP

60.6 LOAD REG				
Test Site				
Tester				
Test Number				
Unit	mV	mV		
Max Limit	8	8		
Min Limit				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	2.708	0.338	-2.370
0	69	0.831	1.174	0.343
0	70	4.126	2.607	-1.518
3	1	0.404	2.589	2.185
3	2	0.630	0.935	0.305
3	3	1.391	1.042	-0.349
3	4	1.279	1.925	0.646
3	5	0.792	3.989	3.197
10	11	2.188	1.176	-1.012
10	12	1.993	2.108	0.115
10	13	0.448	2.321	1.873
10	14	1.766	2.223	0.457
10	15	1.525	0.820	-0.705
20	41	2.263	0.104	-2.158
20	42	2.043	0.033	-2.011
20	43	3.869	2.265	-1.604
20	44	2.921	0.940	-1.981
20	45	3.856	2.256	-1.600
20	46	3.681	1.792	-1.889
20	47	1.269	3.344	2.075
20	48	1.813	1.223	-0.590
20	49	0.951	0.617	-0.335
20	50	1.066	0.268	-0.798
20	51	0.792	1.641	0.849
20	52	1.004	2.025	1.021
20	53	4.688	0.389	-4.299
20	54	1.531	3.292	1.761
20	55	2.762	0.147	-2.615
20	56	2.305	1.400	-0.905
20	57	2.167	1.116	-1.052
20	58	0.290	2.825	2.535
20	59	2.281	3.629	1.348
20	60	3.827	3.616	-0.211
20	61	3.310	2.095	-1.215
20	62	1.056	3.434	2.378
30	21	3.067	2.896	-0.171
30	22	1.237	1.930	0.693
30	23	1.948	1.691	-0.257
30	24	0.520	2.586	2.066
30	25	2.150	0.959	-1.191
50	31	1.529	3.609	2.079
50	32	0.589	3.638	3.049
50	33	2.546	1.154	-1.392
50	34	0.293	0.526	0.233
50	35	2.776	3.277	0.502
Max		4.688	3.989	3.197
Average		1.922	1.866	-0.056
Min		0.290	0.033	-4.299
Std Dev		1.152	1.136	1.687

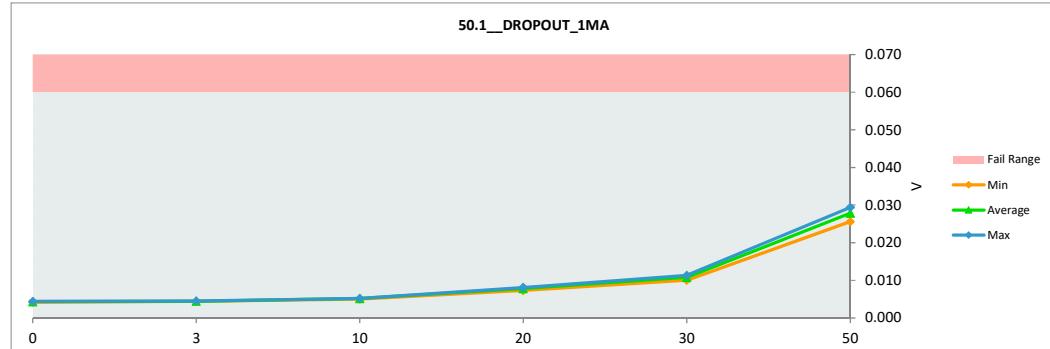


TID LDR Data (Biased)
TPS73801-SEP

50.1_DROPOUT_1MA					
Test Site	Tester	Test Number	Unit	Max Limit	Min Limit
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	0.004	0.004	0.000	
0	69	0.004	0.004	0.000	
0	70	0.004	0.004	0.000	
3	1	0.004	0.004	0.000	
3	2	0.004	0.004	0.000	
3	3	0.004	0.004	0.000	
3	4	0.004	0.004	0.000	
3	5	0.004	0.004	0.000	
10	11	0.004	0.005	0.001	
10	12	0.004	0.005	0.001	
10	13	0.004	0.005	0.001	
10	14	0.004	0.005	0.001	
10	15	0.004	0.005	0.001	
20	41	0.004	0.007	0.003	
20	42	0.004	0.008	0.003	
20	43	0.004	0.008	0.003	
20	44	0.004	0.008	0.003	
20	45	0.004	0.008	0.004	
20	46	0.004	0.008	0.003	
20	47	0.004	0.008	0.003	
20	48	0.004	0.008	0.003	
20	49	0.004	0.007	0.003	
20	50	0.004	0.008	0.003	
20	51	0.004	0.007	0.003	
20	52	0.004	0.008	0.003	
20	53	0.004	0.008	0.003	
20	54	0.004	0.008	0.003	
20	55	0.004	0.008	0.004	
20	56	0.004	0.008	0.003	
20	57	0.004	0.008	0.004	
20	58	0.004	0.008	0.004	
20	59	0.004	0.008	0.004	
20	60	0.005	0.008	0.004	
20	61	0.004	0.008	0.003	
20	62	0.004	0.008	0.003	
30	21	0.004	0.010	0.006	
30	22	0.004	0.011	0.007	
30	23	0.004	0.010	0.006	
30	24	0.004	0.011	0.007	
30	25	0.004	0.011	0.007	
50	31	0.005	0.029	0.024	
50	32	0.004	0.028	0.023	
50	33	0.004	0.026	0.021	
50	34	0.004	0.028	0.023	
50	35	0.004	0.029	0.025	
Max		0.005	0.029	0.025	
Average		0.004	0.009	0.005	
Min		0.004	0.004	0.000	
Std Dev		0.000	0.007	0.007	



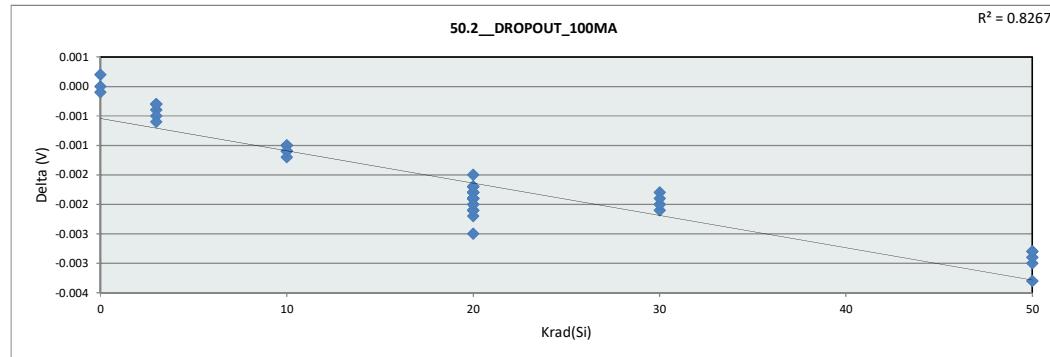
50.1_DROPOUT_1MA					
Test Site	Tester	Test Number	Unit	Max Limit	Min Limit
Krad(Si)	0	3	10	20	30
LL					
Min	0.004	0.004	0.005	0.007	0.010
Average	0.004	0.004	0.005	0.008	0.011
Max	0.004	0.005	0.005	0.008	0.011
UL	0.060	0.060	0.060	0.060	0.060



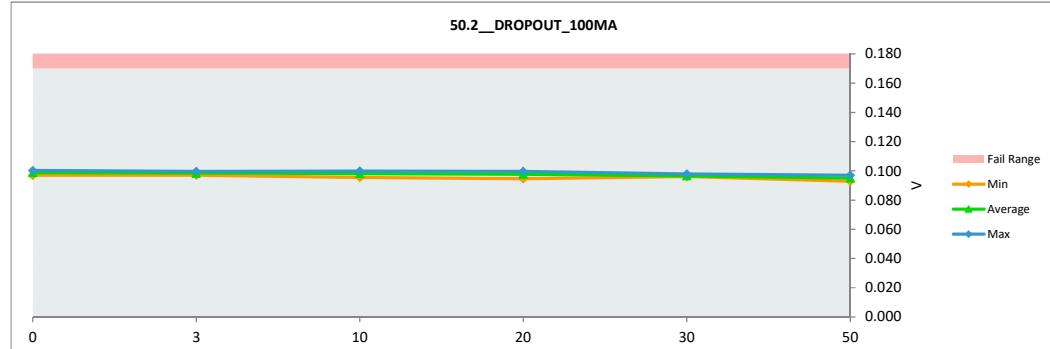
TID LDR Data (Biased)

TPS73801-SEP

50.2_DROPOUT_100MA					
Test Site	Tester			Unit	
		V	V	Max Limit	Min Limit
		0.17	0.17		
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	0.100	0.100	0.000	
0	69	0.097	0.097	0.000	
0	70	0.099	0.099	0.000	
3	1	0.098	0.098	0.000	
3	2	0.100	0.100	0.000	
3	3	0.100	0.100	-0.001	
3	4	0.099	0.098	0.000	
3	5	0.097	0.097	-0.001	
10	11	0.099	0.098	-0.001	
10	12	0.098	0.097	-0.001	
10	13	0.097	0.095	-0.001	
10	14	0.101	0.100	-0.001	
10	15	0.101	0.100	-0.001	
20	41	0.101	0.099	-0.002	
20	42	0.098	0.097	-0.002	
20	43	0.100	0.098	-0.002	
20	44	0.101	0.099	-0.002	
20	45	0.097	0.095	-0.002	
20	46	0.098	0.096	-0.002	
20	47	0.096	0.095	-0.002	
20	48	0.100	0.097	-0.002	
20	49	0.101	0.098	-0.003	
20	50	0.101	0.099	-0.002	
20	51	0.099	0.097	-0.002	
20	52	0.099	0.097	-0.002	
20	53	0.100	0.098	-0.002	
20	54	0.099	0.097	-0.002	
20	55	0.100	0.098	-0.002	
20	56	0.099	0.097	-0.001	
20	57	0.101	0.099	-0.002	
20	58	0.102	0.100	-0.002	
20	59	0.097	0.095	-0.002	
20	60	0.100	0.098	-0.002	
20	61	0.101	0.100	-0.002	
20	62	0.100	0.098	-0.002	
30	21	0.100	0.098	-0.002	
30	22	0.098	0.096	-0.002	
30	23	0.098	0.096	-0.002	
30	24	0.098	0.097	-0.002	
30	25	0.098	0.096	-0.002	
50	31	0.099	0.096	-0.003	
50	32	0.098	0.095	-0.003	
50	33	0.096	0.093	-0.003	
50	34	0.100	0.097	-0.003	
50	35	0.097	0.094	-0.003	
Max		0.102	0.100	0.000	
Average		0.099	0.097	-0.002	
Min		0.096	0.093	-0.003	
Std Dev		0.001	0.002	0.001	

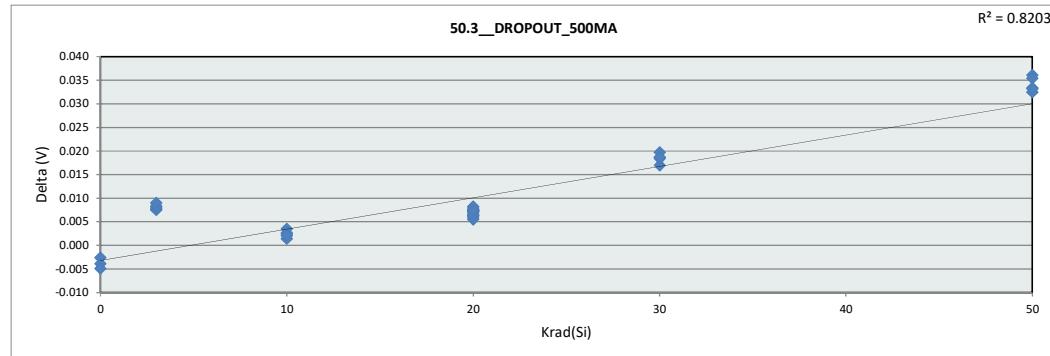


50.2_DROPOUT_100MA						
Test Site	Tester			Unit		
		Max Limit	Min Limit		LL	UL
		0.17	V		0	50
Average		0.099	0.097	0.095	0.095	0.093
Min		0.097	0.095	0.095	0.096	0.093
Max		0.100	0.100	0.100	0.100	0.097

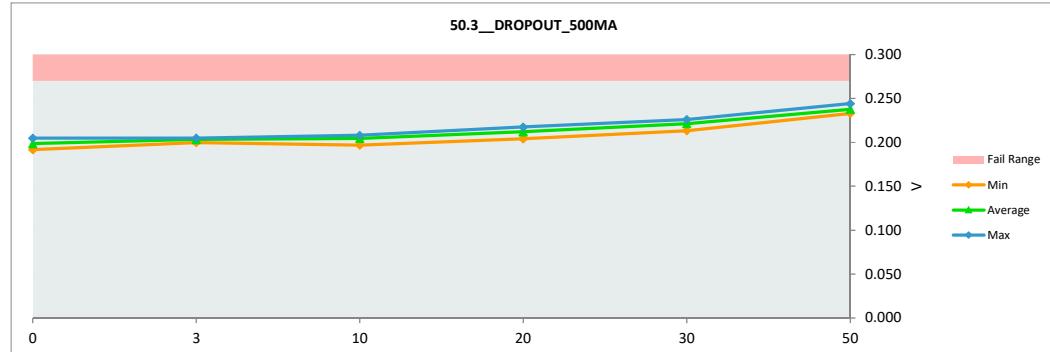


TID LDR Data (Biased)
TPS73801-SEP

50.3_DROPOUT_500MA				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	0.27	0.27		
Min Limit				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.207	0.205	-0.003
0	69	0.196	0.192	-0.004
0	70	0.205	0.200	-0.005
3	1	0.196	0.203	0.007
3	2	0.196	0.203	0.008
3	3	0.192	0.200	0.008
3	4	0.196	0.204	0.008
3	5	0.196	0.205	0.009
10	11	0.203	0.207	0.003
10	12	0.201	0.203	0.002
10	13	0.194	0.197	0.003
10	14	0.207	0.208	0.001
10	15	0.206	0.208	0.002
20	41	0.200	0.207	0.007
20	42	0.206	0.212	0.006
20	43	0.209	0.217	0.008
20	44	0.203	0.209	0.007
20	45	0.204	0.211	0.007
20	46	0.206	0.212	0.006
20	47	0.204	0.211	0.006
20	48	0.206	0.214	0.007
20	49	0.200	0.207	0.007
20	50	0.208	0.213	0.005
20	51	0.197	0.204	0.007
20	52	0.210	0.215	0.006
20	53	0.202	0.210	0.007
20	54	0.201	0.208	0.008
20	55	0.209	0.218	0.008
20	56	0.205	0.213	0.007
20	57	0.206	0.213	0.008
20	58	0.208	0.216	0.008
20	59	0.206	0.213	0.007
20	60	0.210	0.216	0.006
20	61	0.208	0.214	0.006
20	62	0.203	0.211	0.007
30	21	0.205	0.223	0.019
30	22	0.206	0.226	0.020
30	23	0.196	0.213	0.017
30	24	0.204	0.222	0.018
30	25	0.204	0.223	0.019
50	31	0.208	0.244	0.036
50	32	0.198	0.233	0.035
50	33	0.200	0.233	0.032
50	34	0.203	0.236	0.033
50	35	0.209	0.242	0.033
Max		0.210	0.244	0.036
Average		0.203	0.213	0.010
Min		0.192	0.192	-0.005
Std Dev		0.005	0.011	0.010

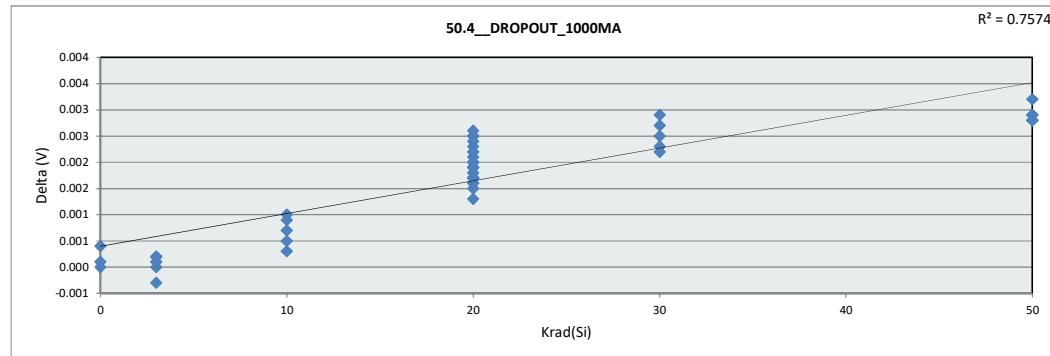


50.3_DROPOUT_500MA						
Test Site						
Tester						
Test Number						
Max Limit	0.27	V				
Min Limit		V				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.192	0.200	0.197	0.204	0.213	0.233
Average	0.199	0.203	0.204	0.212	0.221	0.238
Max	0.205	0.205	0.208	0.218	0.226	0.244
UL	0.270	0.270	0.270	0.270	0.270	0.270

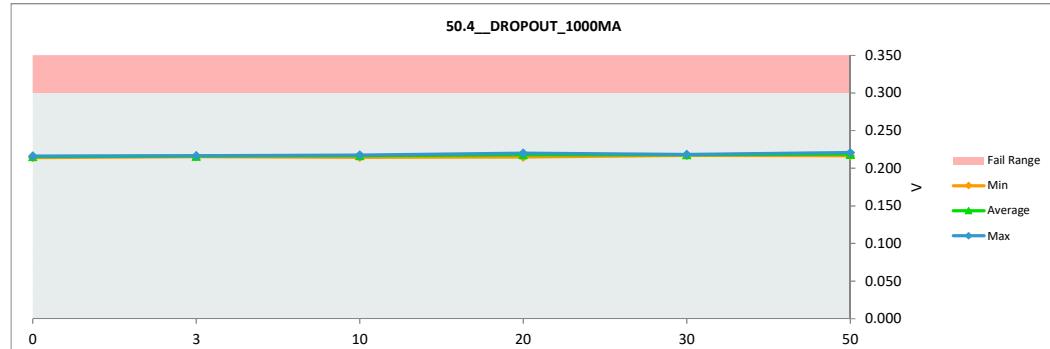


TID LDR Data (Biased)
TPS73801-SEP

50.4_DROPOUT_1000MA					
Test Site	Tester			Unit	
		V	V	Max Limit	Min Limit
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	0.216	0.216	0.000	
0	69	0.214	0.214	0.000	
0	70	0.216	0.216	0.000	
3	1	0.215	0.215	0.000	
3	2	0.216	0.217	0.000	
3	3	0.216	0.217	0.000	
3	4	0.216	0.216	0.000	
3	5	0.216	0.216	0.000	
10	11	0.216	0.217	0.000	
10	12	0.216	0.217	0.001	
10	13	0.214	0.214	0.000	
10	14	0.217	0.218	0.001	
10	15	0.217	0.218	0.001	
20	41	0.215	0.217	0.002	
20	42	0.215	0.217	0.002	
20	43	0.217	0.219	0.002	
20	44	0.216	0.218	0.002	
20	45	0.214	0.216	0.002	
20	46	0.216	0.218	0.002	
20	47	0.215	0.218	0.002	
20	48	0.216	0.218	0.002	
20	49	0.214	0.215	0.001	
20	50	0.217	0.218	0.001	
20	51	0.215	0.216	0.002	
20	52	0.215	0.218	0.002	
20	53	0.216	0.218	0.002	
20	54	0.216	0.218	0.002	
20	55	0.216	0.219	0.002	
20	56	0.217	0.219	0.003	
20	57	0.216	0.218	0.002	
20	58	0.217	0.219	0.002	
20	59	0.215	0.217	0.002	
20	60	0.218	0.220	0.002	
20	61	0.217	0.219	0.002	
20	62	0.215	0.217	0.002	
30	21	0.216	0.218	0.002	
30	22	0.216	0.218	0.002	
30	23	0.215	0.217	0.002	
30	24	0.215	0.218	0.003	
30	25	0.216	0.218	0.003	
50	31	0.218	0.221	0.003	
50	32	0.216	0.219	0.003	
50	33	0.214	0.217	0.003	
50	34	0.216	0.219	0.003	
50	35	0.215	0.219	0.003	
Max		0.218	0.221	0.003	
Average		0.216	0.217	0.002	
Min		0.214	0.214	0.000	
Std Dev		0.001	0.001	0.001	

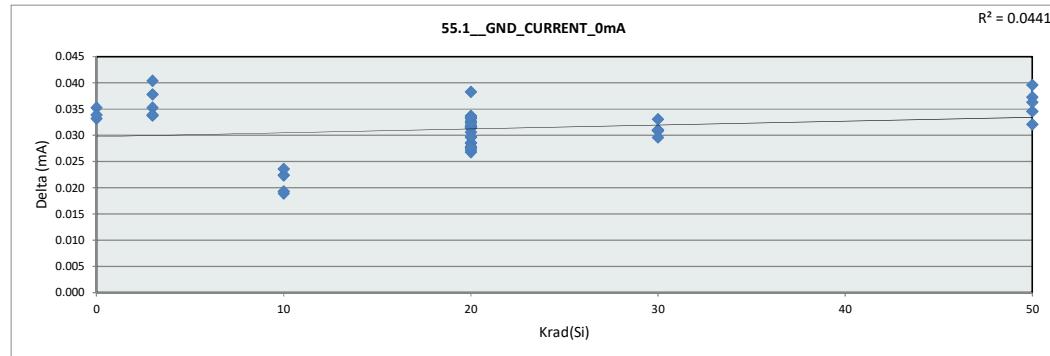


50.4_DROPOUT_1000MA						
Test Site	Tester			Unit		
		Max Limit	Min Limit		LL	UL
Krad(Si)	Serial #	0.3	V		0	50
LL		0.214	0.215	0.215	0.217	0.217
Min		0.214	0.215	0.215	0.216	0.219
Average		0.215	0.216	0.217	0.217	0.219
Max		0.216	0.217	0.218	0.220	0.221
UL		0.300	0.300	0.300	0.300	0.300

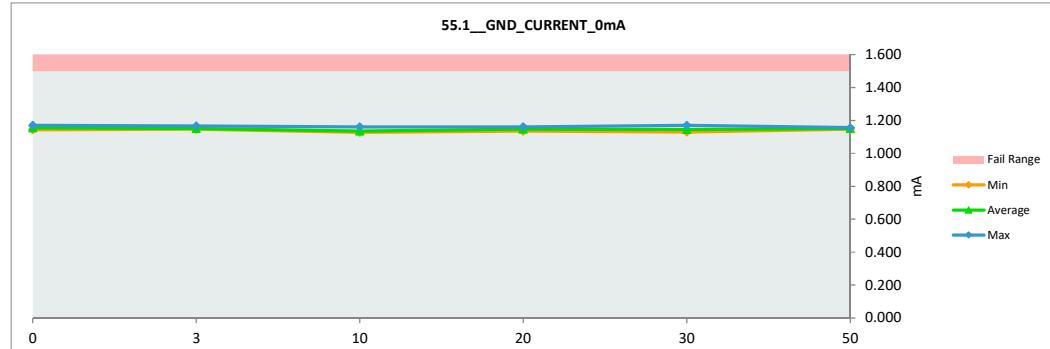


TID LDR Data (Biased)
TPS73801-SEP

55.1_GND_CURRENT_0mA					
Test Site	Tester				
Test Number					
Unit		mA	mA		
Max Limit		1.5	1.5		
Min Limit					
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	1.110	1.144	0.033	
0	69	1.135	1.170	0.035	
0	70	1.118	1.152	0.034	
3	1	1.110	1.146	0.035	
3	2	1.115	1.149	0.034	
3	3	1.126	1.166	0.040	
3	4	1.110	1.147	0.038	
3	5	1.112	1.146	0.034	
10	11	1.111	1.130	0.019	
10	12	1.112	1.132	0.019	
10	13	1.139	1.161	0.022	
10	14	1.105	1.128	0.022	
10	15	1.107	1.131	0.024	
20	41	1.129	1.161	0.032	
20	42	1.113	1.151	0.038	
20	43	1.114	1.148	0.034	
20	44	1.111	1.144	0.033	
20	45	1.113	1.145	0.032	
20	46	1.123	1.151	0.028	
20	47	1.119	1.151	0.032	
20	48	1.107	1.140	0.033	
20	49	1.131	1.160	0.029	
20	50	1.107	1.134	0.027	
20	51	1.130	1.160	0.030	
20	52	1.112	1.142	0.031	
20	53	1.115	1.147	0.032	
20	54	1.109	1.140	0.031	
20	55	1.112	1.145	0.033	
20	56	1.123	1.155	0.032	
20	57	1.113	1.147	0.033	
20	58	1.117	1.144	0.027	
20	59	1.113	1.141	0.028	
20	60	1.112	1.140	0.028	
20	61	1.110	1.140	0.030	
20	62	1.118	1.146	0.028	
30	21	1.111	1.142	0.031	
30	22	1.109	1.142	0.033	
30	23	1.139	1.170	0.031	
30	24	1.110	1.141	0.031	
30	25	1.100	1.130	0.030	
50	31	1.115	1.154	0.040	
50	32	1.114	1.148	0.035	
50	33	1.112	1.149	0.037	
50	34	1.115	1.148	0.032	
50	35	1.120	1.156	0.036	
Max		1.139	1.170	0.040	
Average		1.116	1.147	0.031	
Min		1.100	1.128	0.019	
Std Dev		0.009	0.010	0.005	



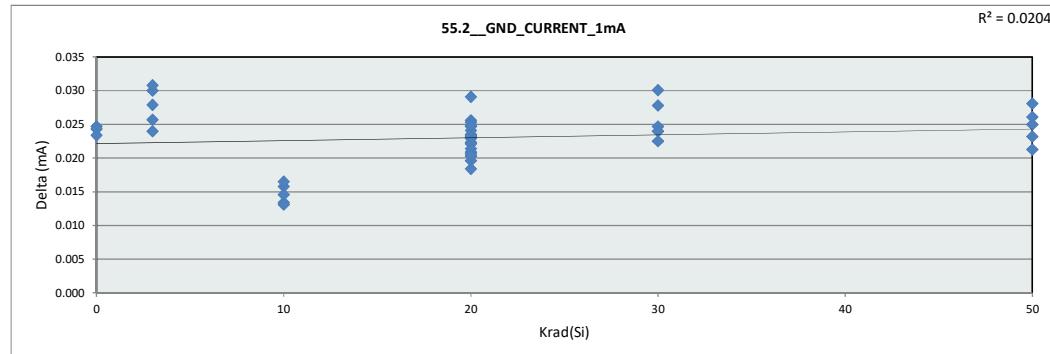
55.1_GND_CURRENT_0mA						
Test Site	Tester					
Test Number						
Max Limit		1.5	mA			
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL	1.144	1.146	1.128	1.134	1.130	1.148
Min	1.155	1.151	1.136	1.147	1.145	1.151
Average	1.170	1.166	1.161	1.161	1.170	1.156
Max	1.500	1.500	1.500	1.500	1.500	1.500
UL						



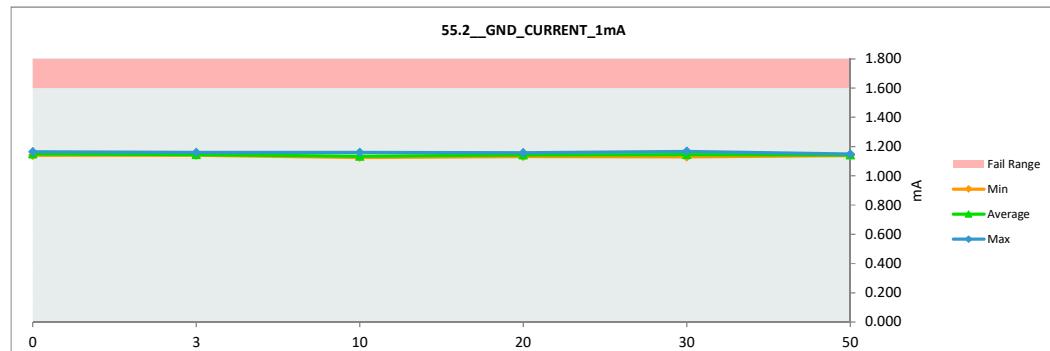
TID LDR Data (Biased)

TPS73801-SEP

55.2_GND_CURRENT_1mA					
Test Site	Tester	Test Number	Unit	Max Limit	Min Limit
				mA	mA
				1.6	1.6
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	1.115	1.140	0.025	
0	69	1.140	1.164	0.024	
0	70	1.123	1.146	0.023	
3	1	1.113	1.141	0.028	
3	2	1.119	1.143	0.024	
3	3	1.130	1.160	0.030	
3	4	1.112	1.143	0.031	
3	5	1.117	1.142	0.026	
10	11	1.115	1.129	0.013	
10	12	1.116	1.129	0.013	
10	13	1.145	1.160	0.016	
10	14	1.111	1.125	0.015	
10	15	1.112	1.129	0.016	
20	41	1.135	1.158	0.023	
20	42	1.117	1.146	0.029	
20	43	1.121	1.144	0.022	
20	44	1.115	1.139	0.024	
20	45	1.118	1.141	0.023	
20	46	1.128	1.148	0.020	
20	47	1.124	1.146	0.022	
20	48	1.112	1.135	0.023	
20	49	1.136	1.158	0.022	
20	50	1.111	1.132	0.021	
20	51	1.135	1.156	0.021	
20	52	1.116	1.139	0.023	
20	53	1.117	1.143	0.026	
20	54	1.114	1.139	0.025	
20	55	1.117	1.141	0.024	
20	56	1.127	1.152	0.025	
20	57	1.119	1.144	0.025	
20	58	1.122	1.140	0.018	
20	59	1.118	1.139	0.021	
20	60	1.117	1.139	0.021	
20	61	1.116	1.136	0.020	
20	62	1.122	1.142	0.020	
30	21	1.115	1.143	0.028	
30	22	1.113	1.143	0.030	
30	23	1.145	1.168	0.023	
30	24	1.115	1.139	0.025	
30	25	1.104	1.128	0.024	
50	31	1.120	1.148	0.028	
50	32	1.117	1.140	0.023	
50	33	1.116	1.142	0.026	
50	34	1.118	1.140	0.021	
50	35	1.124	1.149	0.025	
Max		1.145	1.168	0.031	
Average		1.120	1.143	0.023	
Min		1.104	1.125	0.013	
Std Dev		0.009	0.009	0.004	

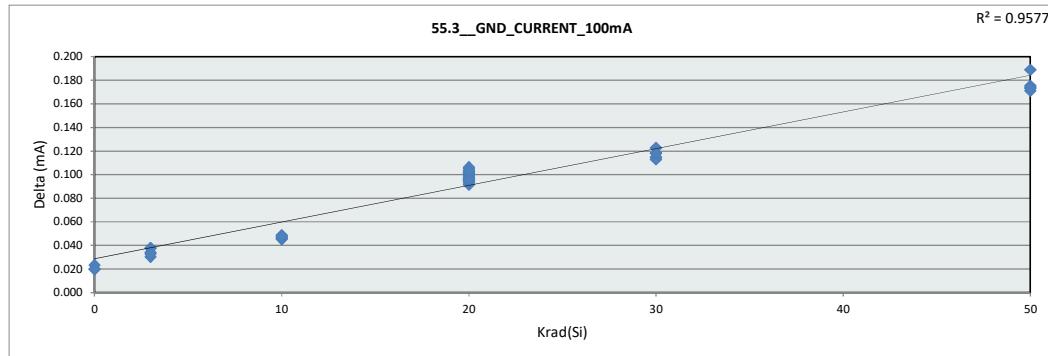


55.2_GND_CURRENT_1mA					
Test Site	Tester	Test Number	Unit	Max Limit	Min Limit
				mA	mA
Krad(Si)	0	3	10	20	30
LL	1.140	1.141	1.125	1.132	1.128
Min	1.140	1.141	1.125	1.132	1.140
Average	1.150	1.146	1.134	1.143	1.144
Max	1.164	1.160	1.160	1.158	1.168
UL	1.600	1.600	1.600	1.600	1.149

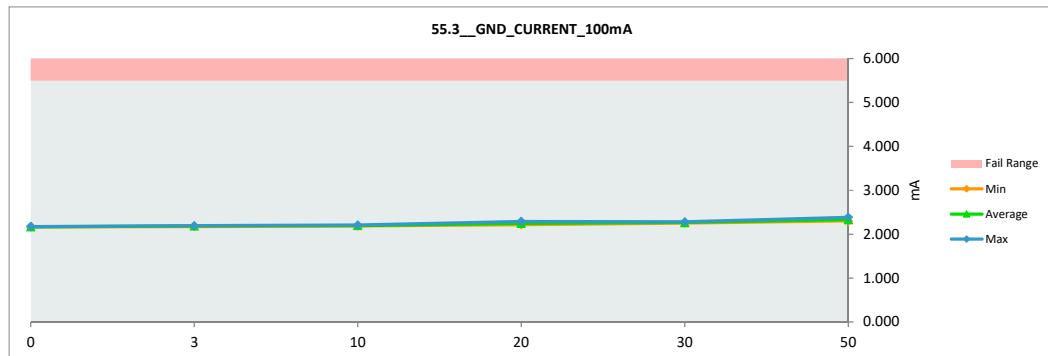


TID LDR Data (Biased)
TPS73801-SEP

55.3_GND_CURRENT_100mA					
Test Site					
Tester					
Test Number					
Unit	mA	mA			
Max Limit	5.5	5.5			
Min Limit					
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	2.146	2.165	0.020	
0	69	2.141	2.165	0.023	
0	70	2.156	2.176	0.020	
3	1	2.141	2.175	0.034	
3	2	2.153	2.183	0.030	
3	3	2.150	2.188	0.038	
3	4	2.149	2.187	0.037	
3	5	2.163	2.196	0.033	
10	11	2.151	2.197	0.045	
10	12	2.141	2.187	0.046	
10	13	2.160	2.209	0.049	
10	14	2.144	2.190	0.047	
10	15	2.145	2.193	0.048	
20	41	2.135	2.232	0.097	
20	42	2.142	2.246	0.104	
20	43	2.164	2.260	0.096	
20	44	2.132	2.231	0.099	
20	45	2.135	2.231	0.096	
20	46	2.167	2.263	0.097	
20	47	2.167	2.267	0.100	
20	48	2.148	2.248	0.101	
20	49	2.124	2.219	0.095	
20	50	2.141	2.233	0.091	
20	51	2.137	2.230	0.093	
20	52	2.145	2.245	0.101	
20	53	2.145	2.246	0.101	
20	54	2.128	2.230	0.102	
20	55	2.160	2.266	0.105	
20	56	2.187	2.293	0.106	
20	57	2.148	2.251	0.103	
20	58	2.161	2.255	0.094	
20	59	2.144	2.239	0.095	
20	60	2.189	2.291	0.103	
20	61	2.149	2.244	0.095	
20	62	2.145	2.240	0.095	
30	21	2.148	2.262	0.115	
30	22	2.158	2.281	0.123	
30	23	2.155	2.268	0.113	
30	24	2.145	2.263	0.118	
30	25	2.133	2.251	0.118	
50	31	2.198	2.386	0.189	
50	32	2.136	2.311	0.175	
50	33	2.129	2.300	0.171	
50	34	2.145	2.318	0.173	
50	35	2.163	2.337	0.173	
Max		2.198	2.386	0.189	
Average		2.150	2.241	0.091	
Min		2.124	2.165	0.020	
Std Dev		0.015	0.047	0.043	

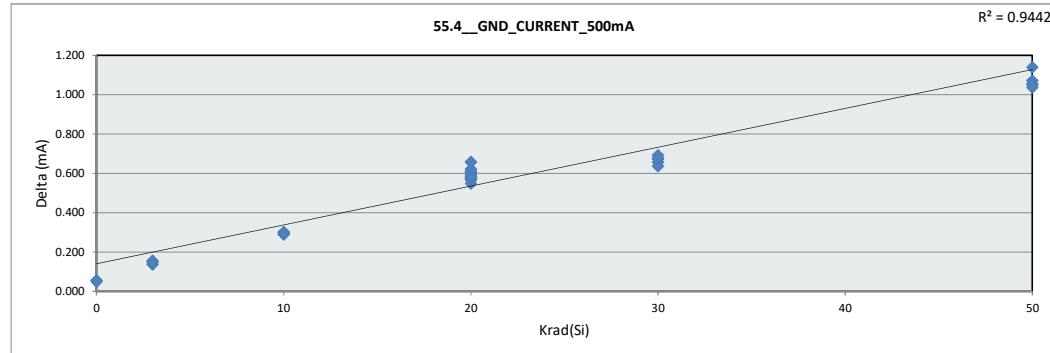


55.3_GND_CURRENT_100mA						
Test Site						
Tester						
Test Number						
Max Limit	5.5	mA				
Min Limit		mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	2.165	2.175	2.187	2.219	2.251	2.300
Average	2.169	2.186	2.195	2.248	2.265	2.330
Max	2.176	2.196	2.209	2.293	2.281	2.386
UL	5.500	5.500	5.500	5.500	5.500	5.500

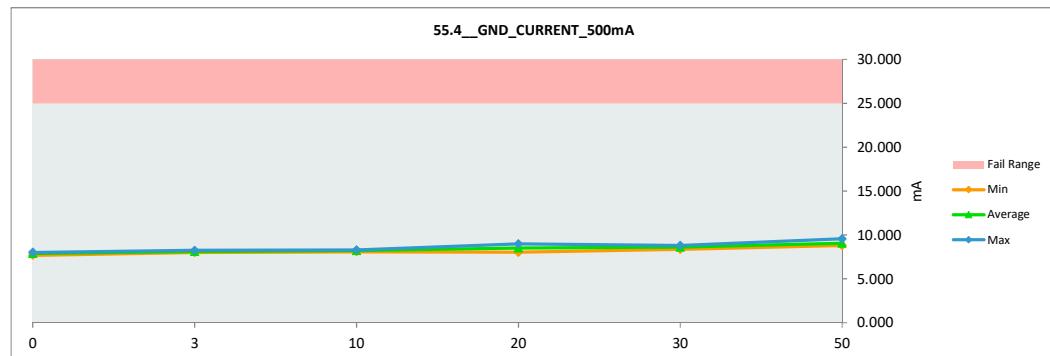


TID LDR Data (Biased)
TPS73801-SEP

55.4_GND_CURRENT_500mA					
Test Site	Tester				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	7.946	7.996	0.049	
0	69	7.633	7.686	0.053	
0	70	7.958	8.015	0.057	
3	1	7.928	8.068	0.139	
3	2	7.940	8.077	0.137	
3	3	7.833	7.986	0.154	
3	4	7.979	8.135	0.156	
3	5	8.086	8.235	0.149	
10	11	7.995	8.286	0.292	
10	12	7.880	8.177	0.297	
10	13	7.784	8.086	0.302	
10	14	8.005	8.295	0.289	
10	15	7.959	8.259	0.299	
20	41	7.597	8.166	0.569	
20	42	7.905	8.497	0.592	
20	43	8.100	8.680	0.581	
20	44	7.814	8.397	0.583	
20	45	7.810	8.393	0.583	
20	46	8.081	8.686	0.605	
20	47	8.043	8.662	0.620	
20	48	7.989	8.597	0.609	
20	49	7.441	8.018	0.577	
20	50	7.960	8.528	0.568	
20	51	7.610	8.158	0.548	
20	52	7.958	8.564	0.606	
20	53	7.908	8.509	0.600	
20	54	7.790	8.388	0.598	
20	55	8.107	8.729	0.622	
20	56	8.217	8.874	0.657	
20	57	7.908	8.517	0.609	
20	58	8.024	8.625	0.601	
20	59	7.905	8.483	0.578	
20	60	8.332	8.991	0.658	
20	61	7.958	8.540	0.581	
20	62	7.860	8.436	0.576	
30	21	7.953	8.611	0.658	
30	22	8.108	8.801	0.693	
30	23	7.725	8.363	0.637	
30	24	7.941	8.615	0.674	
30	25	7.939	8.618	0.679	
50	31	8.418	9.558	1.141	
50	32	7.828	8.901	1.073	
50	33	7.761	8.799	1.038	
50	34	7.893	8.948	1.055	
50	35	8.099	9.150	1.051	
Max		8.418	9.558	1.141	
Average		7.931	8.469	0.538	
Min		7.441	7.686	0.049	
Std Dev		0.179	0.356	0.277	

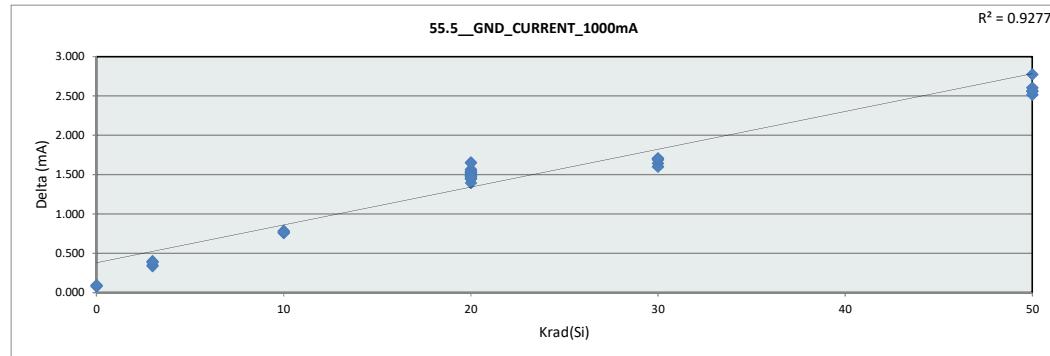


55.4_GND_CURRENT_500mA					
Test Site	Tester				
Krad(Si)	25	mA	mA	mA	mA
LL	0				
Min	3	7.686	7.987	8.086	8.018
Average	10	7.899	8.100	8.221	8.520
Max	20	8.015	8.235	8.295	8.991
UL	30	25.000	25.000	25.000	25.000
	50				

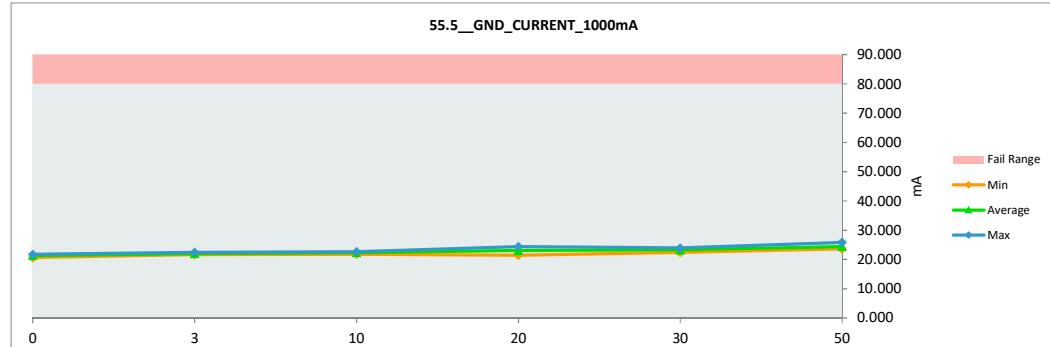


TID LDR Data (Biased)
TPS73801-SEP

55.5_GND_CURRENT_1000mA					
Test Site					
Tester					
Test Number					
Unit					
Max Limit	80	mA			
Min Limit	80	mA			
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	21.636	21.714	0.077	
0	69	20.544	20.630	0.086	
0	70	21.641	21.737	0.096	
3	1	21.579	21.916	0.337	
3	2	21.580	21.926	0.346	
3	3	21.198	21.597	0.399	
3	4	21.743	22.131	0.388	
3	5	22.084	22.472	0.388	
10	11	21.781	22.539	0.758	
10	12	21.405	22.177	0.771	
10	13	21.003	21.787	0.784	
10	14	21.859	22.622	0.762	
10	15	21.690	22.465	0.776	
20	41	20.421	21.870	1.449	
20	42	21.507	23.003	1.496	
20	43	22.124	23.608	1.484	
20	44	21.165	22.647	1.482	
20	45	21.211	22.697	1.487	
20	46	22.066	23.602	1.536	
20	47	21.881	23.447	1.566	
20	48	21.783	23.308	1.525	
20	49	19.929	21.374	1.445	
20	50	21.697	23.148	1.451	
20	51	20.468	21.862	1.395	
20	52	21.703	23.247	1.544	
20	53	21.486	23.020	1.534	
20	54	21.090	22.599	1.510	
20	55	22.152	23.716	1.564	
20	56	22.384	24.035	1.651	
20	57	21.469	23.011	1.542	
20	58	21.856	23.376	1.520	
20	59	21.523	23.001	1.479	
20	60	22.773	24.427	1.654	
20	61	21.647	23.137	1.489	
20	62	21.333	22.799	1.466	
30	21	21.665	23.309	1.644	
30	22	22.172	23.878	1.706	
30	23	20.804	22.404	1.600	
30	24	21.622	23.313	1.691	
30	25	21.663	23.368	1.705	
50	31	23.070	25.845	2.774	
50	32	21.207	23.811	2.604	
50	33	21.061	23.574	2.514	
50	34	21.442	24.001	2.560	
50	35	22.180	24.743	2.563	
Max		23.070	25.845	2.774	
Average		21.562	22.909	1.347	
Min		19.929	20.630	0.077	
Std Dev		0.585	0.974	0.680	

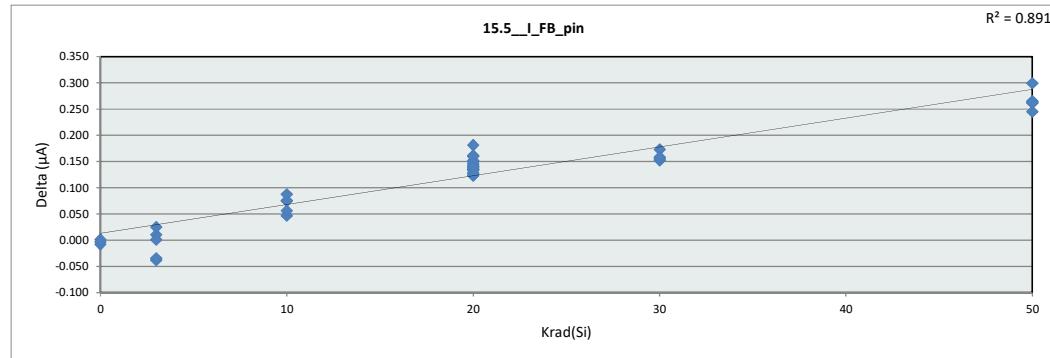


55.5_GND_CURRENT_1000mA						
Test Site						
Tester						
Test Number						
Max Limit	80	mA				
Min Limit	80	mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	20.630	21.597	21.787	21.374	22.404	23.575
Average	21.360	22.008	22.318	23.042	23.254	24.395
Max	21.737	22.472	22.622	24.427	23.878	25.845
UL	80.000	80.000	80.000	80.000	80.000	80.000

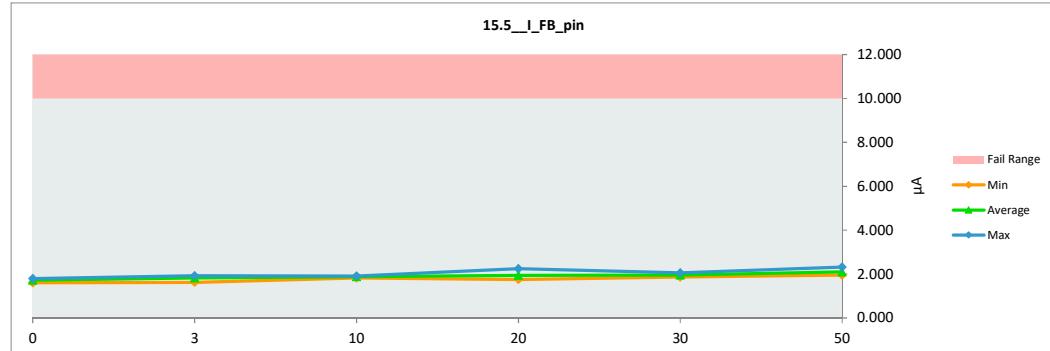


TID LDR Data (Biased)
TPS73801-SEP

15.5_I_FB_pin				
Test Site	Tester	Test Number	Unit	
			μA	μA
			10	10
Max Limit				
Min Limit				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	1.794	1.786	-0.008
0	69	1.607	1.608	0.001
0	70	1.792	1.789	-0.003
3	1	1.955	1.917	-0.038
3	2	1.939	1.905	-0.034
3	3	1.614	1.624	0.010
3	4	1.807	1.808	0.001
3	5	1.864	1.889	0.025
10	11	1.834	1.881	0.047
10	12	1.827	1.902	0.075
10	13	1.832	1.908	0.076
10	14	1.733	1.820	0.087
10	15	1.816	1.872	0.056
20	41	1.658	1.809	0.151
20	42	1.850	2.002	0.152
20	43	1.891	2.030	0.139
20	44	1.670	1.798	0.128
20	45	2.086	2.247	0.161
20	46	1.823	1.964	0.141
20	47	1.981	2.141	0.160
20	48	1.833	1.994	0.160
20	49	1.831	2.012	0.181
20	50	1.718	1.852	0.134
20	51	1.630	1.755	0.125
20	52	1.928	2.069	0.141
20	53	1.701	1.835	0.134
20	54	1.654	1.788	0.134
20	55	1.893	2.016	0.123
20	56	1.716	1.851	0.135
20	57	1.766	1.901	0.135
20	58	1.819	1.963	0.144
20	59	1.769	1.905	0.136
20	60	1.741	1.888	0.147
20	61	1.787	1.916	0.129
20	62	1.806	1.947	0.140
30	21	1.838	1.991	0.153
30	22	1.878	2.051	0.173
30	23	1.714	1.867	0.153
30	24	1.824	1.981	0.156
30	25	1.741	1.899	0.158
50	31	1.741	1.986	0.245
50	32	1.695	1.958	0.263
50	33	2.018	2.318	0.299
50	34	1.798	2.064	0.265
50	35	1.903	2.164	0.262
Max		2.086	2.318	0.299
Average		1.803	1.926	0.123
Min		1.607	1.608	-0.038
Std Dev		0.105	0.138	0.079



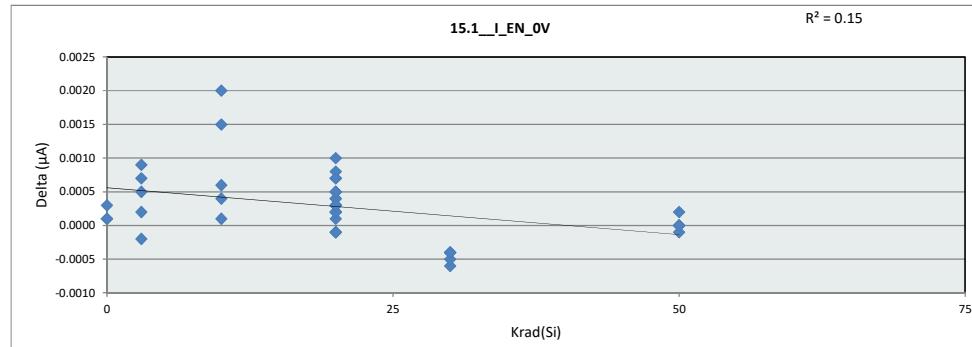
15.5_I_FB_pin						
Test Site	Tester	Test Number	Max Limit	10 μA	μA	Min Limit
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.608	1.624	1.820	1.755	1.867	1.958
Average	1.727	1.828	1.877	1.940	1.958	2.098
Max	1.789	1.917	1.908	2.247	2.051	2.318
UL	10.000	10.000	10.000	10.000	10.000	10.000



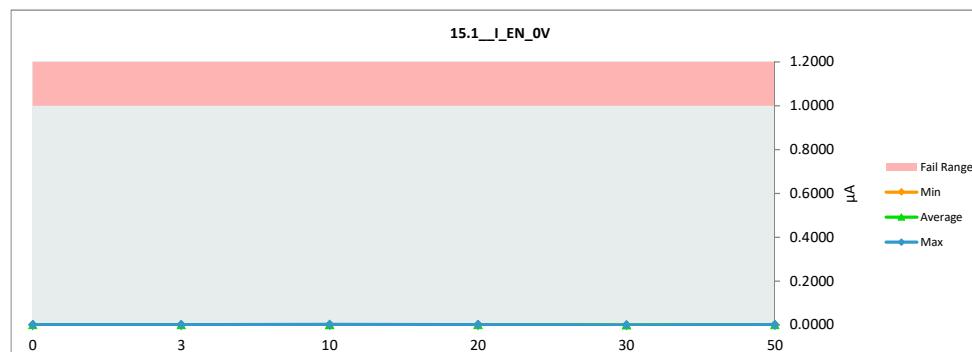
TID LDR Data (Biased)

TPS73801-SEP

15.1_I_EN_0V				
Test Site				
Tester				
Test Number				
Unit	μA	μA		
Max Limit	1	1		
Min Limit				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.0011	0.0012	0.0001
0	69	0.0009	0.0012	0.0003
0	70	0.0012	0.0013	0.0001
3	1	0.0010	0.0015	0.0005
3	2	0.0011	0.0013	0.0002
3	3	0.0008	0.0015	0.0007
3	4	0.0010	0.0019	0.0009
3	5	0.0012	0.0010	-0.0002
10	11	0.0011	0.0012	0.0001
10	12	0.0010	0.0030	0.0020
10	13	0.0007	0.0013	0.0006
10	14	0.0008	0.0023	0.0015
10	15	0.0009	0.0013	0.0004
20	41	0.0009	0.0011	0.0002
20	42	0.0012	0.0011	-0.0001
20	43	0.0010	0.0012	0.0002
20	44	0.0009	0.0013	0.0004
20	45	0.0010	0.0011	0.0001
20	46	0.0010	0.0013	0.0003
20	47	0.0011	0.0013	0.0002
20	48	0.0007	0.0012	0.0005
20	49	0.0009	0.0012	0.0003
20	50	0.0007	0.0011	0.0004
20	51	0.0011	0.0013	0.0002
20	52	0.0003	0.0010	0.0007
20	53	0.0004	0.0014	0.0010
20	54	0.0009	0.0012	0.0003
20	55	0.0008	0.0013	0.0005
20	56	0.0009	0.0014	0.0005
20	57	0.0008	0.0016	0.0008
20	58	0.0010	0.0013	0.0003
20	59	0.0013	0.0012	-0.0001
20	60	0.0007	0.0014	0.0007
20	61	0.0010	0.0013	0.0003
20	62	0.0011	0.0010	-0.0001
30	21	0.0009	0.0003	-0.0006
30	22	0.0008	0.0004	-0.0004
30	23	0.0009	0.0004	-0.0005
30	24	0.0009	0.0005	-0.0004
30	25	0.0008	0.0004	-0.0004
50	31	0.0008	0.0010	0.0002
50	32	0.0010	0.0010	0.0000
50	33	0.0011	0.0011	0.0000
50	34	0.0009	0.0008	-0.0001
50	35	0.0009	0.0009	0.0000
	Max	0.0013	0.0030	0.0020
	Average	0.0009	0.0012	0.0003
	Min	0.0003	0.0003	-0.0006
	Std Dev	0.0002	0.0005	0.0005

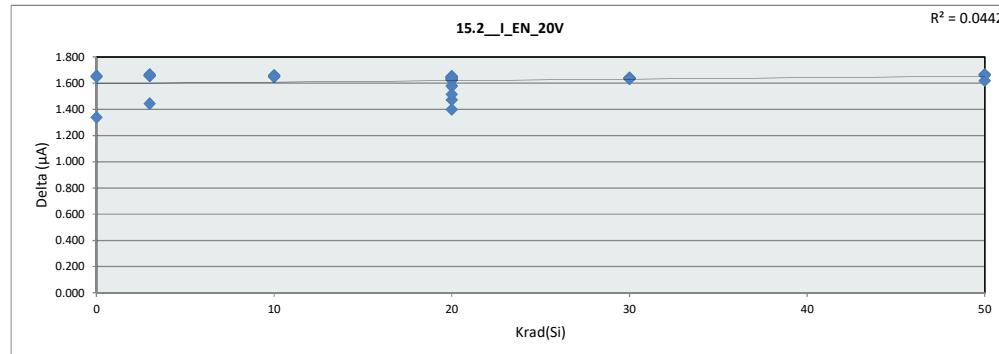


15.1_I_EN_0V						
Test Site						
Tester						
Test Number						
Max Limit	1	μA				
Min Limit		μA				
Krad(Si)	0	3	10	20	30	50
LL	0.0012	0.0010	0.0012	0.0010	0.0003	0.0008
Min	0.0012	0.0014	0.0018	0.0012	0.0004	0.0010
Average	0.0012	0.0014	0.0018	0.0012	0.0004	0.0010
Max	0.0013	0.0019	0.0030	0.0016	0.0005	0.0011
UL	1.0000	1.0000	1.0000	1.0000	1.0000	1.0000

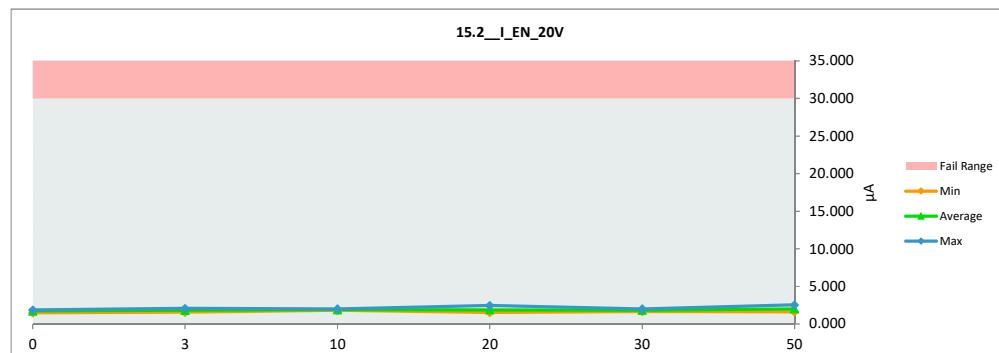


TID LDR Data (Biased)
TPS73801-SEP

15.2_I_EN_20V				
Test Site			<th></th>	
Tester				
Test Number				
Unit				
Max Limit	30		μA	
Min Limit	30		μA	
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.218	1.874	1.656
0	69	0.158	1.496	1.339
0	70	0.173	1.822	1.648
3	1	0.128	1.786	1.658
3	2	0.103	1.760	1.657
3	3	0.108	1.552	1.444
3	4	0.237	1.892	1.656
3	5	0.405	2.073	1.668
10	11	0.157	1.817	1.659
10	12	0.337	1.990	1.653
10	13	0.363	2.021	1.658
10	14	0.181	1.832	1.651
10	15	0.235	1.884	1.649
20	41	0.086	1.558	1.472
20	42	0.316	1.960	1.644
20	43	0.530	2.167	1.637
20	44	0.034	1.615	1.580
20	45	0.816	2.448	1.632
20	46	0.438	2.084	1.647
20	47	0.760	2.390	1.629
20	48	0.253	1.903	1.649
20	49	0.464	2.116	1.653
20	50	0.116	1.768	1.651
20	51	0.126	1.525	1.399
20	52	0.582	2.208	1.625
20	53	0.010	1.634	1.624
20	54	0.037	1.613	1.576
20	55	0.527	2.158	1.631
20	56	0.060	1.576	1.515
20	57	0.139	1.784	1.645
20	58	0.199	1.847	1.648
20	59	0.138	1.776	1.638
20	60	0.004	1.640	1.635
20	61	0.149	1.785	1.635
20	62	0.239	1.883	1.644
30	21	0.261	1.899	1.638
30	22	0.386	2.024	1.637
30	23	0.011	1.652	1.642
30	24	0.250	1.883	1.632
30	25	0.138	1.774	1.636
50	31	0.027	1.692	1.665
50	32	0.023	1.642	1.619
50	33	0.868	2.535	1.667
50	34	0.171	1.835	1.664
50	35	0.684	2.346	1.662
Max		0.868	2.535	1.668
Average		0.259	1.878	1.619
Min		0.004	1.496	1.339
Std Dev		0.222	0.250	0.072

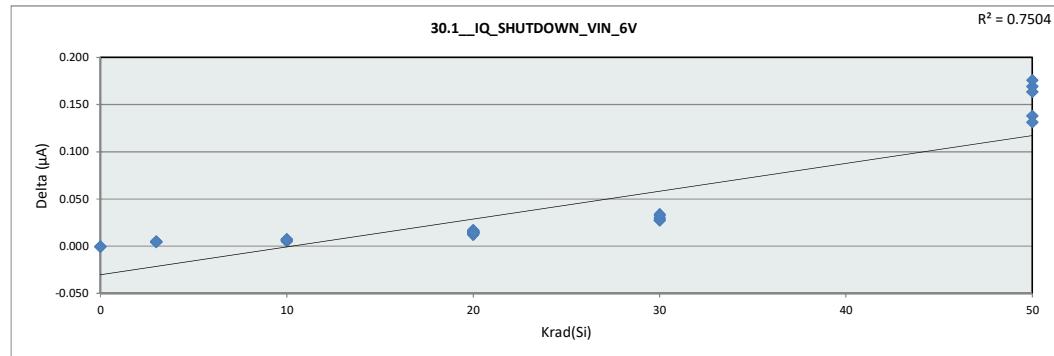


15.2_I_EN_20V						
Test Site			<th></th> <th></th> <th></th>			
Tester						
Test Number						
Max Limit	30		μA			
Min Limit			μA			
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.496	1.552	1.817	1.525	1.652	1.642
Average	1.731	1.813	1.909	1.883	1.846	2.010
Max	1.874	2.073	2.021	2.448	2.024	2.535
UL	30.000	30.000	30.000	30.000	30.000	30.000

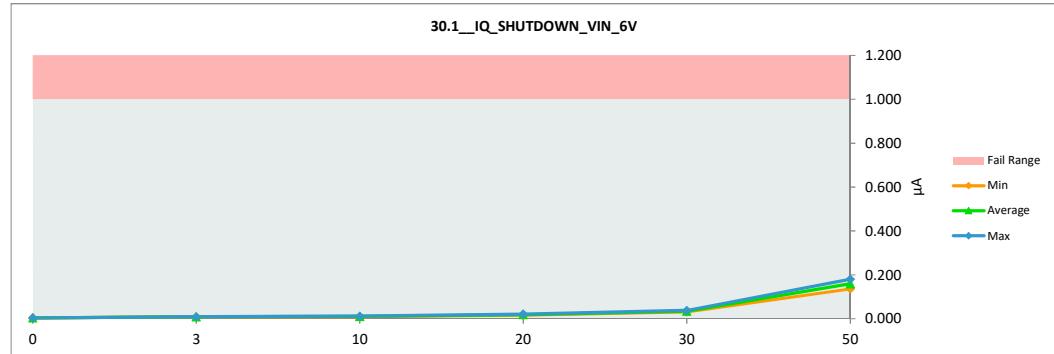


TID LDR Data (Biased) TPS73801-SEP

30.1_IQ_SHUTDOWN_VIN_6V				
Test Site				
Tester				
Test Number				
Unit				
Max Limit		μA		μA
Min Limit		1		1
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta
0	68	0.004	0.004	-0.001
0	69	0.004	0.004	0.000
0	70	0.004	0.004	-0.001
3	1	0.004	0.009	0.005
3	2	0.004	0.009	0.005
3	3	0.004	0.009	0.005
3	4	0.004	0.009	0.005
3	5	0.004	0.009	0.005
10	11	0.004	0.010	0.006
10	12	0.004	0.009	0.005
10	13	0.004	0.010	0.006
10	14	0.004	0.011	0.007
10	15	0.004	0.011	0.007
20	41	0.004	0.020	0.016
20	42	0.004	0.017	0.012
20	43	0.004	0.019	0.015
20	44	0.004	0.019	0.014
20	45	0.004	0.021	0.017
20	46	0.004	0.019	0.014
20	47	0.004	0.016	0.012
20	48	0.004	0.019	0.015
20	49	0.004	0.021	0.017
20	50	0.004	0.019	0.015
20	51	0.004	0.019	0.015
20	52	0.005	0.020	0.015
20	53	0.004	0.019	0.015
20	54	0.004	0.019	0.015
20	55	0.004	0.018	0.014
20	56	0.004	0.019	0.015
20	57	0.004	0.017	0.013
20	58	0.004	0.020	0.016
20	59	0.004	0.020	0.016
20	60	0.004	0.019	0.015
20	61	0.004	0.017	0.013
20	62	0.004	0.018	0.014
30	21	0.004	0.031	0.027
30	22	0.004	0.034	0.030
30	23	0.004	0.032	0.028
30	24	0.004	0.038	0.034
30	25	0.004	0.037	0.032
50	31	0.004	0.142	0.138
50	32	0.004	0.173	0.169
50	33	0.004	0.135	0.131
50	34	0.004	0.180	0.176
50	35	0.004	0.168	0.164
Max		0.005	0.180	0.176
Average		0.004	0.033	0.029
Min		0.004	0.004	-0.001
Std Dev		0.000	0.046	0.046

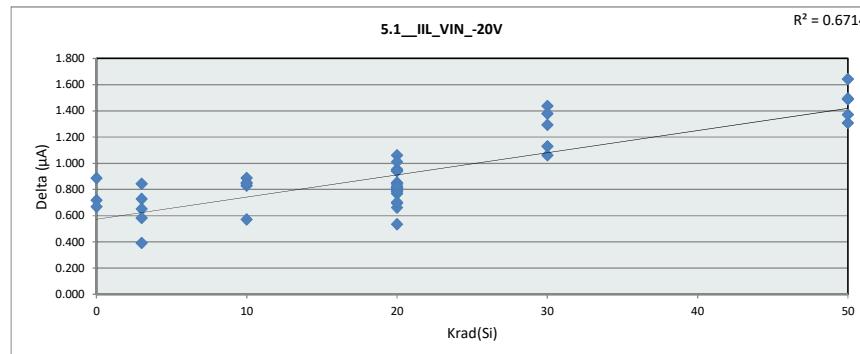


30.1_IQ_SHUTDOWN_VIN_6V						
Test Site						
Tester						
Test Number						
Max Limit		1		μA		
Min Limit			μA			
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.009	0.009	0.016	0.031	0.136
Average	0.004	0.009	0.010	0.019	0.034	0.160
Max	0.004	0.009	0.011	0.021	0.038	0.180
UL	1.000	1.000	1.000	1.000	1.000	1.000

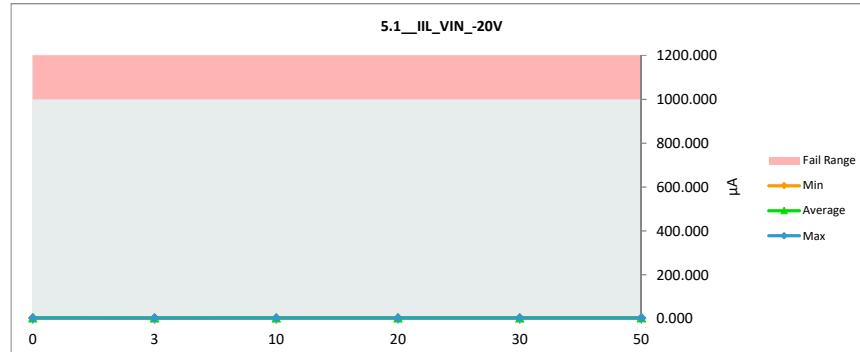


TID LDR Data (Biased)
TPS73801-SEP

5.1_IIL_VIN_-20V					
Test Site	Tester			Unit	
		μA	μA	Max Limit	Min Limit
		1000	1000		
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	2.185	2.903	0.718	
0	69	2.152	3.039	0.888	
0	70	2.208	2.879	0.671	
3	1	2.264	2.658	0.394	
3	2	2.120	2.849	0.729	
3	3	2.050	2.895	0.845	
3	4	2.294	2.947	0.653	
3	5	2.190	2.774	0.584	
10	11	2.235	2.807	0.572	
10	12	2.217	3.047	0.829	
10	13	2.138	2.992	0.854	
10	14	2.074	2.962	0.888	
10	15	2.168	3.013	0.846	
20	41	2.405	3.175	0.770	
20	42	2.302	3.244	0.942	
20	43	2.487	3.330	0.843	
20	44	2.303	3.074	0.770	
20	45	2.436	3.251	0.815	
20	46	2.521	3.056	0.535	
20	47	2.460	3.254	0.794	
20	48	2.421	3.116	0.696	
20	49	2.443	3.250	0.807	
20	50	2.458	3.272	0.814	
20	51	2.501	3.164	0.662	
20	52	2.242	3.303	1.061	
20	53	2.357	3.142	0.785	
20	54	2.187	3.142	0.955	
20	55	2.214	3.156	0.942	
20	56	2.303	3.111	0.807	
20	57	2.208	3.062	0.853	
20	58	2.359	3.208	0.849	
20	59	2.236	3.247	1.011	
20	60	2.324	3.026	0.702	
20	61	2.339	3.129	0.789	
20	62	2.413	3.238	0.825	
30	21	2.253	3.382	1.130	
30	22	2.140	3.577	1.438	
30	23	2.310	3.689	1.379	
30	24	2.245	3.540	1.294	
30	25	2.329	3.391	1.062	
50	31	2.141	3.783	1.642	
50	32	2.382	3.691	1.309	
50	33	2.163	3.652	1.488	
50	34	2.248	3.619	1.371	
50	35	2.278	3.773	1.495	
Max		2.521	3.783	1.642	
Average		2.282	3.196	0.914	
Min		2.050	2.658	0.394	
Std Dev		0.119	0.274	0.281	

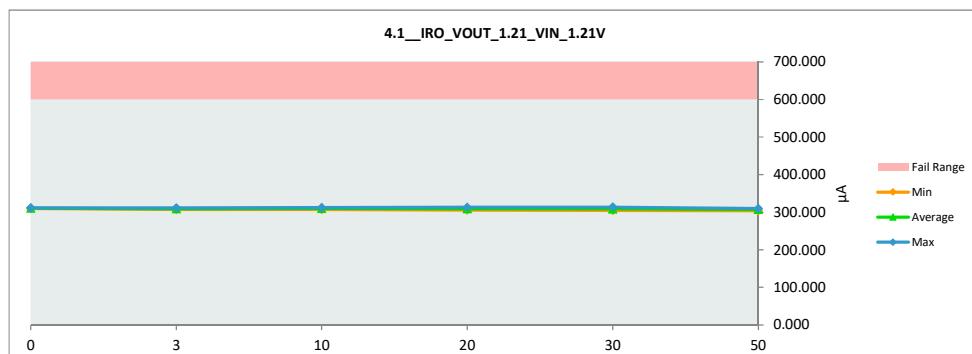
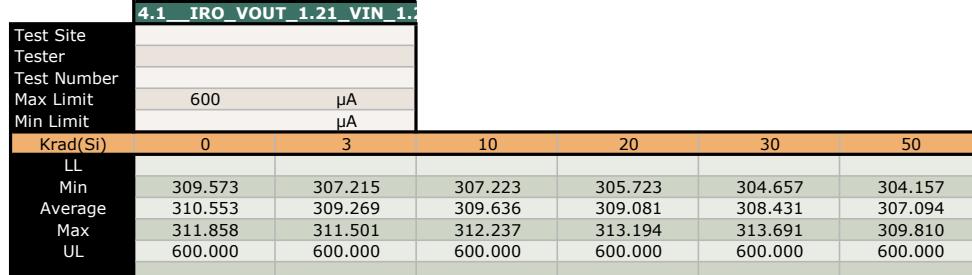
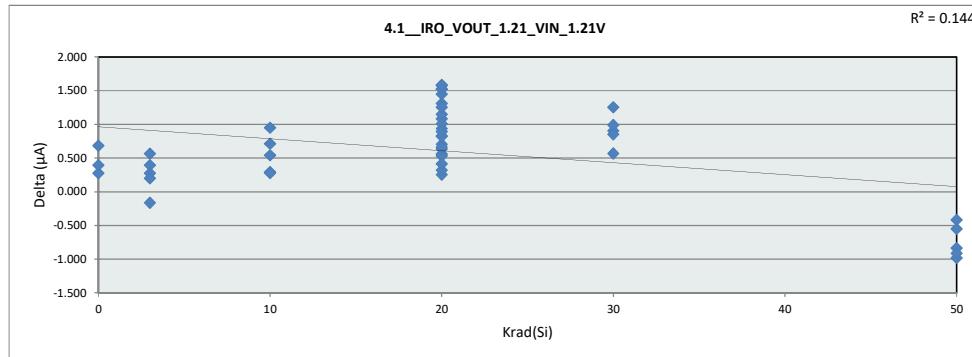


5.1_IIL_VIN_-20V					
Test Site	Tester			Unit	
		Max Limit	μA	Min Limit	μA
		1000	μA		
Krad(Si)	0	3	10	20	30
LL	2.879	2.658	2.807	3.026	3.382
Min	2.879	2.658	2.807	3.026	3.619
Average	2.940	2.825	2.964	3.180	3.516
Max	3.039	2.947	3.047	3.330	3.689
UL	1000.000	1000.000	1000.000	1000.000	1000.000



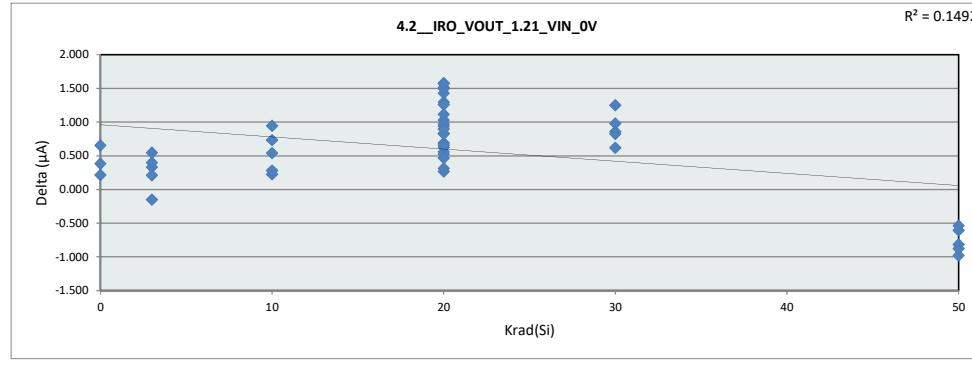
TID LDR Data (Biased)
TPS73801-SEP

4.1_IRO_VOUT_1.21_VIN_1.21					
Test Site	Tester				
Test Number	Unit	μA	μA		
		600	600		
Max Limit					
Min Limit					
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	309.297	309.573	0.275	
0	69	311.463	311.858	0.395	
0	70	309.543	310.229	0.686	
3	1	308.286	308.562	0.276	
3	2	307.015	307.215	0.200	
3	3	311.105	311.501	0.396	
3	4	308.979	309.544	0.565	
3	5	309.689	309.524	-0.165	
10	11	309.660	309.952	0.292	
10	12	309.011	309.554	0.543	
10	13	311.958	312.237	0.279	
10	14	306.509	307.223	0.714	
10	15	308.262	309.213	0.952	
20	41	312.109	313.194	1.085	
20	42	307.642	308.471	0.829	
20	43	306.407	307.556	1.149	
20	44	308.148	308.710	0.561	
20	45	304.930	306.244	1.313	
20	46	306.608	307.313	0.705	
20	47	305.935	307.386	1.451	
20	48	308.118	308.651	0.533	
20	49	310.627	310.882	0.255	
20	50	305.400	305.723	0.322	
20	51	311.345	311.761	0.416	
20	52	305.213	306.739	1.526	
20	53	308.855	309.795	0.940	
20	54	307.615	308.249	0.634	
20	55	307.076	308.600	1.524	
20	56	310.298	311.876	1.578	
20	57	309.161	309.987	0.826	
20	58	309.222	309.884	0.662	
20	59	307.672	308.926	1.255	
20	60	307.322	308.331	1.010	
20	61	309.171	310.758	1.587	
20	62	309.862	310.755	0.893	
30	21	305.715	306.620	0.905	
30	22	305.543	306.396	0.853	
30	23	313.124	313.691	0.568	
30	24	309.535	310.791	1.256	
30	25	303.666	304.657	0.991	
50	31	310.227	309.810	-0.417	
50	32	307.830	306.848	-0.982	
50	33	304.994	304.157	-0.837	
50	34	310.389	309.475	-0.914	
50	35	305.731	305.180	-0.551	
Max		313.124	313.691	1.587	
Average		308.361	308.969	0.607	
Min		303.666	304.157	-0.982	
Std Dev		2.200	2.202	0.638	

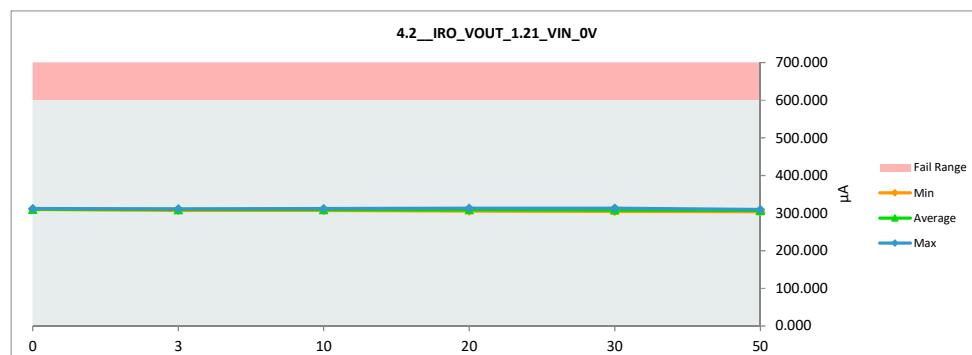


TID LDR Data (Biased)
TPS73801-SEP

4.2_IRO_VOUT_1.21_VIN_OV					
Test Site	Tester				
Test Number	Unit	μA	μA		
		600	600		
Max Limit	Min Limit				
Krad(Si)	Serial #	PRE-BIAS	POST-BIAS	Delta	
0	68	309.040	309.255	0.215	
0	69	311.210	311.591	0.382	
0	70	309.290	309.941	0.652	
3	1	307.935	308.266	0.331	
3	2	306.735	306.945	0.210	
3	3	310.831	311.227	0.396	
3	4	308.707	309.251	0.544	
3	5	309.412	309.260	-0.152	
10	11	309.403	309.627	0.224	
10	12	308.743	309.281	0.538	
10	13	311.691	311.971	0.280	
10	14	306.218	306.951	0.733	
10	15	307.988	308.930	0.942	
20	41	311.843	312.872	1.029	
20	42	307.365	308.196	0.831	
20	43	306.149	307.264	1.115	
20	44	307.888	308.446	0.558	
20	45	304.666	305.960	1.294	
20	46	306.354	307.044	0.691	
20	47	305.676	307.103	1.427	
20	48	307.857	308.382	0.525	
20	49	310.357	310.622	0.266	
20	50	305.144	305.455	0.311	
20	51	311.032	311.496	0.464	
20	52	304.947	306.456	1.510	
20	53	308.593	309.531	0.938	
20	54	307.355	307.980	0.625	
20	55	306.827	308.320	1.493	
20	56	310.030	311.607	1.577	
20	57	308.899	309.721	0.823	
20	58	308.948	309.603	0.655	
20	59	307.398	308.657	1.259	
20	60	307.089	308.061	0.972	
20	61	308.916	310.485	1.569	
20	62	309.598	310.492	0.894	
30	21	305.449	306.306	0.857	
30	22	305.297	306.120	0.823	
30	23	312.770	313.389	0.618	
30	24	309.268	310.515	1.247	
30	25	303.394	304.373	0.979	
50	31	309.976	309.371	-0.605	
50	32	307.566	306.587	-0.979	
50	33	304.717	303.900	-0.817	
50	34	310.098	309.221	-0.877	
50	35	305.462	304.925	-0.537	
Max		312.770	313.389	1.577	
Average		308.092	308.688	0.596	
Min		303.394	303.900	-0.979	
Std Dev		2.194	2.198	0.635	



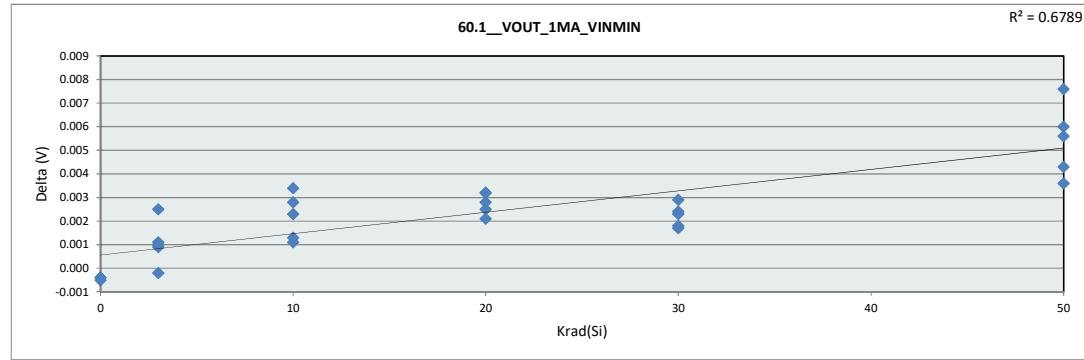
Test Site	Tester						
Test Number	Unit	600	μA	μA	μA	μA	μA
Krad(Si)	0	3	10	20	30	50	
LL	309.255	306.945	306.951	305.455	304.373	303.900	
Min	309.255	306.945	306.951	305.455	304.373	303.900	
Average	310.263	308.990	309.352	308.807	308.141	306.801	
Max	311.591	311.227	311.971	312.872	313.389	309.371	
UL	600.000	600.000	600.000	600.000	600.000	600.000	



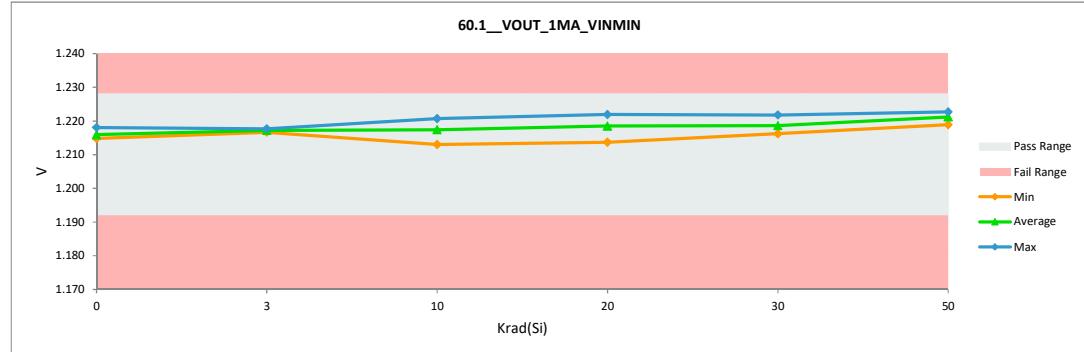
**TID LDR Data - UNBIASED
TPS73801-SEP**

TID LDR Data (Unbiased)
TPS73801-SEP

60.1_VOUT_1MA_VINMIN				
Test Site				
Tester				
Test Number				
Unit	V	V		
Max Limit	1.228	1.228		
Min Limit	1.192	1.192		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.215	1.215	0.000
0	69	1.219	1.218	0.000
0	70	1.215	1.215	0.000
3	6	1.216	1.217	0.001
3	7	1.216	1.217	0.001
3	8	1.218	1.218	0.000
3	9	1.216	1.217	0.001
3	10	1.215	1.218	0.002
10	16	1.212	1.213	0.001
10	17	1.219	1.220	0.001
10	18	1.213	1.216	0.003
10	19	1.217	1.221	0.003
10	20	1.215	1.218	0.002
20	63	1.216	1.220	0.003
20	64	1.219	1.222	0.003
20	65	1.212	1.214	0.002
20	66	1.216	1.219	0.003
20	67	1.215	1.218	0.003
30	26	1.216	1.218	0.002
30	27	1.215	1.218	0.002
30	28	1.220	1.222	0.002
30	29	1.217	1.219	0.002
30	30	1.213	1.216	0.003
50	36	1.216	1.222	0.006
50	37	1.217	1.221	0.004
50	38	1.218	1.222	0.004
50	39	1.215	1.223	0.008
50	40	1.213	1.219	0.006
Max		1.220	1.223	0.008
Average		1.216	1.218	0.002
Min		1.212	1.213	0.000
Std Dev		0.002	0.003	0.002

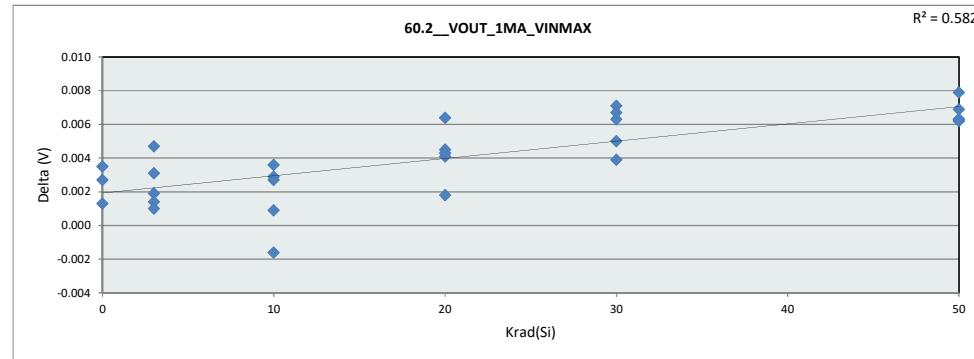


60.1_VOUT_1MA_VINMIN						
Test Site						
Tester						
Test Number						
Max Limit	1.228	V				
Min Limit	1.192	V				
Krad(Si)	0	3	10	20	30	50
LL	1.192	1.192	1.192	1.192	1.192	1.192
Min	1.215	1.217	1.213	1.214	1.216	1.219
Average	1.216	1.217	1.217	1.218	1.219	1.221
Max	1.218	1.218	1.221	1.222	1.222	1.223
UL	1.228	1.228	1.228	1.228	1.228	1.228

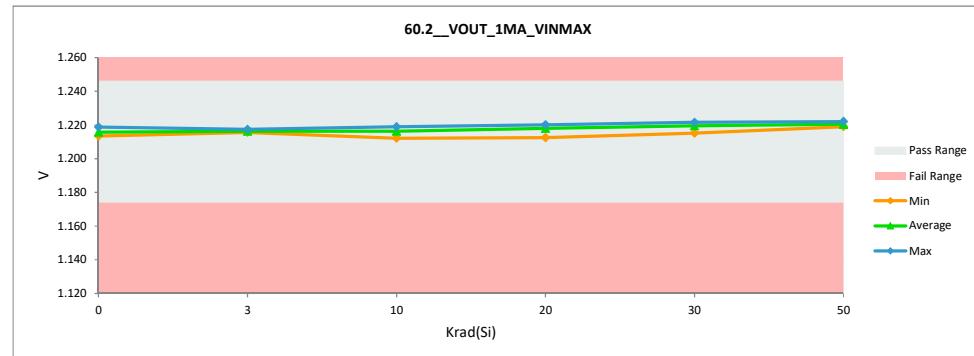


TID LDR Data (Unbiased)
TPS73801-SEP

60.2_VOUT_1MA_VINMAX				
Test Site			Tester	
Tester			Test Number	
Unit	V	V	Max Limit	1.246
Max Limit	1.246	1.246	Min Limit	1.174
Min Limit	1.174	1.174		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	1.212	1.214	0.001
0	69	1.216	1.219	0.003
0	70	1.211	1.215	0.003
3	6	1.213	1.216	0.003
3	7	1.213	1.217	0.005
3	8	1.216	1.217	0.001
3	9	1.214	1.216	0.002
3	10	1.215	1.216	0.001
10	16	1.214	1.212	-0.002
10	17	1.218	1.219	0.001
10	18	1.212	1.215	0.003
10	19	1.215	1.219	0.004
10	20	1.214	1.217	0.003
20	63	1.215	1.220	0.004
20	64	1.218	1.220	0.002
20	65	1.208	1.213	0.005
20	66	1.216	1.220	0.004
20	67	1.212	1.218	0.006
30	26	1.214	1.220	0.006
30	27	1.213	1.220	0.007
30	28	1.217	1.222	0.005
30	29	1.214	1.220	0.007
30	30	1.211	1.215	0.004
50	36	1.215	1.222	0.007
50	37	1.214	1.220	0.006
50	38	1.215	1.221	0.006
50	39	1.214	1.220	0.006
50	40	1.211	1.219	0.008
Max		1.218	1.222	0.008
Average		1.214	1.218	0.004
Min		1.208	1.212	-0.002
Std Dev		0.002	0.003	0.002

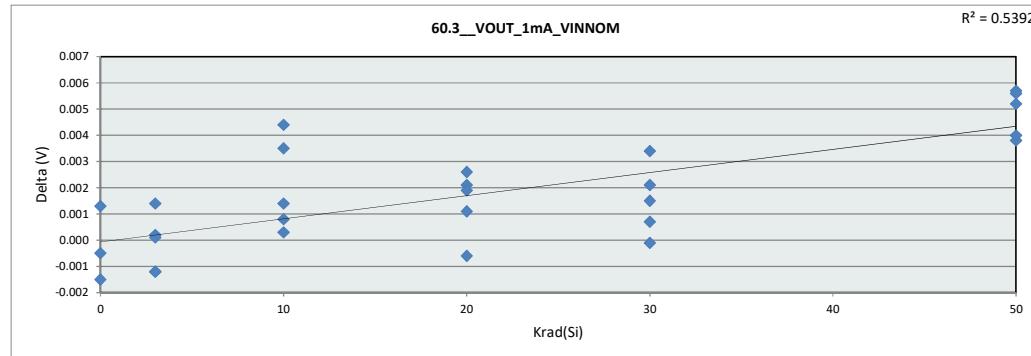


60.2_VOUT_1MA_VINMAX						
Test Site			Tester			
Tester			Test Number			
Max Limit	1.246	V	Min Limit	1.174	V	
Krad(Si)	0	3	10	20	30	50
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.214	1.216	1.212	1.213	1.215	1.219
Average	1.216	1.216	1.216	1.218	1.220	1.220
Max	1.219	1.218	1.219	1.220	1.222	1.222
UL	1.246	1.246	1.246	1.246	1.246	1.246

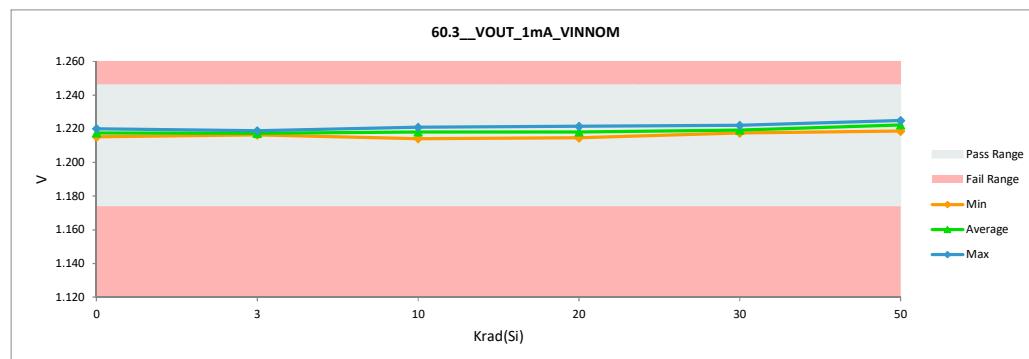


TID LDR Data (Unbiased)
TPS73801-SEP

60.3_VOUT_1mA_VINNOM					
Test Site	Tester			Unit	
		V	V	Max Limit	1.246
		1.246	1.246	Min Limit	1.174
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	1.217	1.215	-0.001	
0	69	1.219	1.220	0.001	
0	70	1.218	1.217	0.000	
3	6	1.218	1.217	-0.001	
3	7	1.217	1.217	0.000	
3	8	1.217	1.219	0.001	
3	9	1.217	1.216	-0.001	
3	10	1.217	1.217	0.000	
10	16	1.214	1.214	0.000	
10	17	1.219	1.221	0.001	
10	18	1.213	1.217	0.004	
10	19	1.217	1.220	0.003	
10	20	1.217	1.218	0.001	
20	63	1.217	1.219	0.003	
20	64	1.219	1.221	0.002	
20	65	1.213	1.215	0.002	
20	66	1.217	1.218	0.001	
20	67	1.217	1.217	-0.001	
30	26	1.217	1.218	0.001	
30	27	1.217	1.219	0.002	
30	28	1.220	1.222	0.002	
30	29	1.220	1.220	0.000	
30	30	1.214	1.217	0.003	
50	36	1.217	1.223	0.006	
50	37	1.219	1.222	0.004	
50	38	1.220	1.225	0.005	
50	39	1.217	1.222	0.006	
50	40	1.215	1.219	0.004	
Max		1.220	1.225	0.006	
Average		1.217	1.219	0.002	
Min		1.213	1.214	-0.001	
Std Dev		0.002	0.003	0.002	

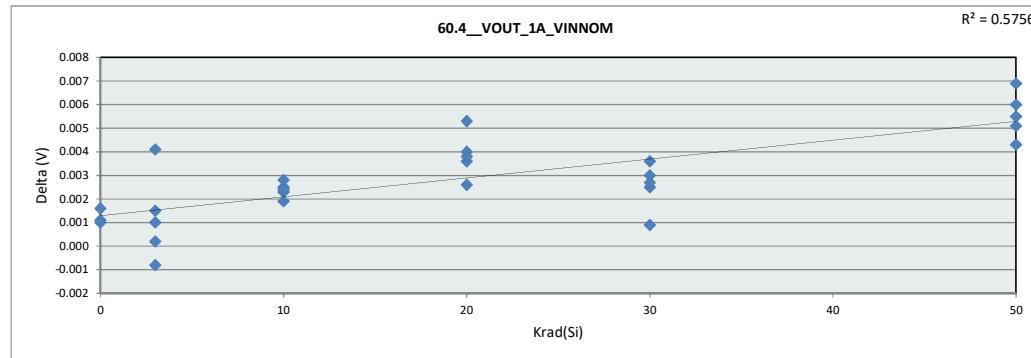


60.3_VOUT_1mA_VINNOM					
Test Site	Tester			Unit	
		V	V	Max Limit	1.246
		1.174	V	Min Limit	1.174
Krad(Si)	0	1.174	1.174	1.174	1.174
	3	1.215	1.216	1.215	1.219
Average	10	1.218	1.217	1.218	1.219
Max	20	1.220	1.219	1.221	1.225
UL	30	1.246	1.246	1.246	1.246
	50				

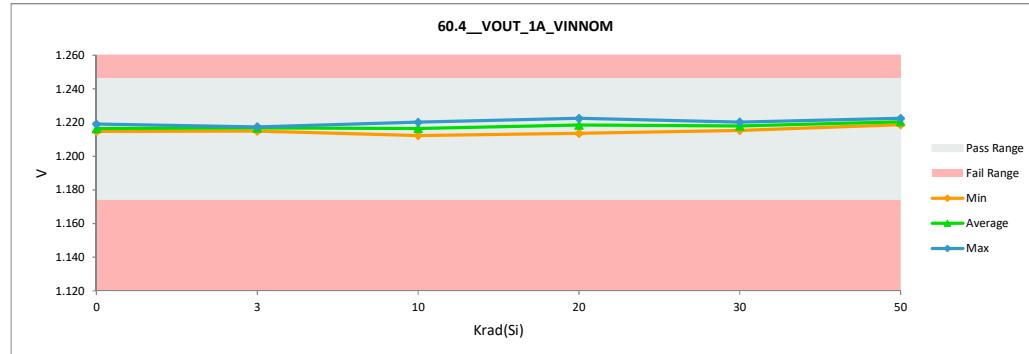


TID LDR Data (Unbiased)
TPS73801-SEP

60.4_VOUT_1A_VINNOM					
Test Site	Tester				
		V	V		
Max Limit		1.246	1.246		
Min Limit		1.174	1.174		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	1.214	1.215	0.002	
0	69	1.218	1.219	0.001	
0	70	1.214	1.215	0.001	
3	6	1.217	1.217	0.000	
3	7	1.215	1.217	0.002	
3	8	1.218	1.217	-0.001	
3	9	1.214	1.215	0.001	
3	10	1.213	1.217	0.004	
10	16	1.210	1.212	0.002	
10	17	1.218	1.220	0.002	
10	18	1.211	1.214	0.003	
10	19	1.217	1.219	0.002	
10	20	1.215	1.217	0.002	
20	63	1.216	1.219	0.004	
20	64	1.217	1.222	0.005	
20	65	1.211	1.214	0.003	
20	66	1.215	1.219	0.004	
20	67	1.214	1.218	0.004	
30	26	1.215	1.218	0.003	
30	27	1.214	1.218	0.004	
30	28	1.219	1.220	0.001	
30	29	1.216	1.219	0.003	
30	30	1.213	1.215	0.003	
50	36	1.216	1.221	0.005	
50	37	1.214	1.219	0.004	
50	38	1.217	1.222	0.005	
50	39	1.214	1.221	0.007	
50	40	1.213	1.219	0.006	
Max		1.219	1.222	0.007	
Average		1.215	1.218	0.003	
Min		1.210	1.212	-0.001	
Std Dev		0.002	0.003	0.002	

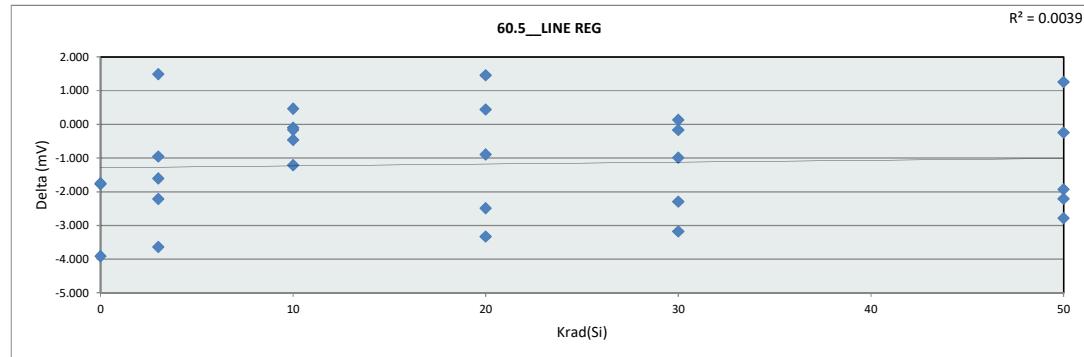


60.4_VOUT_1A_VINNOM					
Test Site	Tester				
		V	V		
Max Limit		1.246	V		
Min Limit		1.174	V		
Krad(Si)	0	1.174	1.174	1.174	1.174
	3	1.215	1.215	1.215	1.219
Average	10	1.216	1.217	1.216	1.220
Max	20	1.219	1.220	1.223	1.222
UL	30	1.246	1.246	1.246	1.246
	50				

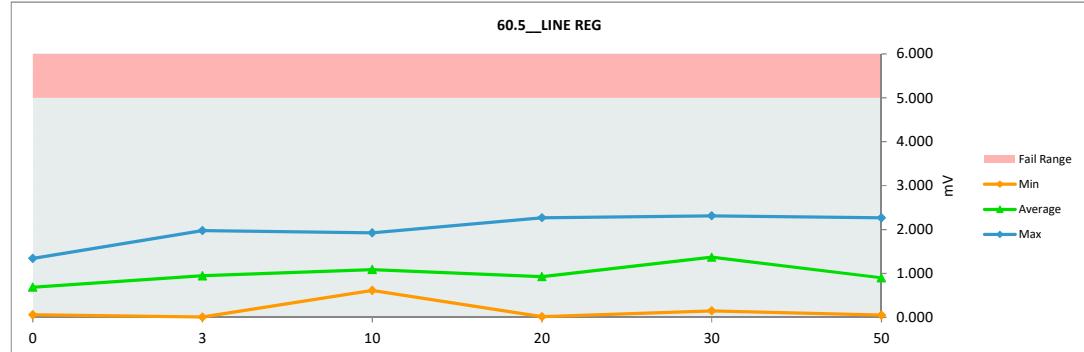


TID LDR Data (Unbiased)
TPS73801-SEP

60.5 LINE REG					
Test Site					
Tester					
Test Number					
Unit	mV	mV			
Max Limit	5	5			
Min Limit					
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	3.112	1.342	-1.771	
0	69	2.410	0.666	-1.744	
0	70	3.971	0.060	-3.912	
3	6	3.263	1.048	-2.215	
3	7	3.643	0.006	-3.637	
3	8	2.354	0.748	-1.606	
3	9	1.902	0.950	-0.952	
3	10	0.488	1.977	1.489	
10	16	1.944	0.734	-1.210	
10	17	0.860	1.325	0.465	
10	18	0.946	0.850	-0.096	
10	19	2.090	1.927	-0.163	
10	20	1.071	0.615	-0.456	
20	63	0.905	0.015	-0.890	
20	64	0.814	2.272	1.458	
20	65	3.569	1.085	-2.484	
20	66	0.557	0.998	0.441	
20	67	3.606	0.278	-3.328	
30	26	1.894	2.031	0.137	
30	27	2.480	2.312	-0.168	
30	28	3.322	0.148	-3.174	
30	29	3.666	1.372	-2.294	
30	30	1.976	0.988	-0.988	
50	36	0.607	0.365	-0.242	
50	37	3.013	1.084	-1.929	
50	38	3.533	0.751	-2.781	
50	39	1.011	2.267	1.256	
50	40	2.253	0.048	-2.205	
Max		3.971	2.312	1.489	
Average		2.188	1.009	-1.179	
Min		0.488	0.006	-3.912	
Std Dev		1.141	0.722	1.528	

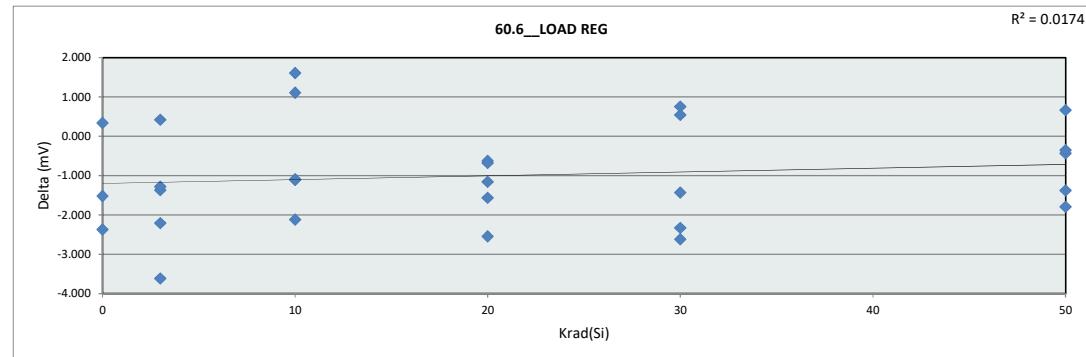


60.5 LINE REG						
Test Site						
Tester						
Test Number						
Max Limit	5	mV				
Min Limit	mV					
Krad(Si)	0	3	10	20	30	50
LL	0.060	0.006	0.615	0.015	0.148	0.048
Average	0.689	0.946	1.090	0.930	1.370	0.903
Max	1.342	1.978	1.927	2.272	2.312	2.267
UL	5.000	5.000	5.000	5.000	5.000	5.000

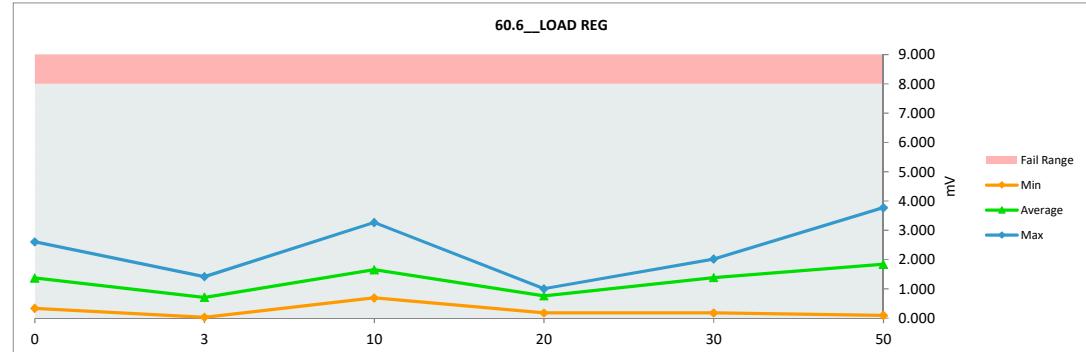


TID LDR Data (Unbiased)
TPS73801-SEP

60.6 LOAD REG					
Test Site					
Tester					
Test Number					
Unit	mV	mV			
Max Limit	8	8			
Min Limit					
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	2.708	0.338	-2.370	
0	69	0.831	1.174	0.343	
0	70	4.126	2.607	-1.518	
3	6	1.402	0.033	-1.369	
3	7	1.879	0.597	-1.282	
3	8	0.885	1.304	0.419	
3	9	3.624	1.416	-2.209	
3	10	3.803	0.191	-3.613	
10	16	3.881	1.762	-2.119	
10	17	1.802	0.692	-1.110	
10	18	1.657	3.270	1.613	
10	19	0.495	1.601	1.106	
10	20	2.039	0.946	-1.093	
20	63	0.806	0.181	-0.625	
20	64	2.165	1.007	-1.158	
20	65	1.678	0.998	-0.681	
20	66	2.261	0.700	-1.561	
20	67	3.474	0.930	-2.543	
30	26	2.503	0.176	-2.327	
30	27	3.143	1.711	-1.432	
30	28	1.080	1.620	0.540	
30	29	4.026	1.409	-2.616	
30	30	1.261	2.020	0.758	
50	36	1.303	1.968	0.665	
50	37	4.209	3.774	-0.436	
50	38	2.761	2.407	-0.354	
50	39	2.325	0.947	-1.379	
50	40	1.887	0.096	-1.791	
Max		4.209	3.774	1.613	
Average		2.286	1.281	-1.005	
Min		0.495	0.033	-3.613	
Std Dev		1.130	0.943	1.280	

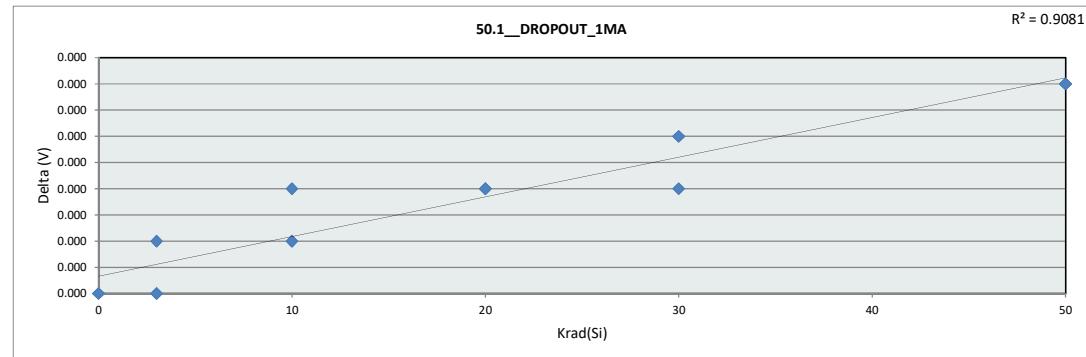


60.6 LOAD REG						
Test Site						
Tester						
Test Number						
Max Limit	8	mV				
Min Limit		mV				
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.338	0.033	0.692	0.181	0.176	0.096
Average	1.373	0.708	1.654	0.763	1.387	1.838
Max	2.607	1.416	3.270	1.007	2.020	3.774
UL	8.000	8.000	8.000	8.000	8.000	8.000

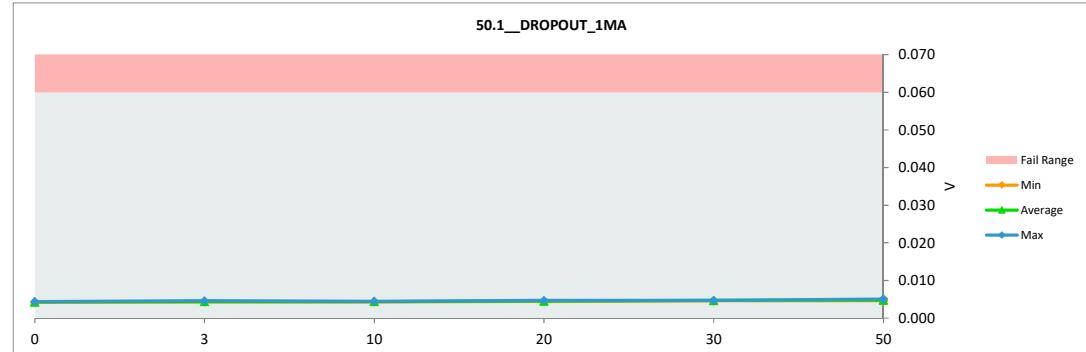


TID LDR Data (Unbiased)
TPS73801-SEP

50.1_DROPOUT_1MA				
Test Site		Tester		
Tester		Test Number		
Unit	V	V		
Max Limit	0.06	0.06		
Min Limit				
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.004	0.004	0.000
0	69	0.004	0.004	0.000
0	70	0.004	0.004	0.000
3	6	0.004	0.004	0.000
3	7	0.004	0.004	0.000
3	8	0.004	0.004	0.000
3	9	0.004	0.005	0.000
3	10	0.004	0.004	0.000
10	16	0.004	0.004	0.000
10	17	0.004	0.004	0.000
10	18	0.004	0.004	0.000
10	19	0.004	0.004	0.000
10	20	0.004	0.004	0.000
20	63	0.004	0.005	0.000
20	64	0.004	0.004	0.000
20	65	0.004	0.005	0.000
20	66	0.004	0.004	0.000
20	67	0.004	0.004	0.000
30	26	0.004	0.005	0.000
30	27	0.004	0.005	0.000
30	28	0.004	0.005	0.000
30	29	0.004	0.005	0.000
30	30	0.004	0.005	0.000
50	36	0.004	0.005	0.000
50	37	0.004	0.005	0.000
50	38	0.004	0.005	0.000
50	39	0.004	0.005	0.000
50	40	0.005	0.005	0.000
Max		0.005	0.005	0.000
Average		0.004	0.005	0.000
Min		0.004	0.004	0.000
Std Dev		0.000	0.000	0.000

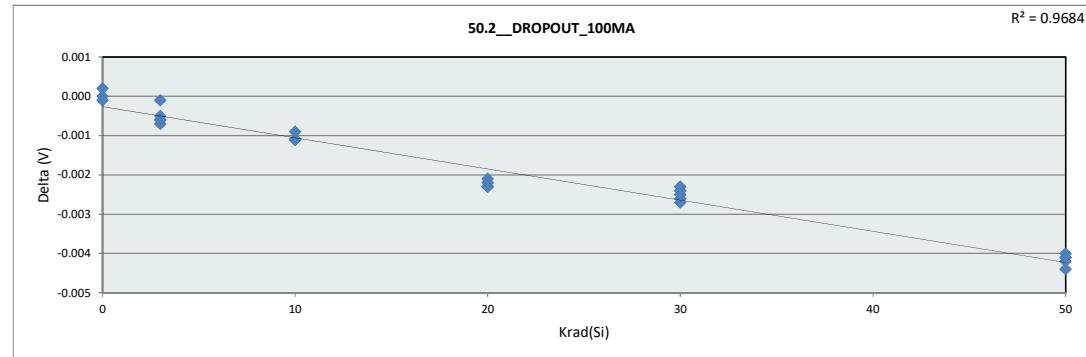


50.1_DROPOUT_1MA						
Test Site		Tester	<th></th> <th></th> <th></th>			
Tester		Test Number				
Max Limit	0.06	V				
Min Limit	V					
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.004	0.004	0.004	0.005	0.005	0.005
Average	0.004	0.004	0.004	0.005	0.005	0.005
Max	0.004	0.005	0.005	0.005	0.005	0.005
UL	0.060	0.060	0.060	0.060	0.060	0.060

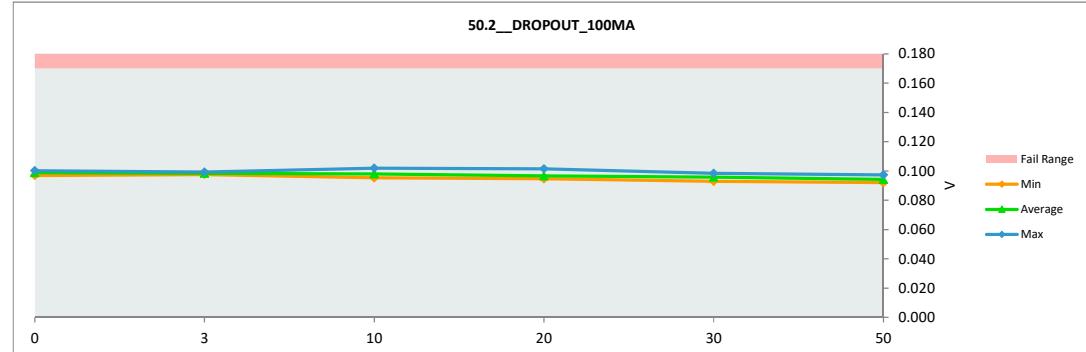


TID LDR Data (Unbiased)
TPS73801-SEP

50.2_DROPOUT_100MA					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Unit	V	V		Max Limit	0.17
Min Limit				0.17	0.17
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	0.100	0.100	0.000	
0	69	0.097	0.097	0.000	
0	70	0.099	0.099	0.000	
3	6	0.099	0.098	-0.001	
3	7	0.099	0.098	-0.001	
3	8	0.098	0.098	-0.001	
3	9	0.100	0.099	-0.001	
3	10	0.098	0.098	0.000	
10	16	0.103	0.102	-0.001	
10	17	0.096	0.095	-0.001	
10	18	0.101	0.099	-0.001	
10	19	0.097	0.096	-0.001	
10	20	0.098	0.097	-0.001	
20	63	0.097	0.095	-0.002	
20	64	0.097	0.095	-0.002	
20	65	0.104	0.101	-0.002	
20	66	0.097	0.095	-0.002	
20	67	0.100	0.097	-0.002	
30	26	0.099	0.097	-0.002	
30	27	0.098	0.096	-0.002	
30	28	0.095	0.093	-0.003	
30	29	0.098	0.095	-0.003	
30	30	0.101	0.098	-0.003	
50	36	0.096	0.092	-0.004	
50	37	0.098	0.094	-0.004	
50	38	0.098	0.094	-0.004	
50	39	0.097	0.093	-0.004	
50	40	0.101	0.097	-0.004	
Max		0.104	0.102	0.000	
Average		0.099	0.097	-0.002	
Min		0.095	0.092	-0.004	
Std Dev		0.002	0.003	0.001	

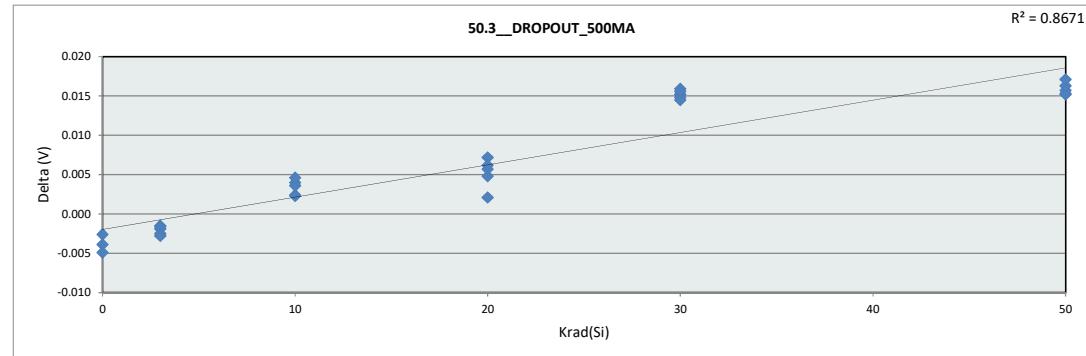


50.2_DROPOUT_100MA						
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number		
Unit	V	V	<th>Max Limit</th> <td>0.17</td>	Max Limit	0.17	
Min Limit	V	V		0.17	0.17	
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.097	0.098	0.095	0.095	0.093	0.092
Average	0.099	0.098	0.098	0.097	0.096	0.094
Max	0.100	0.099	0.102	0.102	0.098	0.097
UL	0.170	0.170	0.170	0.170	0.170	0.170

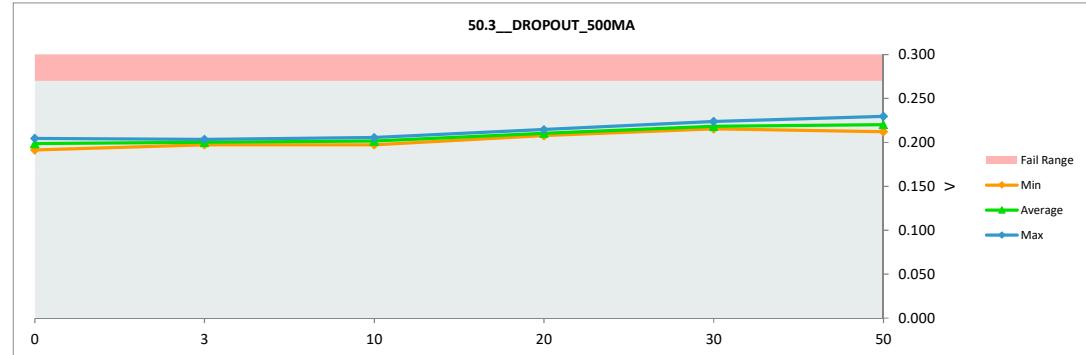


TID LDR Data (Unbiased)
TPS73801-SEP

50.3_DROPOUT_500MA					
Test Site					
Tester					
Test Number					
Unit					
Max Limit		V	V		
Min Limit		0.27	0.27		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	0.207	0.205	-0.003	
0	69	0.196	0.192	-0.004	
0	70	0.205	0.200	-0.005	
3	6	0.199	0.197	-0.001	
3	7	0.205	0.204	-0.002	
3	8	0.202	0.200	-0.002	
3	9	0.203	0.201	-0.002	
3	10	0.201	0.198	-0.003	
10	16	0.200	0.204	0.004	
10	17	0.195	0.197	0.002	
10	18	0.198	0.200	0.002	
10	19	0.197	0.200	0.004	
10	20	0.201	0.206	0.005	
20	63	0.206	0.209	0.002	
20	64	0.205	0.210	0.005	
20	65	0.209	0.215	0.006	
20	66	0.200	0.208	0.007	
20	67	0.206	0.212	0.006	
30	26	0.204	0.219	0.015	
30	27	0.201	0.215	0.015	
30	28	0.202	0.218	0.016	
30	29	0.201	0.216	0.015	
30	30	0.208	0.224	0.016	
50	36	0.208	0.223	0.015	
50	37	0.197	0.212	0.016	
50	38	0.199	0.214	0.015	
50	39	0.206	0.222	0.016	
50	40	0.213	0.230	0.017	
Max		0.213	0.230	0.017	
Average		0.203	0.209	0.006	
Min		0.195	0.192	-0.005	
Std Dev		0.004	0.010	0.008	

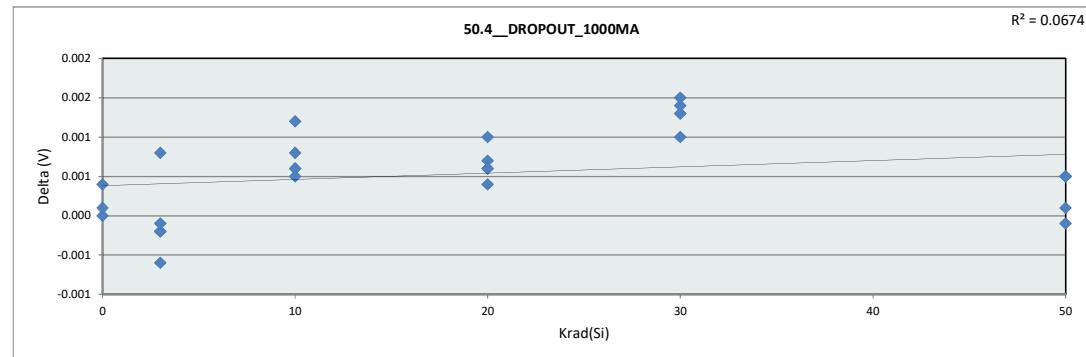


50.3_DROPOUT_500MA						
Test Site						
Tester						
Test Number						
Max Limit		0.27	V			
Min Limit		V	V			
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.192	0.197	0.197	0.208	0.216	0.212
Average	0.199	0.200	0.202	0.211	0.218	0.220
Max	0.205	0.204	0.206	0.215	0.224	0.230
UL	0.270	0.270	0.270	0.270	0.270	0.270

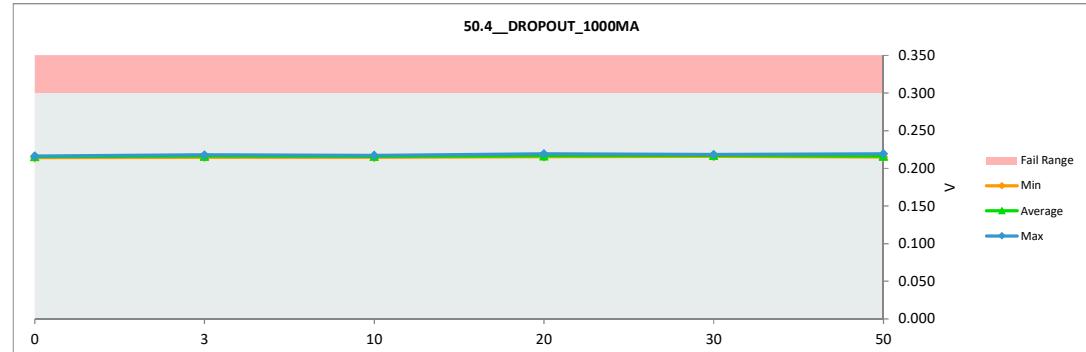


TID LDR Data (Unbiased)
TPS73801-SEP

50.4_DROPOUT_1000MA					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Unit	V	V		Max Limit	0.3
Min Limit				Max Limit	0.3
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	0.216	0.216	0.000	
0	69	0.214	0.214	0.000	
0	70	0.216	0.216	0.000	
3	6	0.215	0.215	-0.001	
3	7	0.216	0.216	0.000	
3	8	0.217	0.216	0.000	
3	9	0.218	0.218	0.000	
3	10	0.215	0.216	0.001	
10	16	0.216	0.217	0.001	
10	17	0.214	0.215	0.001	
10	18	0.217	0.217	0.001	
10	19	0.214	0.215	0.000	
10	20	0.215	0.217	0.001	
20	63	0.215	0.216	0.000	
20	64	0.215	0.215	0.001	
20	65	0.218	0.219	0.001	
20	66	0.215	0.216	0.001	
20	67	0.216	0.217	0.001	
30	26	0.217	0.218	0.001	
30	27	0.216	0.217	0.001	
30	28	0.215	0.216	0.001	
30	29	0.216	0.217	0.001	
30	30	0.217	0.218	0.001	
50	36	0.215	0.215	0.000	
50	37	0.215	0.215	0.001	
50	38	0.217	0.217	0.000	
50	39	0.215	0.215	0.000	
50	40	0.219	0.219	0.001	
Max		0.219	0.219	0.001	
Average		0.216	0.216	0.001	
Min		0.214	0.214	-0.001	
Std Dev		0.001	0.001	0.001	

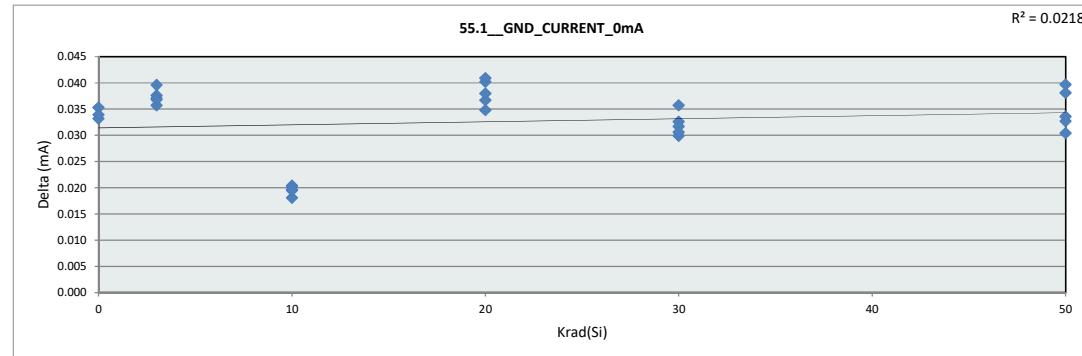


50.4_DROPOUT_1000MA						
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number		
Unit	V	V	<th>Max Limit</th> <td>0.3</td>	Max Limit	0.3	
Min Limit	V	V		Max Limit	0.3	
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.214	0.215	0.215	0.215	0.216	0.215
Average	0.215	0.216	0.216	0.217	0.217	0.216
Max	0.216	0.218	0.217	0.219	0.218	0.219
UL	0.300	0.300	0.300	0.300	0.300	0.300

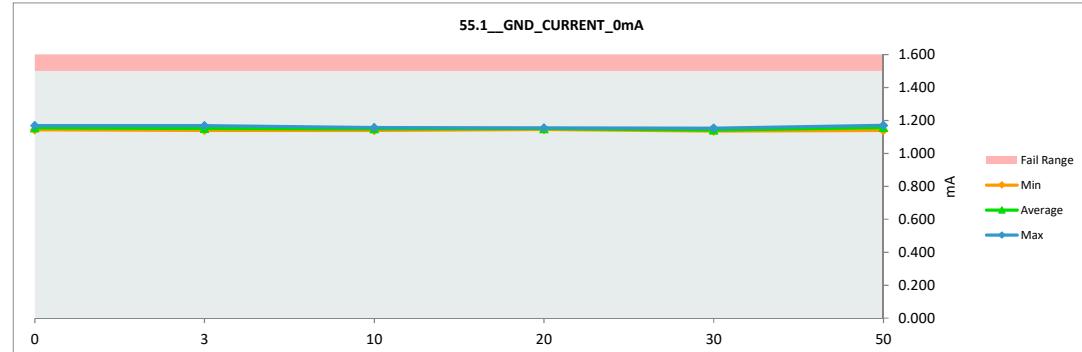


TID LDR Data (Unbiased)
TPS73801-SEP

55.1_GND_CURRENT_0mA					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
		mA	mA		
Max Limit		1.5	1.5		
Min Limit					
0	68	1.110	1.144	0.033	
0	69	1.135	1.170	0.035	
0	70	1.118	1.152	0.034	
3	6	1.132	1.169	0.038	
3	7	1.104	1.140	0.036	
3	8	1.106	1.143	0.037	
3	9	1.115	1.151	0.037	
3	10	1.114	1.153	0.040	
10	16	1.129	1.147	0.018	
10	17	1.137	1.157	0.020	
10	18	1.120	1.140	0.020	
10	19	1.138	1.158	0.020	
10	20	1.123	1.143	0.020	
20	63	1.118	1.154	0.037	
20	64	1.114	1.152	0.038	
20	65	1.110	1.145	0.035	
20	66	1.115	1.156	0.040	
20	67	1.109	1.149	0.041	
30	26	1.108	1.140	0.033	
30	27	1.105	1.137	0.032	
30	28	1.114	1.144	0.030	
30	29	1.118	1.154	0.036	
30	30	1.104	1.135	0.031	
50	36	1.123	1.162	0.040	
50	37	1.136	1.170	0.034	
50	38	1.127	1.157	0.030	
50	39	1.107	1.139	0.033	
50	40	1.120	1.158	0.038	
Max		1.138	1.170	0.041	
Average		1.118	1.151	0.033	
Min		1.104	1.135	0.018	
Std Dev		0.011	0.010	0.007	

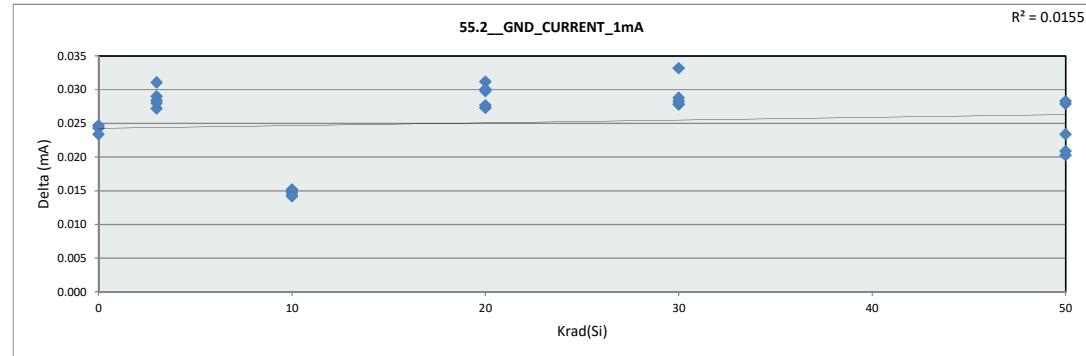


55.1_GND_CURRENT_0mA					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Krad(Si)	0	3	10	20	30
LL					
Min	1.144	1.140	1.140	1.145	1.135
Average	1.155	1.151	1.149	1.151	1.142
Max	1.170	1.170	1.158	1.156	1.154
UL	1.500	1.500	1.500	1.500	1.500

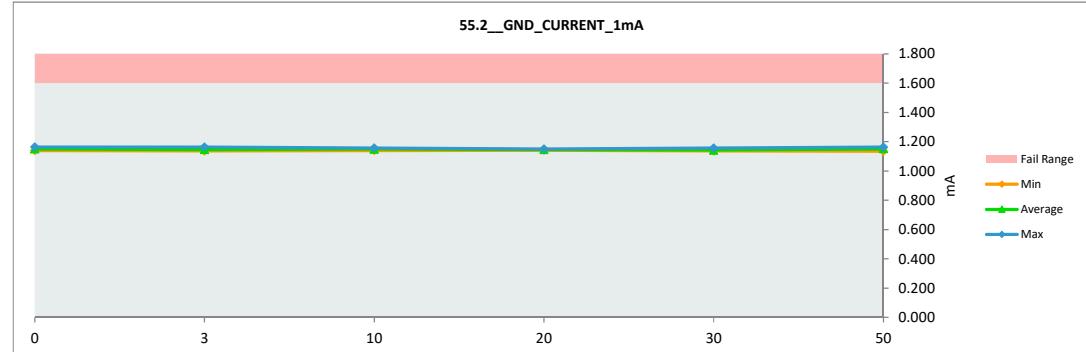


TID LDR Data (Unbiased)
TPS73801-SEP

55.2_GND_CURRENT_1mA					
Test Site					
Tester					
Test Number					
Unit					
Max Limit	mA	mA			
Min Limit	1.6	1.6			
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	1.115	1.140	0.025	
0	69	1.140	1.164	0.024	
0	70	1.123	1.146	0.023	
3	6	1.137	1.164	0.027	
3	7	1.107	1.136	0.029	
3	8	1.109	1.138	0.028	
3	9	1.119	1.147	0.028	
3	10	1.119	1.150	0.031	
10	16	1.133	1.148	0.015	
10	17	1.143	1.157	0.014	
10	18	1.125	1.140	0.015	
10	19	1.142	1.157	0.015	
10	20	1.128	1.142	0.014	
20	63	1.123	1.150	0.028	
20	64	1.118	1.147	0.030	
20	65	1.114	1.142	0.027	
20	66	1.119	1.150	0.031	
20	67	1.114	1.144	0.030	
30	26	1.113	1.141	0.028	
30	27	1.109	1.137	0.028	
30	28	1.117	1.145	0.028	
30	29	1.122	1.156	0.033	
30	30	1.108	1.137	0.029	
50	36	1.128	1.156	0.028	
50	37	1.142	1.163	0.021	
50	38	1.132	1.153	0.020	
50	39	1.111	1.134	0.023	
50	40	1.123	1.152	0.028	
Max		1.143	1.164	0.033	
Average		1.123	1.148	0.025	
Min		1.107	1.134	0.014	
Std Dev		0.011	0.009	0.006	

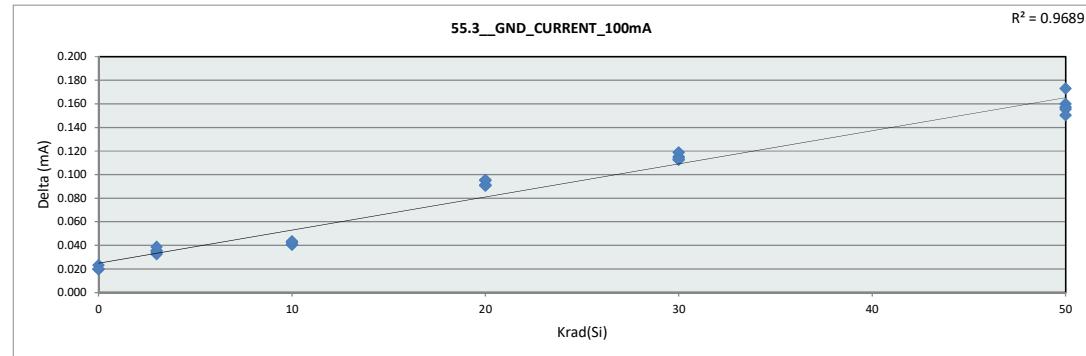


55.2_GND_CURRENT_1mA						
Test Site						
Tester						
Test Number						
Max Limit	1.6	mA				
Min Limit	mA	mA				
Krad(Si)	0	3	10	20	30	50
LL						
Min	1.140	1.136	1.140	1.142	1.137	1.134
Average	1.150	1.147	1.149	1.147	1.143	1.151
Max	1.164	1.164	1.157	1.150	1.156	1.163
UL	1.600	1.600	1.600	1.600	1.600	1.600

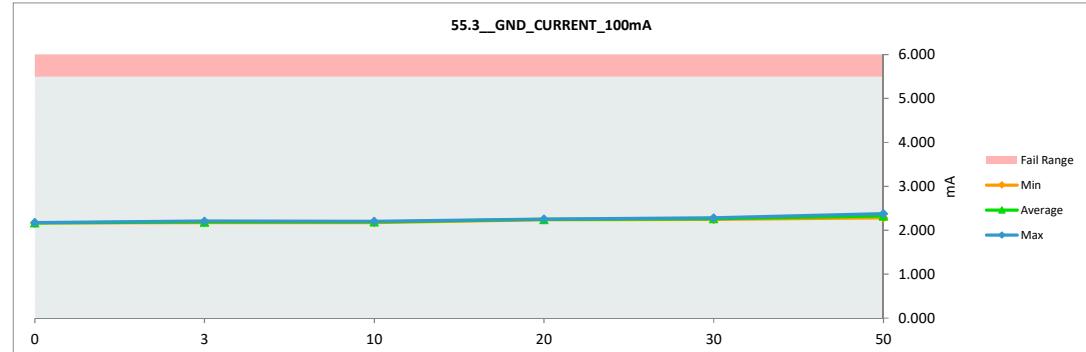


TID LDR Data (Unbiased)
TPS73801-SEP

55.3_GND_CURRENT_100mA					
Test Site	Tester				
Test Number		mA	mA		
Unit		5.5	5.5		
Max Limit					
Min Limit					
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	2.146	2.165	0.020	
0	69	2.141	2.165	0.023	
0	70	2.156	2.176	0.020	
3	6	2.156	2.188	0.033	
3	7	2.140	2.175	0.035	
3	8	2.142	2.178	0.036	
3	9	2.174	2.208	0.034	
3	10	2.142	2.181	0.039	
10	16	2.134	2.175	0.041	
10	17	2.152	2.193	0.041	
10	18	2.136	2.179	0.043	
10	19	2.161	2.203	0.043	
10	20	2.161	2.204	0.043	
20	63	2.165	2.256	0.091	
20	64	2.153	2.244	0.091	
20	65	2.151	2.242	0.091	
20	66	2.155	2.251	0.095	
20	67	2.148	2.244	0.095	
30	26	2.153	2.268	0.115	
30	27	2.134	2.248	0.114	
30	28	2.153	2.266	0.113	
30	29	2.162	2.281	0.119	
30	30	2.148	2.261	0.113	
50	36	2.172	2.332	0.160	
50	37	2.159	2.316	0.157	
50	38	2.168	2.324	0.155	
50	39	2.137	2.287	0.150	
50	40	2.205	2.378	0.173	
Max		2.205	2.378	0.173	
Average		2.154	2.235	0.082	
Min		2.134	2.165	0.020	
Std Dev		0.015	0.058	0.050	

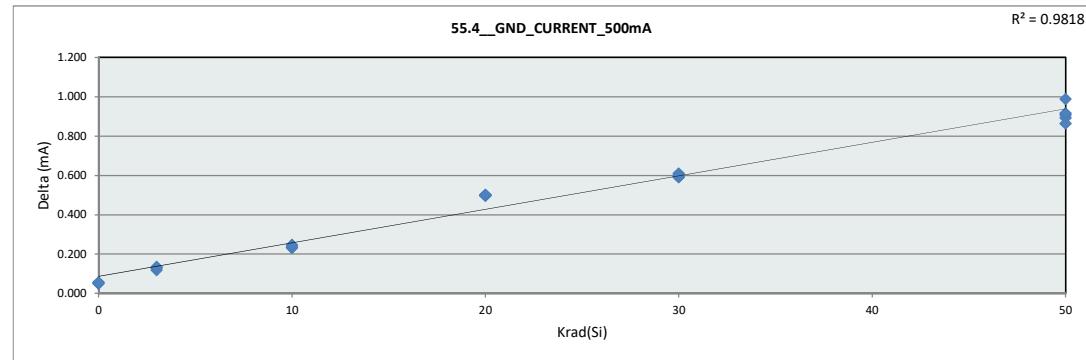


55.3_GND_CURRENT_100mA					
Test Site	Tester				
Test Number		mA	mA		
Unit		5.5	5.5		
Max Limit					
Min Limit					
Krad(Si)		0	3	10	20
LL		2.165	2.175	2.175	2.242
Min		2.169	2.186	2.191	2.247
Average		2.176	2.208	2.204	2.256
Max		5.500	5.500	5.500	5.500
UL		5.500	5.500	5.500	5.500

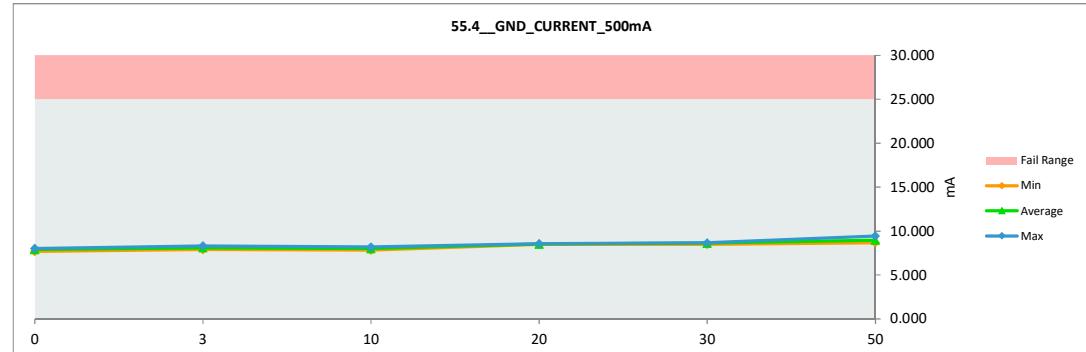


TID LDR Data (Unbiased)
TPS73801-SEP

55.4_GND_CURRENT_500mA					
Test Site					
Tester					
Test Number					
Unit					
Max Limit	mA	mA			
Min Limit	25	25			
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	7.946	7.996	0.049	
0	69	7.633	7.686	0.053	
0	70	7.958	8.015	0.057	
3	6	7.785	7.903	0.118	
3	7	7.953	8.085	0.133	
3	8	7.990	8.122	0.131	
3	9	8.179	8.308	0.129	
3	10	7.860	7.994	0.134	
10	16	7.606	7.839	0.233	
10	17	7.728	7.960	0.232	
10	18	7.732	7.966	0.234	
10	19	7.795	8.038	0.243	
10	20	7.936	8.182	0.246	
20	63	8.067	8.564	0.498	
20	64	7.997	8.493	0.496	
20	65	8.023	8.522	0.500	
20	66	7.989	8.491	0.501	
20	67	7.974	8.475	0.501	
30	26	8.064	8.663	0.600	
30	27	7.890	8.480	0.590	
30	28	8.021	8.615	0.593	
30	29	8.059	8.668	0.609	
30	30	8.022	8.620	0.598	
50	36	8.118	9.026	0.908	
50	37	7.782	8.674	0.892	
50	38	8.007	8.924	0.917	
50	39	7.915	8.778	0.863	
50	40	8.461	9.450	0.989	
Max		8.461	9.450	0.989	
Average		7.946	8.376	0.430	
Min		7.606	7.686	0.049	
Std Dev		0.173	0.411	0.299	

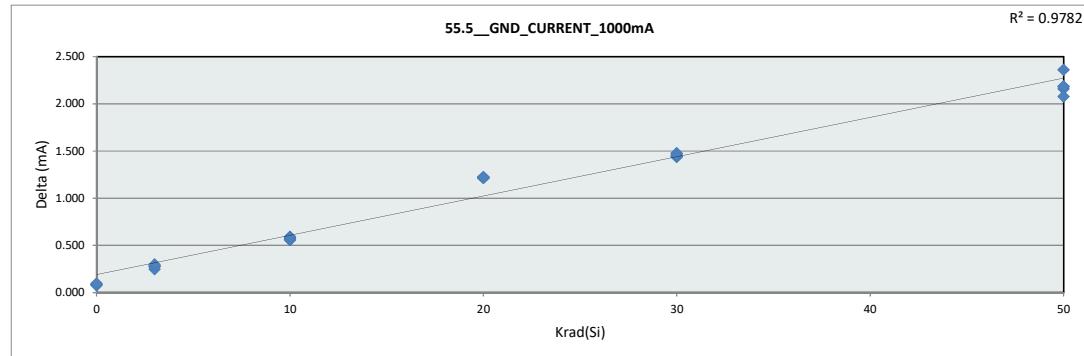


55.4_GND_CURRENT_500mA						
Test Site						
Tester						
Test Number						
Max Limit	25	mA				
Min Limit	mA	mA				
Krad(Si)	0	3	10	20	30	50
LL	7.686	7.903	7.839	8.475	8.480	8.674
Min	7.899	8.082	7.997	8.509	8.609	8.970
Average	8.015	8.308	8.182	8.564	8.668	9.450
Max	25.000	25.000	25.000	25.000	25.000	25.000
UL						

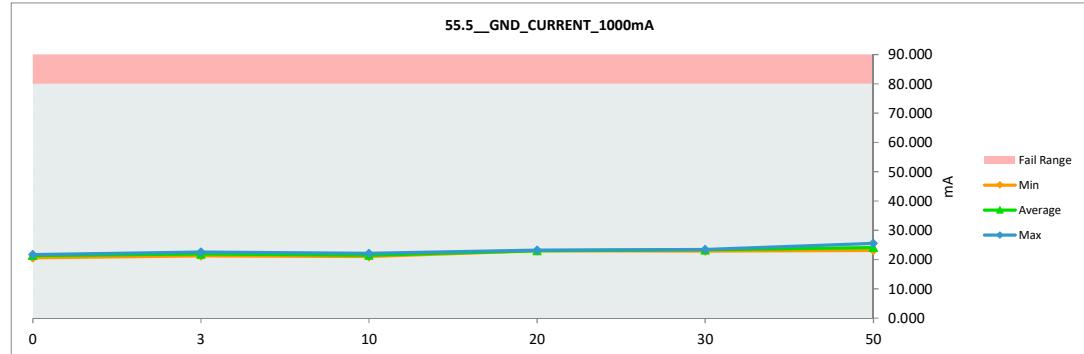


TID LDR Data (Unbiased)
TPS73801-SEP

55.5_GND_CURRENT_1000mA					
Test Site					
Tester					
Test Number					
Unit					
Max Limit	80		mA		
Min Limit		80		mA	
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	21.636	21.714	0.077	
0	69	20.544	20.630	0.086	
0	70	21.641	21.737	0.096	
3	6	21.016	21.265	0.249	
3	7	21.670	21.953	0.283	
3	8	21.811	22.094	0.283	
3	9	22.307	22.583	0.276	
3	10	21.325	21.621	0.297	
10	16	20.462	21.020	0.558	
10	17	20.854	21.417	0.564	
10	18	20.887	21.458	0.571	
10	19	21.037	21.626	0.589	
10	20	21.536	22.127	0.590	
20	63	21.997	23.211	1.214	
20	64	21.814	23.028	1.214	
20	65	21.876	23.101	1.225	
20	66	21.758	22.979	1.221	
20	67	21.721	22.941	1.220	
30	26	22.001	23.470	1.469	
30	27	21.458	22.898	1.440	
30	28	21.910	23.347	1.438	
30	29	21.974	23.452	1.478	
30	30	21.891	23.344	1.453	
50	36	22.220	24.405	2.184	
50	37	20.989	23.148	2.160	
50	38	21.725	23.908	2.184	
50	39	21.583	23.661	2.078	
50	40	23.202	25.561	2.360	
Max		23.202	25.561	2.360	
Average		21.602	22.632	1.031	
Min		20.462	20.630	0.077	
Std Dev		0.575	1.124	0.731	

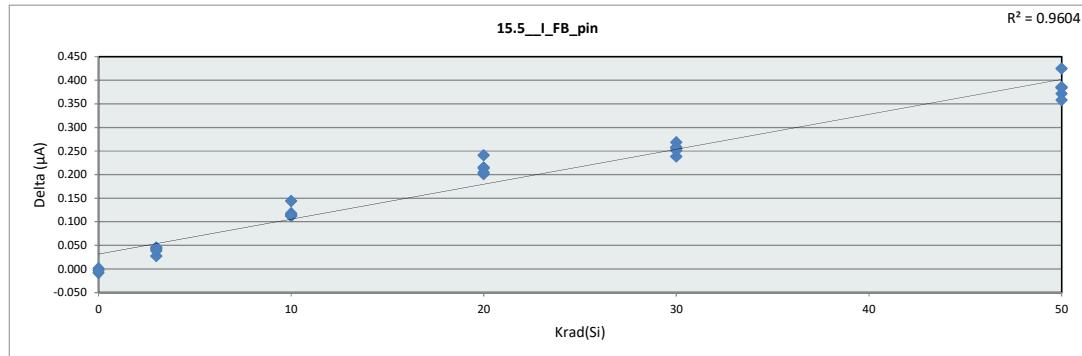


55.5_GND_CURRENT_1000mA						
Test Site						
Tester						
Test Number						
Max Limit	80		mA			
Min Limit		mA		mA		
Krad(Si)	0	3	10	20	30	50
LL						
Min	20.630	21.265	21.020	22.941	22.898	23.148
Average	21.360	21.903	21.530	23.052	23.302	24.137
Max	21.737	22.583	22.127	23.211	23.470	25.561
UL	80.000	80.000	80.000	80.000	80.000	80.000

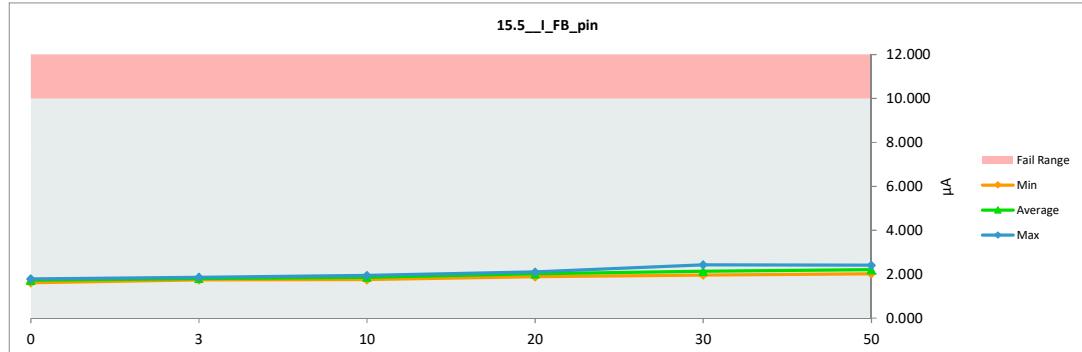


TID LDR Data (Unbiased)
TPS73801-SEP

15.5_I_FB_pin					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	Unit
0	68	1.794	1.786	-0.008	µA
0	69	1.607	1.608	0.001	
0	70	1.792	1.789	-0.003	
3	6	1.774	1.818	0.044	
3	7	1.790	1.817	0.027	
3	8	1.716	1.762	0.046	
3	9	1.697	1.738	0.042	
3	10	1.825	1.864	0.039	
10	16	1.659	1.776	0.117	
10	17	1.811	1.924	0.113	
10	18	1.631	1.749	0.118	
10	19	1.802	1.947	0.144	
10	20	1.792	1.905	0.113	
20	63	1.862	2.103	0.241	
20	64	1.857	2.071	0.214	
20	65	1.683	1.885	0.201	
20	66	1.838	2.053	0.215	
20	67	1.761	1.966	0.205	
30	26	1.726	1.964	0.238	
30	27	1.953	2.209	0.257	
30	28	2.164	2.432	0.269	
30	29	1.765	2.016	0.251	
30	30	1.797	2.055	0.258	
50	36	1.984	2.409	0.425	
50	37	1.927	2.299	0.372	
50	38	1.661	2.019	0.358	
50	39	1.823	2.207	0.384	
50	40	1.726	2.112	0.385	
Max		2.164	2.432	0.425	
Average		1.793	1.974	0.181	
Min		1.607	1.608	-0.008	
Std Dev		0.116	0.206	0.131	

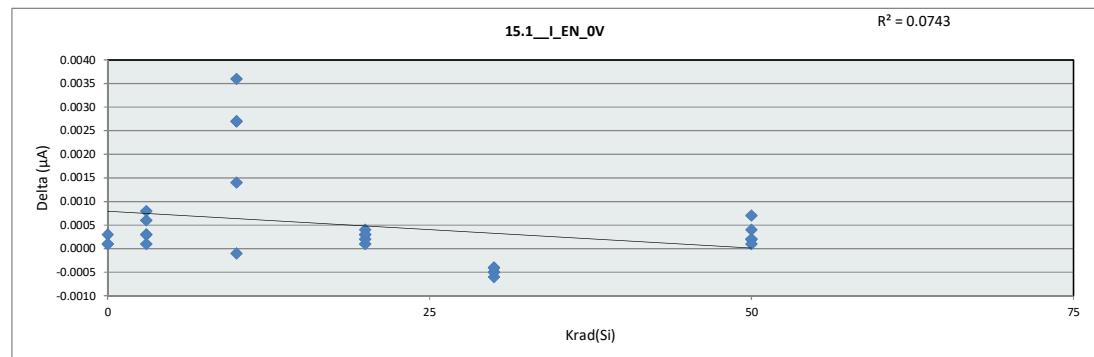


15.5_I_FB_pin					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Krad(Si)	0	3	10	20	30
LL					
Min	1.608	1.739	1.749	1.885	1.964
Average	1.727	1.800	1.860	2.016	2.135
Max	1.789	1.864	1.947	2.103	2.433
UL	10.000	10.000	10.000	10.000	10.000

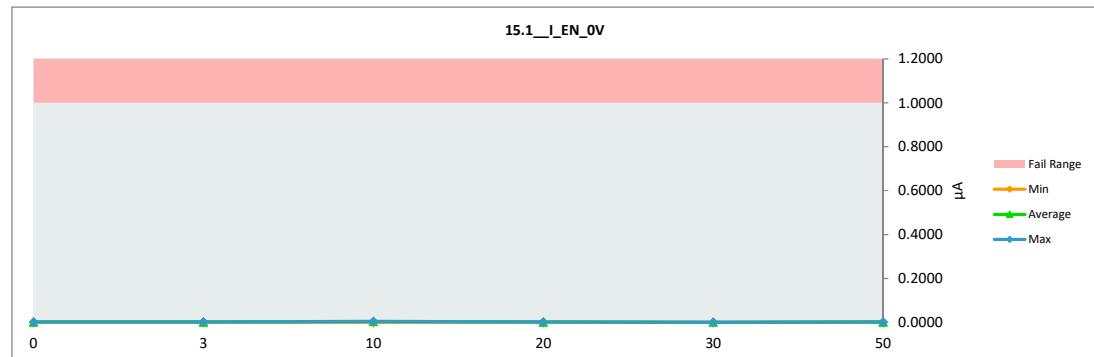


TID LDR Data (Unbiased)
TPS73801-SEP

15.1_I_EN_0V					
Test Site					
Tester					
Test Number					
Unit					
Max Limit	1	μA	1	μA	
Min Limit	1	μA	1	μA	
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	0.0011	0.0012	0.0001	
0	69	0.0009	0.0012	0.0003	
0	70	0.0012	0.0013	0.0001	
3	6	0.0010	0.0013	0.0003	
3	7	0.0011	0.0014	0.0003	
3	8	0.0007	0.0013	0.0006	
3	9	0.0008	0.0016	0.0008	
3	10	0.0011	0.0012	0.0001	
10	16	0.0011	0.0025	0.0014	
10	17	0.0011	0.0047	0.0036	
10	18	0.0007	0.0006	-0.0001	
10	19	0.0010	0.0037	0.0027	
10	20	0.0008	0.0035	0.0027	
20	63	0.0011	0.0012	0.0001	
20	64	0.0011	0.0013	0.0002	
20	65	0.0009	0.0013	0.0004	
20	66	0.0009	0.0012	0.0003	
20	67	0.0010	0.0013	0.0003	
30	26	0.0008	0.0002	-0.0006	
30	27	0.0008	0.0003	-0.0005	
30	28	0.0008	0.0003	-0.0005	
30	29	0.0008	0.0004	-0.0004	
30	30	0.0009	0.0005	-0.0004	
50	36	0.0003	0.0010	0.0007	
50	37	0.0007	0.0011	0.0004	
50	38	0.0008	0.0010	0.0002	
50	39	0.0009	0.0011	0.0002	
50	40	0.0009	0.0010	0.0001	
Max		0.0012	0.0047	0.0036	
Average		0.0009	0.0014	0.0005	
Min		0.0003	0.0002	-0.0006	
Std Dev		0.0002	0.0010	0.0010	

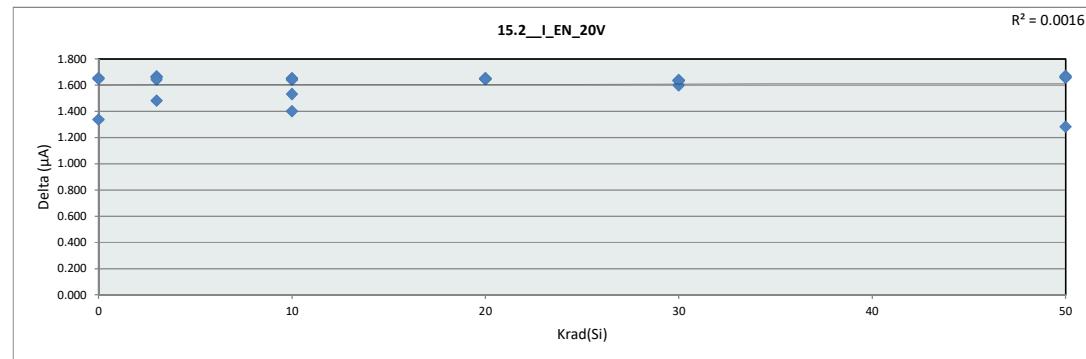


15.1_I_EN_0V						
Test Site						
Tester						
Test Number						
Max Limit	1	μA	1	μA		
Min Limit	1	μA	1	μA		
Krad(Si)	0	3	10	20	30	50
LL						
Min	0.0012	0.0012	0.0006	0.0012	0.0002	0.0010
Average	0.0012	0.0014	0.0030	0.0013	0.0003	0.0010
Max	0.0013	0.0016	0.0047	0.0013	0.0005	0.0011
UL	1.0000	1.0000	1.0000	1.0000	1.0000	1.0000

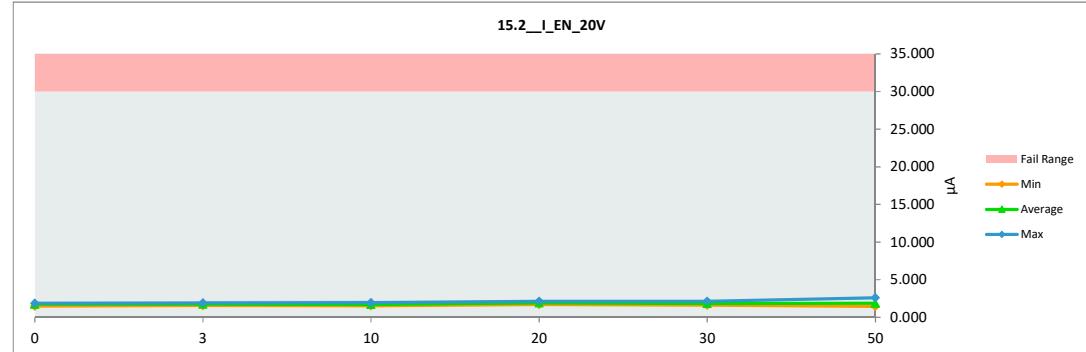


TID LDR Data (Unbiased)
TPS73801-SEP

15.2_I_EN_20V					
Test Site		Tester		Test Number	
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	Unit
0	68	0.218	1.874	1.656	µA
0	69	0.158	1.496	1.339	
0	70	0.173	1.822	1.648	
3	6	0.255	1.923	1.668	
3	7	0.218	1.877	1.659	
3	8	0.021	1.680	1.660	
3	9	0.088	1.571	1.482	
3	10	0.196	1.839	1.643	
10	16	0.061	1.594	1.533	
10	17	0.172	1.825	1.653	
10	18	0.123	1.526	1.403	
10	19	0.289	1.940	1.652	
10	20	0.088	1.729	1.641	
20	63	0.499	2.153	1.654	
20	64	0.339	1.986	1.647	
20	65	0.077	1.722	1.646	
20	66	0.205	1.856	1.651	
20	67	0.176	1.825	1.650	
30	26	0.075	1.712	1.637	
30	27	0.018	1.617	1.599	
30	28	0.512	2.151	1.639	
30	29	0.197	1.831	1.634	
30	30	0.226	1.861	1.635	
50	36	0.924	2.595	1.671	
50	37	0.056	1.714	1.657	
50	38	0.189	1.472	1.284	
50	39	0.197	1.861	1.664	
50	40	0.065	1.726	1.661	
Max		0.924	2.595	1.671	
Average		0.208	1.814	1.606	
Min		0.018	1.472	1.284	
Std Dev		0.186	0.229	0.103	

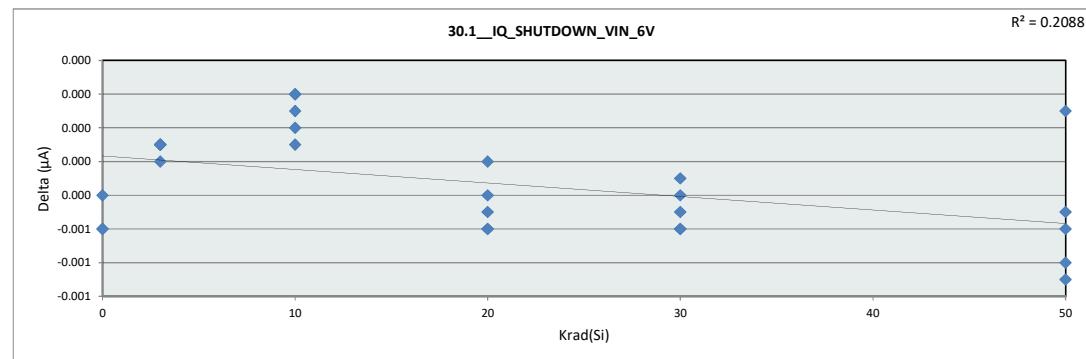


15.2_I_EN_20V					
Test Site		Tester		Test Number	
Krad(Si)	0	3	10	20	30
LL					
Min	1.496	1.571	1.526	1.723	1.617
Average	1.731	1.778	1.723	1.909	1.834
Max	1.874	1.923	1.940	2.153	2.151
UL	30.000	30.000	30.000	30.000	30.000

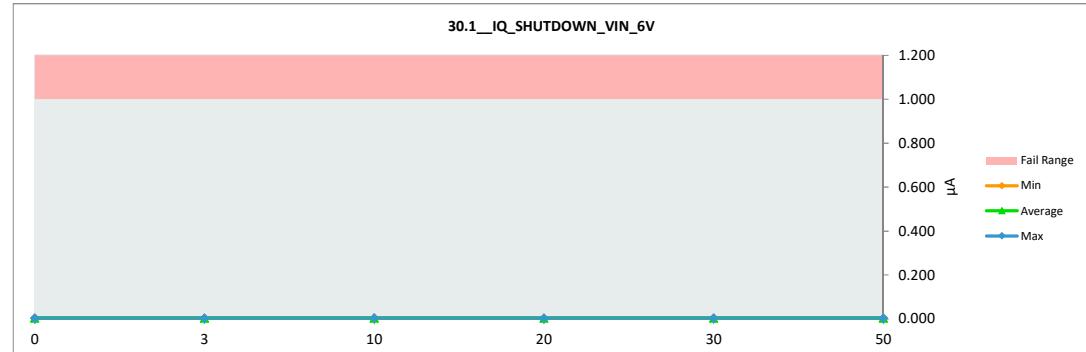


TID LDR Data (Unbiased)
TPS73801-SEP

30.1__IQ_SHUTDOWN_VIN_6V				
Test Site		Tester		Test Number
Unit	μA	Unit	μA	Max Limit
	1		1	
Min Limit				
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta
0	68	0.004	0.004	-0.001
0	69	0.004	0.004	0.000
0	70	0.004	0.004	-0.001
3	6	0.004	0.004	0.000
3	7	0.004	0.004	0.000
3	8	0.004	0.004	0.000
3	9	0.004	0.004	0.000
3	10	0.004	0.004	0.000
10	16	0.004	0.004	0.000
10	17	0.004	0.004	0.000
10	18	0.004	0.004	0.000
10	19	0.004	0.004	0.000
10	20	0.004	0.004	0.000
20	63	0.004	0.004	0.000
20	64	0.004	0.004	0.000
20	65	0.004	0.004	-0.001
20	66	0.004	0.004	-0.001
20	67	0.004	0.004	-0.001
30	26	0.004	0.004	0.000
30	27	0.004	0.004	-0.001
30	28	0.004	0.004	-0.001
30	29	0.004	0.004	-0.001
30	30	0.004	0.004	0.000
50	36	0.005	0.004	-0.001
50	37	0.004	0.004	-0.001
50	38	0.005	0.004	-0.001
50	39	0.004	0.004	-0.001
50	40	0.004	0.004	0.000
Max		0.005	0.004	0.000
Average		0.004	0.004	0.000
Min		0.004	0.004	-0.001
Std Dev		0.000	0.000	0.000

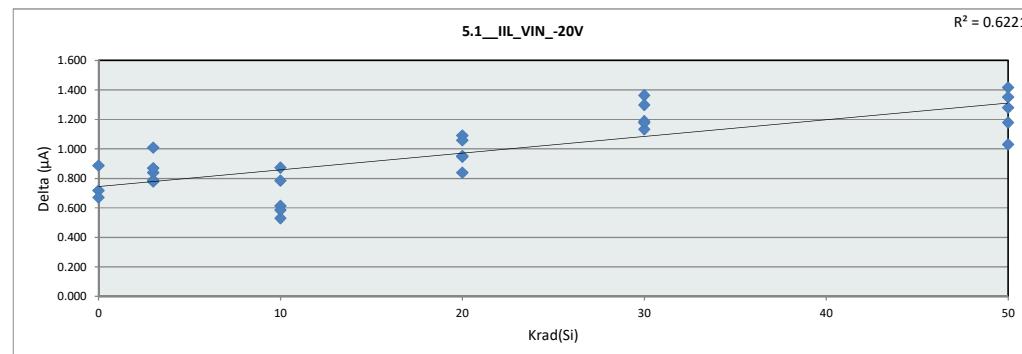


30.1__IQ_SHUTDOWN_VIN_6V					
Test Site		Tester		Test Number	
Max Limit	1	μA		Min Limit	μA
Krad(Si)	0	3	10	20	30
	LL				
Min	0.004	0.004	0.004	0.004	0.004
Average	0.004	0.004	0.004	0.004	0.004
Max	0.004	0.004	0.004	0.004	0.004
UL	1.000	1.000	1.000	1.000	1.000

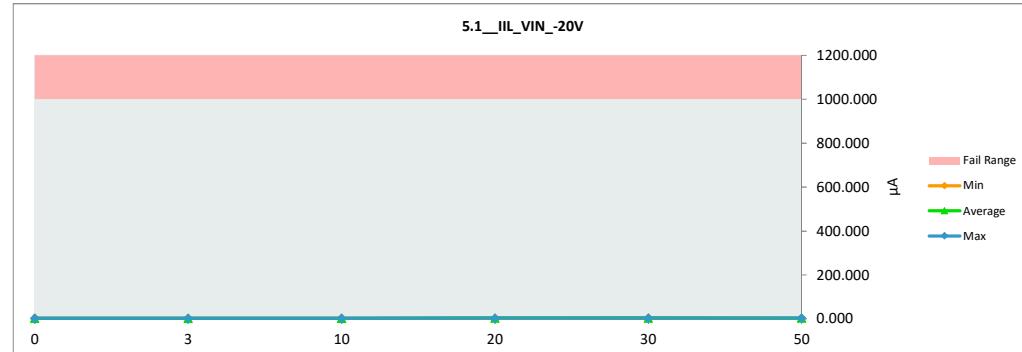


TID LDR Data (Unbiased)
TPS73801-SEP

5.1_IIL_VIN_-20V					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Unit	μA	Unit	μA	Max Limit	1000
Min Limit			<th></th> <td></td>		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	2.185	2.903	0.718	
0	69	2.152	3.039	0.888	
0	70	2.208	2.879	0.671	
3	6	2.095	3.103	1.008	
3	7	2.088	2.927	0.839	
3	8	2.090	2.877	0.788	
3	9	2.046	2.916	0.870	
3	10	2.158	2.938	0.779	
10	16	2.184	2.714	0.530	
10	17	2.174	2.960	0.786	
10	18	2.256	2.870	0.614	
10	19	2.249	3.121	0.873	
10	20	2.297	2.881	0.585	
20	63	2.255	3.346	1.091	
20	64	2.287	3.346	1.059	
20	65	2.368	3.206	0.838	
20	66	2.411	3.358	0.947	
20	67	2.262	3.214	0.952	
30	26	2.158	3.521	1.363	
30	27	2.345	3.478	1.133	
30	28	2.234	3.422	1.188	
30	29	2.311	3.609	1.298	
30	30	2.316	3.494	1.177	
50	36	2.348	3.764	1.416	
50	37	2.373	3.653	1.280	
50	38	2.408	3.760	1.352	
50	39	2.506	3.537	1.031	
50	40	2.262	3.440	1.178	
Max		2.506	3.764	1.416	
Average		2.251	3.224	0.973	
Min		2.046	2.714	0.530	
Std Dev		0.112	0.311	0.249	

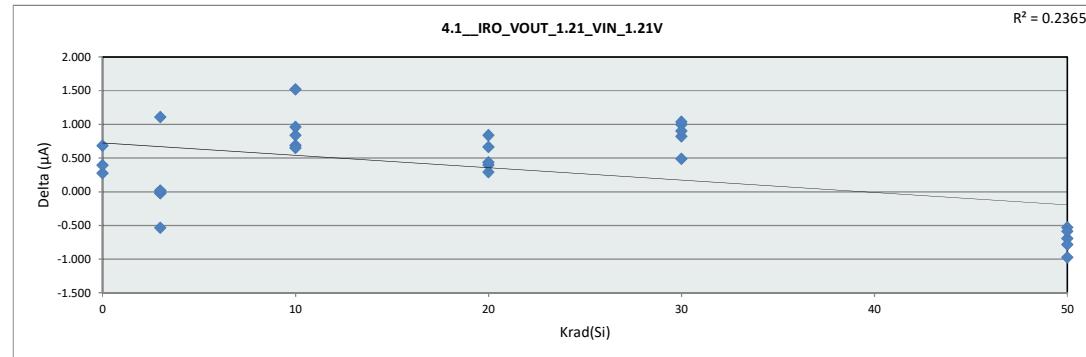


5.1_IIL_VIN_-20V					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Max Limit	1000	μA		Min Limit	μA
Krad(Si)	0	3	10	20	30
LL	2.879	2.877	2.714	3.206	3.422
Min	2.879	2.877	2.714	3.206	3.440
Average	2.940	2.952	2.909	3.294	3.505
Max	3.039	3.103	3.121	3.358	3.764
UL	1000.000	1000.000	1000.000	1000.000	1000.000

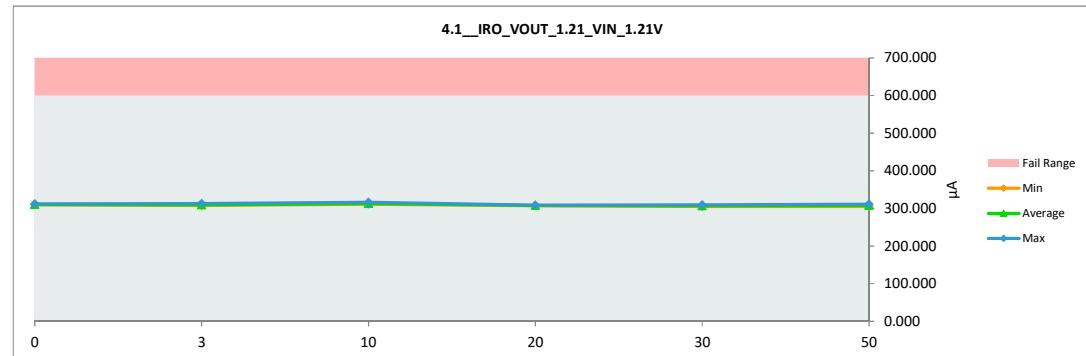


TID LDR Data (Unbiased)
TPS73801-SEP

4.1_IRO_VOUT_1.21_VIN_1.21V					
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number	
Unit	μA	Unit	μA	Max Limit	600
Min Limit			<th></th> <td></td>		
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	309.297	309.573	0.275	
0	69	311.463	311.858	0.395	
0	70	309.543	310.229	0.686	
3	6	313.828	313.294	-0.534	
3	7	308.006	307.999	-0.007	
3	8	307.667	307.643	-0.023	
3	9	310.986	311.004	0.018	
3	10	308.776	309.886	1.110	
10	16	315.489	316.330	0.841	
10	17	311.520	312.207	0.688	
10	18	310.716	311.680	0.963	
10	19	311.706	312.356	0.651	
10	20	312.140	313.659	1.520	
20	63	306.815	307.108	0.293	
20	64	308.211	308.877	0.666	
20	65	307.001	307.840	0.838	
20	66	308.517	308.914	0.397	
20	67	308.480	308.918	0.438	
30	26	305.153	305.974	0.822	
30	27	306.372	307.371	0.998	
30	28	304.482	304.971	0.489	
30	29	308.218	309.256	1.038	
30	30	307.288	308.190	0.901	
50	36	306.806	305.832	-0.974	
50	37	311.026	310.498	-0.528	
50	38	311.953	311.259	-0.694	
50	39	305.966	305.183	-0.783	
50	40	309.272	308.686	-0.586	
Max		315.489	316.330	1.520	
Average		309.168	309.521	0.353	
Min		304.482	304.971	-0.974	
Std Dev		2.630	2.711	0.656	

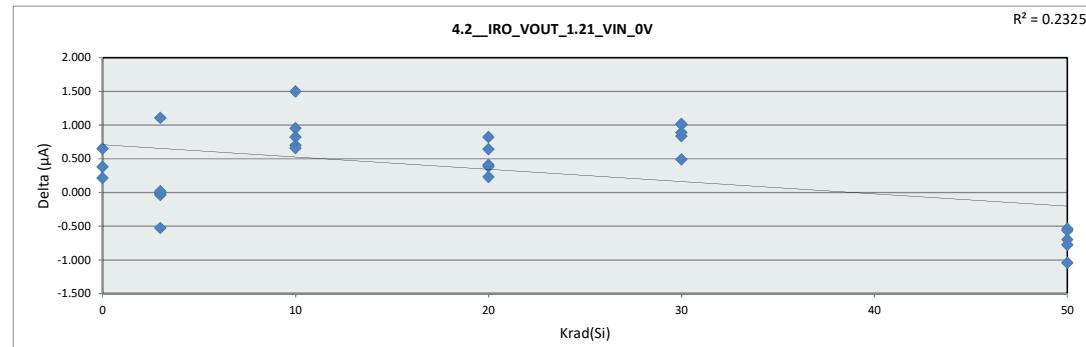


4.1_IRO_VOUT_1.21_VIN_1.21V						
Test Site		Tester	<th>Test Number</th> <td></td>	Test Number		
Unit	μA	Unit	μA	Max Limit	600	
Min Limit	μA				μA	
Krad(Si)	0	3	10	20	30	50
LL						
Min	309.573	307.643	311.680	307.108	304.971	305.183
Average	310.553	309.965	313.247	308.331	307.152	308.292
Max	311.858	313.294	316.330	308.919	309.256	311.259
UL	600.000	600.000	600.000	600.000	600.000	600.000

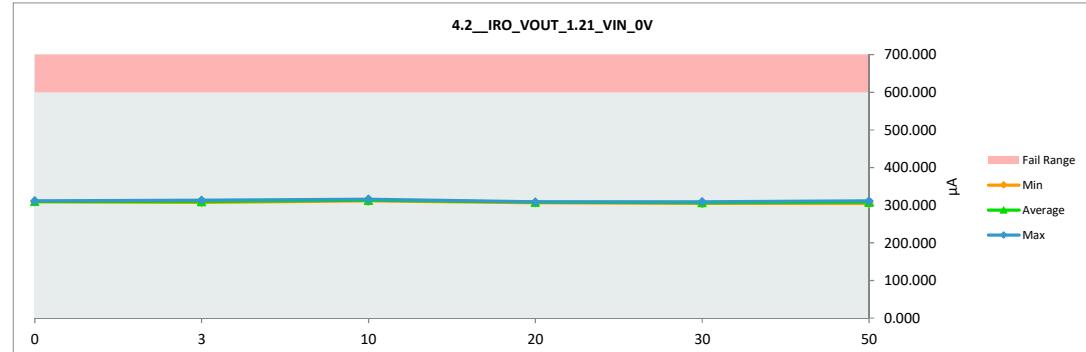


TID LDR Data (Unbiased)
TPS73801-SEP

4.2_IRO_VOUT_1.21_VIN_0V					
Test Site	Tester				
Test Number	Unit	μA	μA		
		600	600		
Max Limit	Min Limit				
Krad(Si)	Serial #	PRE-UNBIAS	POST-UNBIAS	Delta	
0	68	309.040	309.255	0.215	
0	69	311.210	311.591	0.382	
0	70	309.290	309.941	0.652	
3	6	313.542	313.017	-0.524	
3	7	307.729	307.716	-0.013	
3	8	307.401	307.366	-0.034	
3	9	310.712	310.731	0.019	
3	10	308.493	309.599	1.106	
10	16	315.245	316.066	0.822	
10	17	311.247	311.946	0.698	
10	18	310.448	311.400	0.952	
10	19	311.425	312.084	0.659	
10	20	311.886	313.387	1.501	
20	63	306.552	306.785	0.232	
20	64	307.969	308.611	0.642	
20	65	306.735	307.558	0.823	
20	66	308.251	308.638	0.387	
20	67	308.228	308.638	0.410	
30	26	304.862	305.699	0.837	
30	27	306.096	307.104	1.008	
30	28	304.211	304.702	0.491	
30	29	307.976	308.993	1.017	
30	30	307.026	307.916	0.890	
50	36	306.547	305.504	-1.044	
50	37	310.775	310.239	-0.537	
50	38	311.686	310.988	-0.699	
50	39	305.689	304.913	-0.775	
50	40	308.996	308.433	-0.563	
		315.245	316.066	1.501	
		308.902	309.244	0.341	
		304.211	304.702	-1.044	
		2.633	2.716	0.657	



4.2_IRO_VOUT_1.21_VIN_0V							
Test Site	Tester						
Test Number	Unit	600	μA				
Max Limit	Min Limit						
Krad(Si)	0	3	10	20	30		
LL	309.255	307.366	311.400	306.785	304.702		
Min	310.263	309.686	312.977	308.046	306.883		
Average	310.263	309.686	312.977	308.046	306.883		
Max	311.591	313.017	316.067	308.638	308.993		
UL	600.000	600.000	600.000	600.000	600.000		



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